R&S®FSW Signal and Spectrum Analyzer User Manual



® ROHDE&SCHWARZ This manual applies to the following R&S®FSW models with firmware version 1.51 and higher:

- R&S®FSW8 (1312.8000K08)
- R&S®FSW13 (1312.8000K13)
- R&S®FSW26 (1312.8000K26)

In addition to the base unit, the following options are described:

- R&S FSW-B10 (1313.1622.02)
- R&S FSW-B13 (1313.0761.02)
- R&S FSW-B17 (1313.0784.02)
- R&S FSW-B21 (1313.1100.26)
- R&S FSW-B24 (1313.0832.13/26)
- R&S FSW-B25 (1313.0990.02)
- R&S FSW-B28 (1313.1645.02)
- R&S FSW-B40 (1313.0861.02) / R&S FSW-U40 (1313.52505.02)
- R&S FSW-B80 (1313.0878.02) / R&S FSW-U80 (1313.5211.02)
- R&S FSW-B160 (1313.1668.02) / R&S FSW-U160 (1313.3754.02)

The firmware of the instrument makes use of several valuable open source software packages. For information, see the "Open Source Acknowledgement" on the user documentation CD-ROM (included in delivery).

Rohde & Schwarz would like to thank the open source community for their valuable contribution to embedded computing.

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Phone: +49 89 41 29 - 0
Fax: +49 89 41 29 12 164
E-mail: info@rohde-schwarz.com
Internet: http://www.rohde-schwarz.com

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The following abbreviations are used throughout this manual: R&S®FSW is abbreviated as R&S FSW. R&S®MultiView is abbreviated as MultiView.

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R&S®FSW Contents

About this Manual

1 Preface

1.1 About this Manual

This User Manual describes general instrument functions and settings common to all applications and operating modes in the R&S FSW. Furthermore, it provides all the information specific to **RF measurements in the Spectrum application**. All other operating modes and applications are described in the specific application manuals.

The main focus in this manual is on the measurement results and the tasks required to obtain them. The following topics are included:

Welcome to the R&S FSW

Introduction to and getting familiar with the instrument

Operating Modes and Applications

The concept of using multiple operating modes

Measurements

Descriptions of the individual measurements in the Spectrum application, including result types and configuration settings.

Common Measurement Settings

Description of the measurement settings common to all measurement types with their corresponding remote control commands

Common Measurement Analysis and Display Functions

Description of the settings and functions provided to analyze results independantly of the measurement type with their corresponding remote control commands

• Data Management

Description of general functions to handle data files (configuration and result data, not I/Q data)

• General Instrument Setup

Description of general instrument settings and functions that are independent of the current operating mode

Network and Remote Operation

Information on setting up the instrument in a network and operating it remotely.

Remote Commands

Remote commands required to configure and perform measurements in a remote environment, sorted by tasks

Remote commands required to set up the environment and to perform common tasks on the instrument, sorted by tasks

Programming examples demonstrate the use of many commands and can usually be executed directly for test purposes

Maintenance

Information on tasks required to maintain operability of the instrument

Troubleshooting

Hints and tips on how to handle errors

List of Commands

Documentation Overview

Alpahabetical list of all remote commands described in the manual

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1.2 Documentation Overview

The user documentation for the R&S FSW consists of the following parts:

- "Getting Started" printed manual
- Online Help system on the instrument
- Documentation CD-ROM with:
 - Getting Started
 - User Manuals for base unit and options
 - Service Manual
 - Release Notes
 - Data sheet and product brochures

Online Help

The Online Help is embedded in the instrument's firmware. It offers quick, context-sensitive access to the complete information needed for operation and programming. Online help is available using the ? icon on the toolbar of the R&S FSW.

Getting Started

This manual is delivered with the instrument in printed form and in PDF format on the CD. It provides the information needed to set up and start working with the instrument. Basic operations and handling are described. Safety information is also included.

The Getting Started manual in various languages is also available for download from the R&S website, on the R&S FSW product page at http://www2.rohde-schwarz.com/product/FSW.html.

User Manuals

User manuals are provided for the base unit and each additional (software) option.

The user manuals are available in PDF format - in printable form - on the Documentation CD-ROM delivered with the instrument. In the user manuals, all instrument functions are described in detail. Furthermore, they provide a complete description of the remote control commands with programming examples.

The user manual for the base unit provides basic information on operating the R&S FSW in general, and the Spectrum application in particular. Furthermore, the software functions that enhance the basic functionality for various applications are described here. An introduction to remote control is provided, as well as information on maintenance, instrument interfaces and troubleshooting.

In the individual application manuals, the specific instrument functions of the application are described in detail. For additional information on default settings and parameters,

Conventions Used in the Documentation

refer to the data sheets. Basic information on operating the R&S FSW is not included in the application manuals.

All user manuals are also available for download from the R&S website, on the R&S FSW product page at http://www2.rohde-schwarz.com/product/FSW.html.

Service Manual

This manual is available in PDF format on the CD delivered with the instrument. It describes how to check compliance with rated specifications, instrument function, repair, troubleshooting and fault elimination. It contains all information required for repairing the R&S FSW by replacing modules.

Release Notes

The release notes describe the installation of the firmware, new and modified functions, eliminated problems, and last minute changes to the documentation. The corresponding firmware version is indicated on the title page of the release notes.

The most recent release notes are also available for download from the R&S website, on the R&S FSW product page at http://www2.rohde-schwarz.com/product/FSW.html > Downloads > Firmware.

1.3 Conventions Used in the Documentation

1.3.1 Typographical Conventions

The following text markers are used throughout this documentation:

Convention	Description
"Graphical user interface elements"	All names of graphical user interface elements on the screen, such as dialog boxes, menus, options, buttons, and softkeys are enclosed by quotation marks.
KEYS	Key names are written in capital letters.
File names, commands, program code	File names, commands, coding samples and screen output are distinguished by their font.
Input	Input to be entered by the user is displayed in italics.
Links	Links that you can click are displayed in blue font.
"References"	References to other parts of the documentation are enclosed by quotation marks.

1.3.2 Conventions for Procedure Descriptions

When describing how to operate the instrument, several alternative methods may be available to perform the same task. In this case, the procedure using the touchscreen is

Conventions Used in the Documentation

described. Any elements that can be activated by touching can also be clicked using an additionally connected mouse. The alternative procedure using the keys on the instrument or the on-screen keyboard is only described if it deviates from the standard operating procedures.

The term "select" may refer to any of the described methods, i.e. using a finger on the touchscreen, a mouse pointer in the display, or a key on the instrument or on a keyboard.

2 Welcome to the R&S FSW

The R&S FSW is a new high-performance R&S®FSW signal and spectrum analyzer developed to meet demanding customer requirements. Offering low phase noise, wide analysis bandwidth and straightforward and intuitive operation, the analyzer makes measurements fast and easy.

This user manual contains a description of the functionality that the instrument provides, including remote control operation. The latest version is available for download at the product homepage (http://www2.rohde-schwarz.com/product/FSW.html).

3 Applications and Operating Modes

The R&S FSW provides several applications for different analysis tasks and different types of signals, e.g. 3G FDD, I/Q analysis or basic spectrum analysis. When you activate an application, a new measurement channel is created which determines the measurement settings for that application. The same application can be activated with different measurement settings by creating several channels for the same application. Each channel is displayed in a separate tab on the screen.



The maximum number may be limited further by the available memory on the instrument.

Independant vs correlating measurements

With the **conventional R&S FSW Signal and Spectrum Analyzer** you can perform several different measurements almost simultaneously. However, the individual measurements are independent of each other - **each application captures and evaluates its own set of data**, regardless of what the other applications do.

In some cases it may be useful to **analyze the exact same input data using different applications**. For example, imagine capturing data from a base station and analyzing the RF spectrum in the Analog Demodulation application. If a spur or an unexpected peak occurs, you may want to analyze the same data in the I/Q Analyzer to see the real and imaginary components of the signal and thus detect the reason for the irregular signal. Normally when you switch to a different application, evaluation is performed on the data that was captured by that application, and not the previous one. In our example that would mean the irregular signal would be lost. Therefore, a new operating mode has been introduced to the R&S FSW: Multi-Standard Radio Analyzer (MSRA) mode.

In **Multi-Standard Radio Analyzer mode**, data acquisition is performed once and the captured data is then evaluated by any number of applications for different radio standards. Data acquisition and global configuration settings are controlled globally, while the evaluation and display settings can be configured individually for each application. Using the Multi-Standard Radio Analyzer, unwanted correlations between different signal components using different transmission standards can be detected. Thus, for example, an irregularity in a GSM burst can be examined closer in the WCDMA application to reveal dependencies like a change in the EVM value.

Distinct operating modes

Although the applications themselves are identical in either operating mode, the handling of the data between applications is not. Thus, the operating mode determines which applications are available and active. Whenever you change the operating mode, the currently active measurement channels are closed. The default operating mode is Signal and Spectrum Analyzer mode; however, the presetting can be changed.

SCPI command:

INST:MODE SAN, see INSTrument:MODE on page 452

R&S MultiView

Switching between applications

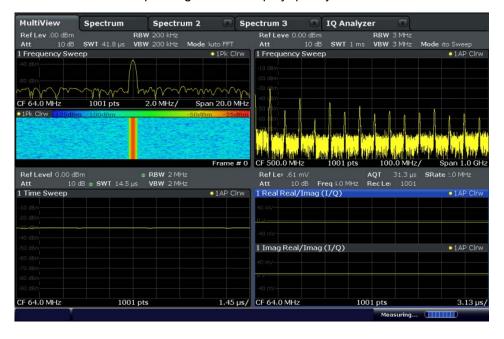
When you switch to a new application, a set of parameters is passed on from the current application to the new one:

- center frequency and frequency offset
- · reference level and reference level offset
- attenuation

After initial setup, the parameters for the measurement channel are stored upon exiting and restored upon re-entering the channel. Thus, you can switch between applications quickly and easily.

3.1 R&S MultiView

Each application is displayed in a separate tab. An additional tab ("MultiView") provides an overview of all currently active channels at a glance. In the "MultiView" tab, each individual window contains its own channel bar with an additional button. Tap this button to switch to the corresponding channel display quickly.



3.2 Available Applications

The R&S FSW provides some applications in the base unit while others are available only if the corresponding firmware options are installed. Not all R&S FSW applications are supported in MSRA mode. For an overview of supported MSRA applications see the R&S FSW MSRA User Manual.



Spectrogram application

Spectrogram measurements are not a separate application, but rather a trace evaluation method, thus they are available as an evaluation method for the Display Configuration, not by creating a new channel. Spectrograms are configured and activated in the "Trace" settings. See chapter 6.3.1.6, "Spectrograms", on page 242 for details.

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Spectrum

In the Spectrum application the provided functions correspond to those of a conventional spectrum analyzer. The analyzer measures the frequency spectrum of the RF input signal over the selected frequency range with the selected resolution and sweep time, or, for a fixed frequency, displays the waveform of the video signal. This application is used in the initial configuration.

For details see chapter 4, "Measurements", on page 30.

SCPI command:

INST:SEL SAN, see INSTrument[:SELect] on page 453

1xEV-DO BTS

The 1xEV-DO BTS application requires an instrument equipped with the 1xEV-DO BTS Measurements option, R&S FSW-K84. This application provides test measurements for 1xEV-DO BTS downlink signals (base station signals) according to the test specification.

For details see the R&S FSW-K84/-K85 User Manual.

SCPI command:

INST:SEL BDO, see INSTrument[:SELect] on page 453

1xEV-DO MS

The 1xEV-DO MS application requires an instrument equipped with the 1xEV-DO MS Measurements option, R&S FSW-K85. This application provides test measurements for 1xEV-DO MS uplink signals (mobile signals) according to the test specification.

Available Applications

For details see the R&S FSW-K84/-K85 User Manual.

SCPI command:

INST:SEL MDO, see INSTrument[:SELect] on page 453

3G FDD BTS

The 3G FDD BTS application requires an instrument equipped with the 3GPP Base Station Measurements option, R&S FSW-K72. This application provides test measurements for WCDMA downlink signals (base station signals) according to the test specification.

For details see the R&S FSW-K72/-K73 User Manual.

SCPI command:

INST:SEL BWCD, see INSTrument[:SELect] on page 453

3G FDD UE

The 3G FDD UE application requires an instrument equipped with the 3GPP User Equipment Measurements option, R&S FSW-K73. This application provides test measurements for WCDMA uplink signals (mobile signals) according to the test specification.

For details see the R&S FSW-K72/-K73 User Manual.

SCPI command:

INST:SEL MWCD, see INSTrument[:SELect] on page 453

Analog Demodulation

The Analog Demodulation application requires an instrument equipped with the corresponding optional software. This application provides measurement functions for demodulating AM, FM, or PM signals.

For details see the R&S FSW-K7 User Manual.

SCPI command:

```
INST:SEL ADEM, see INSTrument[:SELect] on page 453
```

cdma2000 BTS

The cdma2000 BTS application requires an instrument equipped with the cdma2000 BTS Measurements option, R&S FSW-K82. This application provides test measurements for cdma2000 BTS downlink signals (base station signals) according to the test specification.

For details see the R&S FSW-K82/-K83 User Manual.

SCPI command:

```
INST:SEL BC2K, see INSTrument[:SELect] on page 453
```

cdma2000 MS

The cdma2000 MS application requires an instrument equipped with the cdma2000 MS Measurements option, R&S FSW-K83. This application provides test measurements for cdma2000 MS uplink signals (mobile signals) according to the test specification.

For details see the R&S FSW-K82/-K83 User Manual.

SCPI command:

INST:SEL MC2K, see INSTrument[:SELect] on page 453

Available Applications

(Multi-Carrier) Group Delay

The Group Delay application requires an instrument equipped with the Multi-Carrier Group Delay Measurements option R&S FSW-K17. This application provides a Multi-Carrier Group Delay measurement.

For details see the R&S FSW-K17 User Manual.

SCPI command:

INST:SEL MCGD, see INSTrument[:SELect] on page 453

GSM

The GSM application requires an instrument equipped with the GSM Measurements option R&S FSW-K10. This application provides GSM measurements.

For details see the R&S FSW-K10 User Manual.

SCPI command:

INST:SEL GSM, see INSTrument[:SELect] on page 453

I/Q Analyzer

The I/Q Analyzer application provides measurement and display functions for I/Q data.

For details see the R&S FSW I/Q Analyzer User Manual.

SCPI command:

```
INST:SEL IQ, see INSTrument[:SELect] on page 453
```

LTE

The LTE application requires an instrument equipped with the LTE Measurements option R&S FSW-K10. This application provides LTE measurements.

For details see the R&S FSW-K10x (LTE Downlink) User Manual.

SCPI command:

```
INST:SEL LTE, see INSTrument[:SELect] on page 453
```

Noise Figure

The Noise Figure application requires an instrument equipped with the Noise Figure Measurements option R&S FSW-K30. This application provides noise figure measurements.

For details see the R&S FSW-K30 User Manual.

SCPI command:

```
INST:SEL NOISE, see INSTrument[:SELect] on page 453
```

Phase Noise

The Phase Noise application requires an instrument equipped with the Phase Noise Measurements option, R&S FSW-K40. This application provides measurements for phase noise tests.

For details see the R&S FSW-K40 User Manual.

SCPI command:

```
INST:SEL PNOISE, see INSTrument[:SELect] on page 453
```

Selecting the Operating Mode

Pulse Measurements

The Pulse application requires an instrument equipped with the Pulse Measurements option, R&S FSW-K6. This application provides measurement functions for pulsed signals.

For details see the R&S FSW-K6 User Manual.

SCPI command:

INST:SEL PULSE, see INSTrument[:SELect] on page 453

Vector Signal Analysis (VSA)

The VSA application requires an instrument equipped with the Vector Signal Analysis option, R&S FSW-K70. This application provides measurements and evaluations for Vector Signal Analysis.

For details see the R&S FSW-K70 User Manual.

SCPI command:

INST:SEL DDEM, see INSTrument[:SELect] on page 453

WLAN

The WLAN application requires an instrument equipped with the WLAN option, R&S FSW-K91/91n. This application provides measurements and evaluations according to the WLAN IEEE 802.11 standards.

For details see the R&S FSW-K91 User Manual.

SCPI command:

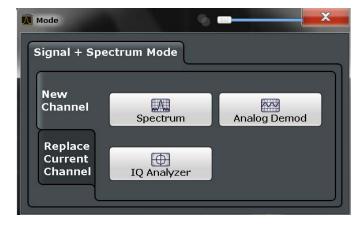
INST:SEL WLAN, see INSTrument[:SELect] on page 453

3.3 Selecting the Operating Mode

The default operating mode is Signal and Spectrum Analyzer mode, however, the presetting can be changed.

(See chapter 8.3.4.5, "Preset", on page 356).

Both the operating mode and the application can be selected in the "Mode" dialog box which is displayed when you press the MODE key.



Starting an Application

To switch the operating mode, select the corresponding tab.

The remote commands required to perform these tasks are described in chapter 10.2, "Selecting the Operating Mode and Application", on page 449.

To activate the Signal and Spectrum Analyzer operating mode

- Press the MODE key on the front panel of the R&S FSW.
 A dialog box opens that contains all operating modes and applications currently available on your R&S FSW.
- 2. Select the "Signal and Spectrum Analyzer" tab.
- 3. Confirm the message informing you that you are changing operating modes.

The R&S FSW stores and closes all active measurement channels in the current operating mode, then opens a new measurement channel for the Signal and Spectrum Analyzer operating mode.

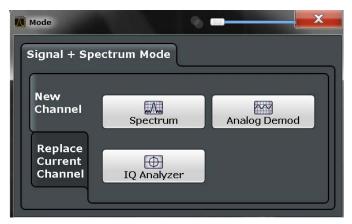
Note: when you return to the previous operating mode, the stored configuration of all measurement channels is restored.

The default Spectrum measurement channel is displayed and the Sequencer is automatically activated in continuous mode (see chapter 3.5, "Running a Sequence of Measurements", on page 25).

3.4 Starting an Application

The default application in Signal and Spectrum Analyzer mode is a Spectrum measurement.

The application can be selected in the "Mode" dialog box which is displayed when you press the MODE key.



To select an application, select the corresponding button.



The measurement channels are labeled with their default name. If that name already exists, a sequential number is added. In remote control, the name of the measurement channel can be changed. For details and an overview of default names see table 10-1.

Switching between applications

When you switch to a new application, a set of parameters is passed on from the current application to the new one:

- · center frequency and frequency offset
- reference level and reference level offset
- attenuation

After initial setup, the parameters for the measurement channel are stored upon exiting and restored upon re-entering the channel. Thus, you can switch between applications quickly and easily.



To deactivate a channel, simply close the corresponding tab.

The remote commands required to perform these tasks are described in chapter 10.2, "Selecting the Operating Mode and Application", on page 449.

New Channel25	į
Replace Current Channel	;

New Channel

The applications selected on this tab are started in a new channel, i.e. a new tab in the display.

SCPI command:

```
INSTrument:CREate[:NEW] on page 450
INSTrument[:SELect] on page 453
```

Replace Current Channel

The applications selected on this tab are started in the currently displayed channel, replacing the current application.

SCPI command:

INSTrument:CREate:REPLace on page 450

3.5 Running a Sequence of Measurements

Only one measurement can be performed at any time, namely the one in the currently active channel. However, in order to perform the configured measurements consecutively, a Sequencer function is provided.

•	The Sequencer Concept	26
•	Sequencer Settings	28
	How to Set Up the Sequencer	

3.5.1 The Sequencer Concept

The instrument can only be in one specific channel at any time. Thus, only one measurement can be performed at any time, namely the one in the currently active channel. However, in order to perform the configured measurements consecutively, a Sequencer function is provided, which changes the application of the instrument as required. If activated, the measurements configured in the currently active channels are performed one after the other in the order of the tabs. For each individual measurement, the sweep count is considered. Thus, each measurement may consist of several sweeps. The currently active measurement is indicated by a symbol in the tab label. The result displays of the individual channels are updated in the tabs (including the "MultiView") as the measurements are performed. Sequential operation itself is independant of the currently displayed tab.

Sequencer modes

Three different Sequencer modes are available:

• Single Sequence

Similar to single sweep mode; each measurement is performed once, until all measurements in all active channels have been performed.

Continuous Sequence

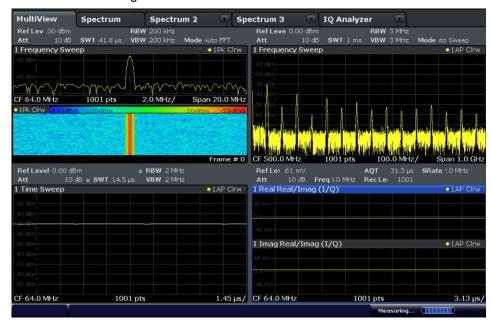
Similar to continuous sweep mode; the measurements in each active channel are performed one after the other, repeatedly, in the same order, until sequential operation is stopped. This is the default Sequencer mode.

Channel-defined Sequence

First, a single sequence is performed. Then, only channels in continuous sweep mode are repeated continuously.

Example: Sequencer procedure

Assume the following active channel definition:



Tab name	application	Sweep mode	Sweep count
Spectrum	Spectrum	Cont. Sweep	5
Spectrum 2	Spectrum	Single Sweep	6
Spectrum 3	Spectrum	Cont. Sweep	2
IQ Analyzer	IQ Analyzer	Single Sweep	7

For **single Sequence**, the following sweeps will be performed:

5x Spectrum, 6x Spectrum 2, 2 x Spectrum 3, 7x IQ Analyzer

For **continuous Sequence**, the following sweeps will be performed:

5x Spectrum, 6x Spectrum 2, 2 x Spectrum 3, 7x IQ Analyzer,

5x Spectrum, 6x Spectrum 2, 2 x Spectrum 3, 7x IQ Analyzer,

• • •

For **channel-defined Sequence**, the following sweeps will be performed:

5x Spectrum, 6x Spectrum 2, 2 x Spectrum 3, 7x IQ Analyzer,

5x Spectrum, 2 x Spectrum 3,

5x Spectrum, 2 x Spectrum 3,

...

RUN SINGLE/RUN CONT and Single Sweep/Sweep Continuous keys

While the Sequencer is active, the RUN SINGLE and RUN CONT keys on the front panel control the Sequencer, not individual sweeps. RUN SINGLE starts the Sequencer in single mode, while RUN CONT starts the Sequencer in continuous mode.

The "Single Sweep" and "Continuous Sweep" softkeys control the sweep mode for the currently selected channel only; the sweep mode only has an effect the next time the Sequencer activates that channel, and only for a channel-defined sequence. In this case, a channel in single sweep mode is swept only once by the Sequencer. A channel in continuous sweep mode is swept repeatedly.

3.5.2 Sequencer Settings

The "Sequencer" menu is available from the toolbar.



Sequencer	State	28
Sequencer	Mode	28

Sequencer State

Activates or deactivates the Sequencer. If activated, sequential operation according to the selected Sequencer mode is started immediately.

SCPI command:

```
SYSTem: SEQuencer on page 455
```

INITiate:SEQuencer:IMMediate on page 454
INITiate:SEQuencer:ABORt on page 454

Sequencer Mode

Defines how often which measurements are performed. The currently selected mode softkey is highlighted blue. During an active Sequencer process, the selected mode softkey is highlighted orange.

"Single Sequencer"

Each measurement is performed once, until all measurements in all active channels have been performed.

"Continuous Sequencer"

The measurements in each active channel are performed one after the other, repeatedly, in the same order, until sequential operation is stopped.

This is the default Sequencer mode.

"Channel-defined Sequencer"

First, a single sequence is performed. Then, only channels in continuous sweep mode are repeated.

SCPI command:

INITiate: SEQuencer: MODE on page 454

3.5.3 How to Set Up the Sequencer

In order to perform the configured measurements consecutively, a Sequencer function is provided.

- Configure a channel for each measurement configuration as required, including the sweep mode.
- 2. In the toolbar, select the "Sequencer" icon.



The "Sequencer" menu is displayed.

3. Toggle the "Sequencer" softkey to "On".

A continuous sequence is started immediately.

4. To change the Sequencer mode and start a new sequence immediately, select the corresponding mode softkey, or press the RUN SINGLE or RUN CONT key.

The measurements configured in the currently active channels are performed one after the other in the order of the tabs until the Sequencer is stopped. The result displays in the individual channels are updated as the measurements are performed.

To stop the Sequencer

➤ To stop the Sequencer temporarily, press the highlighted RUN SINGLE or RUN CONT key (not for a channel-defined sequence). To continue the Sequencer, press the key again.

To stop the Sequencer permanently, select the "Sequencer" icon in the toolbar and toggle the "Sequencer" softkey to "Off".

Available Measurement Functions

4 Measurements

In the Spectrum application, the R&S FSW provides a variety of different measurement functions.

- Basic measurements measure the spectrum of your signal or watch your signal in time domain
- Power measurements calculate the powers involved in modulated carrier signals
- Emission measurements detect unwanted signal emission
- Statistic measurements evaluate the spectral distribution of the signal
- Special measurements provide characteristic values of the signal

The individual functions are described in detail in the following chapters.

 Channel Power and Adjacent-Channel Power (ACLR) Measurement	•	Available Measurement Functions	30
 Occupied Bandwidth Measurement (OBW)	•	Channel Power and Adjacent-Channel Power (ACLR) Measurement	34
 Spectrum Emission Mask (SEM) Measurement. Spurious Emissions Measurement. Statistical Measurements (APD, CCDF). Time Domain Power Measurement. Harmonic Distortion Measurement. Third Order Intercept (TOI) Measurement. AM Modulation Depth Measurement. 151 	•	Carrier-to-Noise Measurements	63
 Spurious Emissions Measurement	•	Occupied Bandwidth Measurement (OBW)	67
 Statistical Measurements (APD, CCDF)	•	Spectrum Emission Mask (SEM) Measurement	73
 Time Domain Power Measurement	•	Spurious Emissions Measurement	104
 Harmonic Distortion Measurement	•	Statistical Measurements (APD, CCDF)	117
 Third Order Intercept (TOI) Measurement	•	Time Domain Power Measurement	131
AM Modulation Depth Measurement	•	Harmonic Distortion Measurement	136
·	•	Third Order Intercept (TOI) Measurement	142
Basic Measurements	•	AM Modulation Depth Measurement	151
	•	Basic Measurements	154

4.1 Available Measurement Functions

The measurement function determines which settings, functions and evaluation methods are available in the R&S FSW. The various measurement functions are described in detail here. They are selected in the "Select Measurement" dialog box that is displayed when you press the MEAS key or tap "Select Measurement" in the configuration "Overview".

When you select a measurement function, the measurement is started with its default settings immediately and the corresponding measurement configuration menu is displayed. The measurement configuration menu can be displayed at any time by pressing the MEAS CONFIG key.

The easiest way to configure measurements is using the configuration "Overview", see chapter 5.1, "Configuration Overview", on page 159.

In addition to the measurement-specific parameters, the general parameters can be configured as usual, see chapter 5, "Common Measurement Settings", on page 159. Many measurement functions provide special result displays or evaluation methods; however, in most cases the general evaluation methods are also available, see chapter 6, "Common Analysis and Display Functions", on page 228.

After a preset, the R&S FSW performs a basic frequency sweep.

Available Measurement Functions

Frequency Sweep	31
Zero Span	31
Ch Power ACLR	31
C/N, C/No	32
OBW	32
Spectrum Emission Mask	32
Spurious Emissions	
Time Domain Power	32
APD	
CCDF	33
TOI	33
AM Mod Depth	
Harmonic Distortion	
Marker Functions	
All Functions Off	34

Frequency Sweep

A common frequency sweep of the input signal over a specified span. Can be used for general purposes to obtain basic measurement results such as peak levels and spectrum traces. The "Frequency" menu is displayed. This is the default measurement if no other function is selected.

Use the general measurement settings to configure the measurement, e.g. via the "Overview" (see chapter 5, "Common Measurement Settings", on page 159).

SCPI command:

```
INITiate[:IMMediate] on page 461
INITiate:CONTinuous on page 460
```

Zero Span

A sweep in the time domain at the specified (center) frequency, i.e. the frequency span is set to zero. The display shows the time on the x-axis and the signal level on the y-axis, as on an oscilloscope. On the time axis, the grid lines correspond to 1/10 of the current sweep time.

The "Frequency" menu is displayed. Use the general measurement settings to configure the measurement, e.g. via the "Overview" (see chapter 5, "Common Measurement Settings", on page 159).

Most result evaluations can also be used for zero span measurements, although some functions (e.g. markers) may work slightly differently and some may not be available. If so, this will be indicated in the function descriptions (see chapter 6, "Common Analysis and Display Functions", on page 228).

SCPI command:

```
INITiate[:IMMediate] on page 461
INITiate:CONTinuous on page 460
```

Ch Power ACLR

Measures the active channel or adjacent-channel power for one or more carrier signals, depending on the current measurement configuration, and opens a submenu to configure the channel power measurement.

Available Measurement Functions

For details see chapter 4.2, "Channel Power and Adjacent-Channel Power (ACLR) Measurement", on page 34.

SCPI command:

chapter 10.3.3, "Measuring the Channel Power and ACLR", on page 467

C/N, C/No

Measures the carrier/noise ratio and opens a submenu to configure the measurement. Measurements without (C/N) and measurements with reference to the bandwidth (C/No) are possible.

Carrier/noise measurement is only possible in the frequency domain (span > 0).

For details see chapter 4.3, "Carrier-to-Noise Measurements", on page 63.

SCPI command:

chapter 10.3.4, "Measuring the Carrier-to-Noise Ratio", on page 483

OBW

Measures the occupied bandwidth, i.e. the bandwidth which must contain a defined percentage of the power, and opens a submenu to configure the measurement. For details see chapter 4.4, "Occupied Bandwidth Measurement (OBW)", on page 67.

OBW measurement is only possible in the frequency domain (span > 0).

SCPI command:

chapter 10.3.5, "Measuring the Occupied Bandwidth", on page 483

Spectrum Emission Mask

Activates a Spectrum Emission Mask (SEM) measurement, which monitors compliance with a spectral mask, and opens a submenu to configure the measurement.

For details see chapter 4.5, "Spectrum Emission Mask (SEM) Measurement", on page 73.

SCPI command:

```
SENS: SWE: MODE ESP, see [SENSe:] SWEep: MODE on page 487 chapter 10.3.6, "Measuring the Spectrum Emission Mask", on page 485
```

Spurious Emissions

Activates the Spurious Emissions measurement, which monitors unwanted RF products outside the assigned frequency band generated by an amplifier. A submenu to configure the measurement is opened.

For details see chapter 4.6, "Spurious Emissions Measurement", on page 104.

SCPI command:

```
SENS: SWE: MODE LIST, see [SENSe:] SWEep: MODE on page 487 chapter 10.3.7, "Measuring Spurious Emissions", on page 511
```

Time Domain Power

Measures the power in zero span and opens a submenu to configure the measurement. For details see chapter 4.12, "Basic Measurements", on page 154.

Available Measurement Functions

A time domain power measurement is only possible for zero span.

SCPI command:

```
CALCulate<n>:MARKer<m>:FUNCtion:SUMMary[:STATe] on page 533 chapter 10.3.9, "Measuring the Time Domain Power", on page 532
```

APD

Measures the amplitude probability density (APD) and opens a submenu to configure the measurement.

For details see chapter 4.7, "Statistical Measurements (APD, CCDF)", on page 117.

SCPI command:

```
CALCulate<n>:STATistics:APD[:STATe] on page 523 chapter 10.3.8, "Analyzing Statistics (APD, CCDF)", on page 523
```

CCDF

Measures the complementary cumulative distribution function (CCDF) and opens a submenu to configure the measurement.

For details see chapter 4.7, "Statistical Measurements (APD, CCDF)", on page 117.

SCPI command:

```
CALCulate<n>:STATistics:CCDF[:STATe] on page 523 chapter 10.3.8, "Analyzing Statistics (APD, CCDF)", on page 523
```

TOI

Measures the third order intercept point and opens a submenu to configure the measurement.

For details see chapter 4.10, "Third Order Intercept (TOI) Measurement", on page 142.

SCPI command:

```
CALCulate<n>:MARKer<m>:FUNCtion:TOI[:STATe] on page 543
CALCulate<n>:MARKer<m>:FUNCtion:TOI:RESult? on page 544
chapter 10.3.11, "Measuring the Third Order Intercept Point", on page 542
```

AM Mod Depth

Measures the AM modulation depth and opens a submenu to configure the measurement. An AM-modulated carrier is required in the window to ensure correct operation.

For details see chapter 4.11, "AM Modulation Depth Measurement", on page 151.

SCPI command:

```
CALCulate<n>:MARKer<m>:FUNCtion:MDEPth[:STATe] on page 545 CALCulate<n>:MARKer<m>:FUNCtion:MDEPth:RESult? on page 545 chapter 10.3.12, "Measuring the AM Modulation Depth", on page 544
```

Harmonic Distortion

Measures the harmonic distortion, including the total harmonic distortion, and opens a submenu to configure the measurement.

For details see chapter 4.9, "Harmonic Distortion Measurement", on page 136.

SCPI command:

chapter 10.3.10, "Measuring the Harmonic Distortion", on page 539

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Marker Functions

In addition to the measurement functions, some special marker functions are available. See chapter 6.4.2.3, "Marker Function Configuration", on page 288.

All Functions Off

Switches off all measurement functions and returns to a basic frequency sweep.

4.2 Channel Power and Adjacent-Channel Power (ACLR) Measurement

Measuring the power in channels adjacent to the carrier or transmission channel is useful to detect interference. The results are displayed as a bar chart for the individual channels.

•	About Channel Power Measurements	34
	Channel Power Results	
	Channel Power Basics	
•	Channel Power Configuration	43
	How to Perform Channel Power Measurements	
	Measurement Examples	
	Reference: Predefined CP/ACLR Standards	

4.2.1 About Channel Power Measurements

Measuring channel power and adjacent channel power is one of the most important tasks for a signal analyzer with the necessary test routines in the field of digital transmission. While, theoretically, channel power could be measured at highest accuracy with a power meter, its low selectivity means that it is not suitable for measuring adjacent channel power as an absolute value or relative to the transmit channel power. The power in the adjacent channels can only be measured with a selective power meter.

A signal analyzer cannot be classified as a true power meter, because it displays the IF envelope voltage. However, it is calibrated such as to correctly display the power of a pure sine wave signal irrespective of the selected detector. This calibration cannot be applied for non-sinusoidal signals. Assuming that the digitally modulated signal has a Gaussian amplitude distribution, the signal power within the selected resolution bandwidth can be obtained using correction factors. These correction factors are normally used by the signal analyzer's internal power measurement routines in order to determine the signal power from IF envelope measurements. These factors apply if and only if the assumption of a Gaussian amplitude distribution is correct.

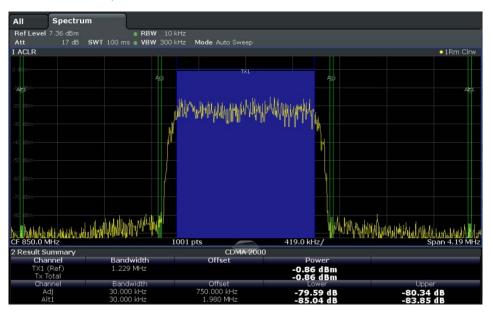
Apart from this common method, the R&S FSW also has a true power detector, i.e. an RMS detector. It displays the power of the test signal within the selected resolution bandwidth correctly, irrespective of the amplitude distribution, without additional correction factors being required.

A detailed measurement example is provided in chapter 4.2.6, "Measurement Examples", on page 56.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

4.2.2 Channel Power Results

For channel or adjacent-channel power measurements, the individual channels are indicated by different colored bars in the diagram. The height of each bar corresponds to the measured power of that channel. In addition, the name of the channel ("Adj", "Alt1", "TX1", etc. or a user-defined name) is indicated above the bar (separated by a line which has no further meaning). For "Fast ACLR" measurements, which are performed in the time domain, the power versus time is shown for each channel.



Results are provided for the TX channel and the number of defined adjacent channels above and below the TX channel. If more than one TX channel is defined, the carrier channel to which the relative adjacent-channel power values should be referenced must be defined. By default, this is the TX channel with the maximum power.

Table 4-1: Measurements performed depending on the number of adjacent channels

0	Only the channel powers are measured.
1	The channel powers and the power of the upper and lower adjacent channel are measured.
2	The channel powers, the power of the upper and lower adjacent channel, and of the next higher and lower channel (alternate channel 1) are measured.
3	The channel power, the power of the upper and lower adjacent channel, the power of the next higher and lower channel (alternate channel 1), and of the next but one higher and lower adjacent channel (alternate channel 2) are measured.
12	The channel power, the power of the upper and lower adjacent channel, and the power of all the higher and lower channels (alternate channels 1 to 11) are measured.



In the R&S FSW's display, only the first neighboring channel of the carrier (TX) channel is labelled "Adj" (adjacent) channel; all others are labelled "Alt" (alternate) channels. In this manual, "adjacent" refers to both adjacent and alternate channels.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

The measured power values for the TX and adjacent channels are also output as a table in the second window. Which powers are measured depends on the number of configured channels.

For each channel, the following values are displayed:

Label	Description
Channel	Channel name as specified in the "Channel Settings" (see "Channel Names" on page 53).
Bandwidth	Configured channel bandwidth (see "Channel Bandwidths" on page 51)
Offset	Offset of the channel to the TX channel (Configured channel spacing, see "Channel Bandwidths" on page 51)
Power (Lower/Upper)	The measured power values for the TX and lower and upper adjacent channels. The powers of the transmission channels are output in dBm or dBm/Hz, or in dBc, relative to the specified reference TX channel.

Retrieving Results via Remote Control

All or specific channel power measurement results can be retrieved using the CALC:MARK:FUNC:POW:RES? command from a remote computer (see CALCulate<n>:MARKer<m>:FUNCtion:POWer:RESult? on page 464). Alternatively, the results can be output as channel power density, i.e. in reference to the measurement bandwidth.

Furthermore, the measured power values of the displayed trace can be retrieved as usual using the TRAC:DATA? commands (see TRACe < n > [:DATA] on page 625). In this case, the measured power value for each sweep point (by default 1001) is returned.

4.2.3 Channel Power Basics

Some background knowledge on basic terms and principles used in channel power measurements is provided here for a better understanding of the required configuration settings.

•	Measurement Methods	36
•	Measurement Repeatability	38
	Recommended Common Measurement Parameters	39

4.2.3.1 Measurement Methods

The channel power is defined as the integration of the power across the channel bandwidth.

The Adjacent Channel Leakage Power Ratio (ACLR), also known as the Adjacent Channel Power Ratio (ACPR), is defined as the ratio between the total power of the adjacent channel to the carrier channel's power. An ACLR measurement with several carrier channels (also known as transmission or TX channels) is also possible and is referred to as a "multi-carrier ACLR measurement".

Channel Power and Adjacent-Channel Power (ACLR) Measurement

There are two possible methods for measuring channel and adjacent channel power with a signal analyzer:

- IBW method (Integration Bandwidth Method)
- Fast ACLR(Zero-span method), i.e. using a channel filter

IBW method

When measuring the channel power, the R&S FSW integrates the linear power which corresponds to the levels of the measurement points within the selected channel. The signal analyzer uses a resolution bandwidth which is far smaller than the channel bandwidth. When sweeping over the channel, the channel filter is formed by the passband characteristics of the resolution bandwidth.

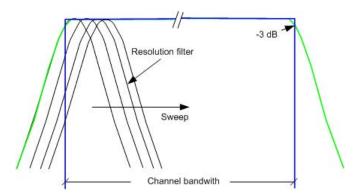


Fig. 4-1: Approximating the channel filter by sweeping with a small resolution bandwidth

The following steps are performed:

1. The linear power of all the trace points within the channel is calculated.

```
P_i = 10^{(Li/10)}
```

where P_i = power of the trace pixel i

L_i = displayed level of trace point i

- 2. The powers of all trace points within the channel are summed up and the sum is divided by the number of trace points in the channel.
- 3. The result is multiplied by the quotient of the selected channel bandwidth and the noise bandwidth of the resolution filter (RBW).

Since the power calculation is performed by integrating the trace within the channel bandwidth, this method is called the IBW method (Integration Bandwidth method).

Fast ACLR

The integrated bandwidth method (IBW) calculates channel power and ACLR from the trace data obtained during a continuous sweep over the selected span. Most parts of this sweep are neither part of the channel itself nor the defined adjacent channels. Therefore, most of the samples taken during the sweeptime cannot be used for channel power or ACLR calculation.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

To decrease the measurement times, the R&S FSW offers a "Fast ACLR" mode. In Fast ACLR mode, the power of the frequency range between the channels of interest is not measured, because it is not required for channel power or ACLR calculation. The measurement time per channel is set with the sweep time. It is equal to the selected measurement time divided by the selected number of channels.

In the "Fast ACLR" mode, the R&S FSW measures the power of each channel in the time domain, with the defined channel bandwidth, at the center frequency of the channel in question. The digital implementation of the resolution bandwidths makes it possible to select filter characteristics that are precisely tailored to the signal. In case of CDMA2000, for example, the power in the useful channel is measured with a bandwidth of 1.23 MHz and that of the adjacent channels with a bandwidth of 30 kHz. Therefore the R&S FSW changes from one channel to the other and measures the power at a bandwidth of 1.23 MHz or 30 kHz using the RMS detector.

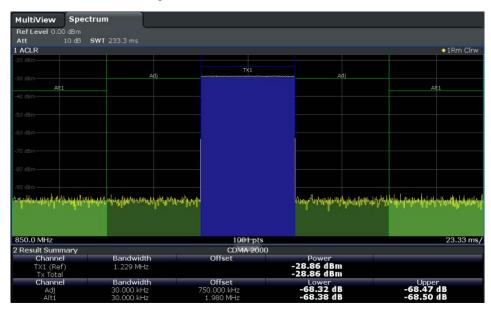


Fig. 4-2: Measuring the channel power and adjacent channel power ratio for CDMA2000 signals with zero span (Fast ACLR)

4.2.3.2 Measurement Repeatability

The repeatability of the results, especially in the narrow adjacent channels, strongly depends on the measurement time for a given resolution bandwidth. A longer sweep time may increase the probability that the measured value converges to the true value of the adjacent channel power, but obviously increases measurement time.

Assuming a measurement with five channels (1 channel plus 2 lower and 2 upper adjacent channels) and a sweep time of 100 ms, a measurement time per channel of 20 ms is required. The number of effective samples taken into account for power calculation in one channel is the product of sweeptime in channel times the selected resolution bandwidth.

Assuming a sweeptime of 100 ms, there are $(30 \text{ kHz} / 4.19 \text{ MHz}) * 100 \text{ ms} * 10 \text{ kHz} \approx 7 \text{ samples}$. Whereas in Fast ACLR mode, there are $(100 \text{ ms} / 5) * 30 \text{ kHz} \approx 600 \text{ samples}$.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Comparing these numbers explains the increase of repeatability with a 95% confidence level (2δ) from \pm 2.8 dB to \pm 0.34 dB for a sweeptime of 100 ms.

For the same repeatability, the sweep time would have to be set to 8.5 s with the integration method. The figure 4-3 shows the standard deviation of the results as a function of the sweep time.

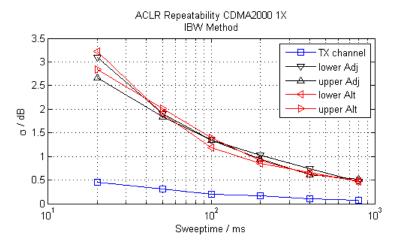


Fig. 4-3: Repeatability of adjacent channel power measurement on CDMA2000 standard signals if the integration bandwidth method is used

The figure 4-4 shows the repeatability of power measurements in the transmit channel and of relative power measurements in the adjacent channels as a function of sweep time. The standard deviation of measurement results is calculated from 100 consecutive measurements. Take scaling into account if comparing power values.

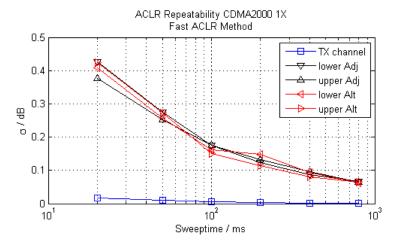


Fig. 4-4: Repeatability of adjacent channel power measurements on CDMA2000 signals in the fast ACLR mode

4.2.3.3 Recommended Common Measurement Parameters

The following sections provide recommendations on the most important measurement parameters for channel power measurements.

Channel Power and Adjacent-Channel Power (ACLR) Measurement



All instrument settings for the selected channel setup (channel bandwidth, channel spacing) can be optimized automatically using the "Adjust Settings" function (see "Optimized Settings (Adjust Settings)" on page 49).

The easiest way to configure a measurement is using the configuration "Overview", see chapter 5.1, "Configuration Overview", on page 159.

Sweep Time

The sweep time is selected depending on the desired reproducibility of results. Reproducibility increases with sweep time since power measurement is then performed over a longer time period. As a general approach, it can be assumed that approx. 500 non-correlated measured values are required for a reproducibility of 0.5 dB (99 % of the measurements are within 0.5 dB of the true measured value). This holds true for white noise. The measured values are considered as non-correlated if their time interval corresponds to the reciprocal of the measured bandwidth.

With IS 136 the measurement bandwidth is approx. 25 kHz, i.e. measured values at an interval of 40 µs are considered as non-correlated. A measurement time of 40 ms is thus required per channel for 1000 measured values. This is the default sweep time which the R&S FSW sets in coupled mode. Approx. 5000 measured values are required for a reproducibility of 0.1 dB (99 %), i.e. the measurement time is to be increased to 200 ms.

The number of A/D converter values, N, used to calculate the power, is defined by the sweep time. The time per trace pixel for power measurements is directly proportional to the selected sweep time.

If the sample detector is used, it is best to select the smallest sweep time possible for a given span and resolution bandwidth. The minimum time is obtained if the setting is coupled. This means that the time per measurement is minimal. Extending the measurement time does not have any advantages as the number of samples for calculating the power is defined by the number of trace points in the channel.

If the RMS detector is used, the repeatability of the measurement results can be influenced by the selection of sweep times. Repeatability is increased at longer sweep times.

If the RMS detector is used, the number of samples can be estimated as follows:

Since only uncorrelated samples contribute to the RMS value, the number of samples can be calculated from the sweep time and the resolution bandwidth.

Samples can be assumed to be uncorrelated if sampling is performed at intervals of 1/RBW. The number of uncorrelated samples is calculated as follows:

N_{decorr} = SWT * RBW

(N_{decorr} means uncorrelated samples)

The number of uncorrelated samples per trace pixel is obtained by dividing N_{decorr} by 1001 (= pixels per trace).

The "Sweep Time" can be defined using the softkey in the "Ch Power" menu or in the "Sweep" configuration dialog box (see "Sweep Time" on page 49).

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Frequency Span

The frequency span must cover at least the channels to be measured plus a measurement margin of approximately 10 %.

If the frequency span is large in comparison to the channel bandwidth (or the adjacent-channel bandwidths) being analyzed, only a few points on the trace are available per channel. This reduces the accuracy of the waveform calculation for the channel filter used, which has a negative effect on the measurement accuracy. It is therefore strongly recommended that the formulas mentioned be taken into consideration when selecting the frequency span.

The frequency span for the defined channel settings can be optimized using the "Adjust Settings" function in the "Ch Power" menu or the "General Settings" tab of the "ACLR Setup" dialog box (see "Optimized Settings (Adjust Settings)" on page 49). You can set the frequency span manually in the "Frequency" configuration dialog box, see chapter 5.3.3, "How To Define the Frequency Range", on page 183.

For channel power measurements the "Adjust Settings" function sets the frequency span as follows:

"(No. of transmission channels -1) x transmission channel spacing +2 x transmission channel bandwidth + measurement margin"

For adjacent-channel power measurements, the "Adjust Settings" function sets the frequency span as a function of the number of transmission channels, the transmission channel spacing, the adjacent-channel spacing, and the bandwidth of one of adjacent-channels ADJ, ALT1 or ALT2, whichever is furthest away from the transmission channels:

"(No. of transmission channels – 1) x transmission channel spacing + 2 x (adjacent-channel spacing + adjacent-channel bandwidth) + measurement margin"

The measurement margin is approx. 10 % of the value obtained by adding the channel spacing and the channel bandwidth.

Resolution Bandwidth (RBW)

To ensure both acceptable measurement speed and the required selection (to suppress spectral components outside the channel to be measured, especially of the adjacent channels), the resolution bandwidth must not be selected too small or too large. As a general approach, the resolution bandwidth is to be set to values between 1% and 4% of the channel bandwidth.

A larger resolution bandwidth can be selected if the spectrum within the channel to be measured and around it has a flat characteristic. In the standard setting, e.g. for standard IS95A REV at an adjacent channel bandwidth of 30 kHz, a resolution bandwidth of 30 kHz is used. This yields correct results since the spectrum in the neighborhood of the adjacent channels normally has a constant level.

The resolution bandwidth for the defined channel settings can be optimized using the "Adjust Settings" function in the "Ch Power" menu or the "General Settings" tab of the "ACLR Setup" dialog box (see "Optimized Settings (Adjust Settings)" on page 49). You can set the RBW manually in the "Bandwidth" configuration dialog box, see "RBW" on page 200.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

With the exception of the IS95 CDMA standards, the "Adjust Settings" function sets the resolution bandwidth (RBW) as a function of the channel bandwidth:

"RBW ≤ 1/40 of channel bandwidth"

The maximum possible resolution bandwidth (with respect to the requirement RBW \leq 1/40) resulting from the available RBW steps (1, 3) is selected.

Video Bandwidth (VBW)

For a correct power measurement, the video signal must not be limited in bandwidth. A restricted bandwidth of the logarithmic video signal would cause signal averaging and thus result in a too low indication of the power (-2.51 dB at very low video bandwidths). The video bandwidth should therefore be selected at least three times the resolution bandwidth:

"VBW ≥ 3 x RBW"

The video bandwidth for the defined channel settings can be optimized using the "Adjust Settings" function in the "Ch Power" menu or the "General Settings" tab of the "ACLR Setup" dialog box (see "Optimized Settings (Adjust Settings)" on page 49). You can set the VBW manually in the "Bandwidth" configuration dialog box, see "VBW" on page 201.

The video bandwidth (VBW) is set as a function of the channel bandwidth (see formula above) and the smallest possible VBW with regard to the available step size is selected.

Detector

The RMS detector correctly indicates the power irrespective of the characteristics of the signal to be measured. The whole IF envelope is used to calculate the power for each measurement point. The IF envelope is digitized using a sampling frequency which is at least five times the resolution bandwidth which has been selected. Based on the sample values, the power is calculated for each measurement point using the following formula:

$$P_{RMS} = \sqrt{\frac{1}{N}} \cdot \sum_{i=1}^{N} s_i^2$$

where:

 s_i = linear digitized video voltage at the output of the A/D converter

N = number of A/D converter values per measurement point

P_{RMS} = power represented by a measurement point

When the power has been calculated, the power units are converted into decibels and the value is displayed as a measurement point.

In principle, the sample detector would be possible as well. Due to the limited number of measurement points used to calculate the power in the channel, the sample detector would yield less stable results.

The RMS detector can be set for the defined channel settings automatically using the "Adjust Settings" function in the "Ch Power" menu or the "General Settings" tab of the "ACLR Setup" dialog box (see "Optimized Settings (Adjust Settings)" on page 49). You

Channel Power and Adjacent-Channel Power (ACLR) Measurement

can set the detector manually in the "Traces" configuration dialog box, see "Detector" on page 250.

Trace Averaging

Averaging, which is often performed to stabilize the measurement results, leads to a level indication that is too low and should therefore be avoided. The reduction in the displayed power depends on the number of averages and the signal characteristics in the channel to be measured.

The "Adjust Settings" function switches off trace averaging. You can deactivate the trace averaging manually in the "Traces" configuration dialog box, see "Average Mode" on page 250.

Reference Level

To achieve an optimum dynamic range, the reference level has to be set such that the signal is as close to the reference level as possible without forcing an overload message or limiting the dynamic range by an S/N ratio that is too small. Since the measurement bandwidth for channel power measurements is significantly smaller than the signal bandwidth, the signal path may be overloaded although the trace is still significantly below the reference level.

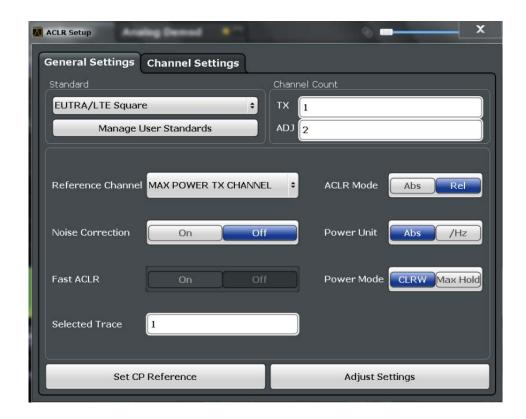


The reference level is not influenced by the selection of a predefined standard or by the automatic setting adjustment. The reference level can be set automatically using the "Auto Level" function in the AUTO SET menu, or manually in the "Amplitude" menu.

4.2.4 Channel Power Configuration

Channel Power (CP) and Adjacent-Channel Power (ACLR) measurements are selected via the "Channel Power ACLR" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "ACLR Setup" dialog box, which is displayed when you select the "CP/ACLR Config" softkey from the "CH Power" menu.

Channel Power and Adjacent-Channel Power (ACLR) Measurement





The easiest way to configure a measurement is using the configuration "Overview", see chapter 5.1, "Configuration Overview", on page 159.

The remote commands required to perform these tasks are described in chapter 10.3.3, "Measuring the Channel Power and ACLR", on page 467.

- 4.2.4.1 General CP/ACLR Measurement Settings

General measurement settings are defined in the "ACLR Setup" dialog, in the "General Settings" tab.

Standard	45
L Predefined Standards	45
L User-Defined Standards	
Number of Channels (TX, ADJ)	
Reference Channel	47
Noise cancellation	47
Fast ACLR	48
Selected Trace	48
Absolute and Relative Values (ACLR Mode)	48
Channel Power Levels and Density (Power Unit)	
Power Mode	49

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Setting a Fixed Reference for Channel Power Measurements (Set CP Reference)	
	49
Optimized Settings (Adjust Settings)	49
Sweep Time	

Standard

The main measurement settings can be stored as a standard file. When such a standard is loaded, the required channel and general measurement settings are automatically set on the R&S FSW. However, the settings can be changed. Predefined standards are available for standard measurements, but standard files with user-defined configurations can also be created.

Predefined Standards ← Standard

Predefined standards contain the main measurement settings for standard measurements. When such a standard is loaded, the required channel settings are automatically set on the R&S FSW. However, the settings can be changed.

The predefined standards contain the following settings:

- Channel bandwidths
- Channel spacings
- Detector
- Trace Average setting
- Resolution Bandwidth (RBW)
- Weighting Filter

Predefined standards can be selected via the "CP/ACLR" softkey in the "CH Power" menu or in the "General Settings" tab of the "CP/ACLR Setup" dialog box.

For details on the available standards see chapter 4.2.7, "Reference: Predefined CP/ACLR Standards", on page 62.

SCPI command:

CALCulate<n>:MARKer<m>:FUNCtion:POWer:PRESet on page 468

User-Defined Standards ← **Standard**

In addition to the predefined standards you can save your own standards with your specific measurement settings in an xml file so you can use them again at a later time.

Note that ACLR user standards are not supported for Fast ACLR and Multi-Carrier ACLR measurements.

Note: User standards created on an analyzer of the R&S FSP family are compatible to the R&S FSW. User standards created on an R&S FSW, however, are not necessarily compatible to the analyzers of the R&S FSP family and may not work there.

The following parameter definitions are saved in a user-defined standard:

- Number of adjacent channels
- Channel bandwidth of transmission (Tx), adjacent (Adj) and alternate (Alt) channels
- Channel spacings
- Weighting filters
- Resolution bandwidth
- Video bandwidth
- Detector
- ACLR limits and their state

Channel Power and Adjacent-Channel Power (ACLR) Measurement

- Sweep time and sweep time coupling
- Trace and power mode

User-defined standards are managed in the "Manage" dialog box which is displayed when you select the "Manage User Standards" button in the "General Settings" tab of the "CP/ACLR Setup" dialog box.



In the "Manage" dialog box you can save the current measurement settings as a userdefined standard, or load a stored measurement configuration. Furthermore, you can delete an existing configuration file.

For details see chapter 4.2.5.3, "How to Manage User-Defined Configurations", on page 55.

SCPI command:

To query all available standards:

CALCulate<n>:MARKer<m>:FUNCtion:POWer:STANdard:CATalog?

on page 468

To load a standard:

CALCulate<n>:MARKer<m>:FUNCtion:POWer:PRESet on page 468

To save a standard:

CALCulate<n>:MARKer<m>:FUNCtion:POWer:STANdard:SAVE on page 469

To delete a standard:

CALCulate<n>:MARKer<m>:FUNCtion:POWer:STANdard:DELete on page 468

Number of Channels (TX, ADJ)

Up to 18 carrier channels and up to 12 adjacent channels can be defined.

Results are provided for the TX channel and the number of defined adjacent channels above and below the TX channel. If more than one TX channel is defined, the carrier channel to which the relative adjacent-channel power values should be referenced must be defined (see "Reference Channel" on page 47).

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Note: If several carriers (TX channels) are activated for the measurement, the number of sweep points is increased to ensure that adjacent-channel powers are measured with adequate accuracy.

For more information on how the number of channels affects the measured powers, see chapter 4.2.2, "Channel Power Results", on page 35.

SCPI command:

Number of TX channels:

```
[SENSe:] POWer: ACHannel: TXCHannel: COUNt on page 472
```

Number of Adjacent channels:

```
[SENSe:] POWer: ACHannel: ACPairs on page 469
```

Reference Channel

The measured power values in the adjacent channels can be displayed relative to the transmission channel. If more than one TX channel is defined, you must select which one is to be used as a reference channel.

TX Channel 1	Transmission channel 1 is used.
Min Power TX Channel	The transmission channel with the lowest power is used as a reference channel.
Max Power TX Chan- nel	The transmission channel with the highest power is used as a reference channel (Default).
Lowest & Highest Channel	The outer left-hand transmission channel is the reference channel for the lower adjacent channels, the outer right-hand transmission channel that for the upper adjacent channels.

SCPI command:

```
[SENSe:] POWer: ACHannel: REFerence: TXCHannel: MANual on page 475 [SENSe:] POWer: ACHannel: REFerence: TXCHannel: AUTO on page 474
```

Noise cancellation

The results can be corrected by the instrument's inherent noise, which increases the dynamic range.

In this case, a reference measurement of the instrument's inherent noise is carried out. The measured noise power is then subtracted from the power in the channel that is being analyzed (first active trace only).

The inherent noise of the instrument depends on the selected center frequency, resolution bandwidth and level setting. Therefore, the correction function is disabled whenever one of these parameters is changed. A disable message is displayed on the screen. To enable the correction function after changing one of these settings, activate it again. A new reference measurement is carried out.

Noise cancellation is also available in zero span.

Currently, noise cancellation is only available for the following trace detectors (see "Detector" on page 250):

- RMS
- Average
- Sample

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Positive Peak

SCPI command:

[SENSe:] POWer: NCORrection on page 576

Fast ACLR

If activated, instead of using the IBW method, the R&S FSW sets the center frequency to the different channel center frequencies consecutively and measures the power with the selected measurement time (= sweep time/number of channels).

SCPI command:

[SENSe:] POWer: HSPeed on page 479

Selected Trace

The CP/ACLR measurement can be performed on any active trace.

SCPI command:

[SENSe:] POWer: TRACe on page 467

Absolute and Relative Values (ACLR Mode)

The powers of the adjacent channels are output in dBm or dBm/Hz (absolute values), or in dBc, relative to the specified reference TX channel.

"Abs" The absolute power in the adjacent channels is displayed in the unit of

the y-axis, e.g. in dBm, dBµV.

"Rel" The level of the adjacent channels is displayed relative to the level of

the transmission channel in dBc.

SCPI command:

[SENSe:] POWer: ACHannel: MODE on page 480

Channel Power Levels and Density (Power Unit)

By default, the channel power is displayed in absolute values. If "/Hz" is activated, the channel power density is displayed instead. Thus, the absolute unit of the channel power is switched from dBm to dBm/Hz.

Note: The channel power density in dBm/Hz corresponds to the power inside a bandwidth of 1 Hz and is calculated as follows:

"channel power density = channel power – log₁₀(channel bandwidth)"

Thus you can measure the signal/noise power density, for example, or use the additional functions Absolute and Relative Values (ACLR Mode) and Reference Channel to obtain the signal to noise ratio.

SCPI command:

CALCulate<n>:MARKer<m>:FUNCtion:POWer:RESult:PHZ on page 480

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Power Mode

The measured power values can be displayed directly for each trace ("Clear/Write"), or only the maximum values over a series of measurements can be displayed ("Max Hold"). In the latter case, the power values are calculated from the current trace and compared with the previous power value using a maximum algorithm. The higher value is retained. If "Max Hold" mode is activated, "Pwr Max" is indicated in the table header. Note that the *trace* mode remains unaffected by this setting.

SCPI command:

CALCulate<n>:MARKer<m>:FUNCtion:POWer:MODE on page 464

Setting a Fixed Reference for Channel Power Measurements (Set CP Reference)

For pure channel power measurements (no adjacent channels defined) with only one TX channel, the currently measured channel power can be used as a fixed reference value for subsequent channel power measurements.

When you select this button, the channel power currently measured on the TX channel is stored as a fixed reference power. In the following channel power measurements, the power is indicated relative to the fixed reference power. The reference value is displayed in the "Reference" field (in relative ACLR mode); the default value is 0 dBm.

Note: In adjacent-channel power measurement, the power is always referenced to a transmission channel (see "Reference Channel" on page 47), thus, this function is not available.

SCPI command:

[SENSe:] POWer: ACHannel: REFerence: AUTO ONCE on page 474

Optimized Settings (Adjust Settings)

All instrument settings for the selected channel setup (channel bandwidth, channel spacing) can be optimized automatically.

The adjustment is carried out only once. If necessary, the instrument settings can be changed later.

The following settings are optimized by "Adjust Settings":

- "Frequency Span" on page 41
- "Resolution Bandwidth (RBW)" on page 41
- "Video Bandwidth (VBW)" on page 42
- "Detector" on page 42
- "Trace Averaging" on page 43

Note: The reference level is not affected by this function. To adjust the reference level automatically, use the Setting the Reference Level Automatically (Auto Level) function in the AUTO SET menu.

SCPI command:

[SENSe:] POWer: ACHannel: PRESet on page 466

Sweep Time

With the RMS detector, a longer sweep time increases the stability of the measurement results. For recommendations on setting this parameter, see "Sweep Time" on page 40.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

The sweep time can be set via the softkey in the "Ch Power" menu and is identical to the general setting in the "Sweep" configuration dialog box.

SCPI command:

[SENSe:] SWEep:TIME on page 573

4.2.4.2 Channel Setup

The "Channel Settings" tab in the "ACLR Setup" dialog box provides all the channel settings to configure the channel power or ACLR measurement. You can define the channel settings for all channels, independant of the defined number of *used* TX or adjacent channels (see "Number of Channels (TX, ADJ)" on page 46).

For details on setting up channels, see chapter 4.2.5.2, "How to Set up the Channels", on page 54.



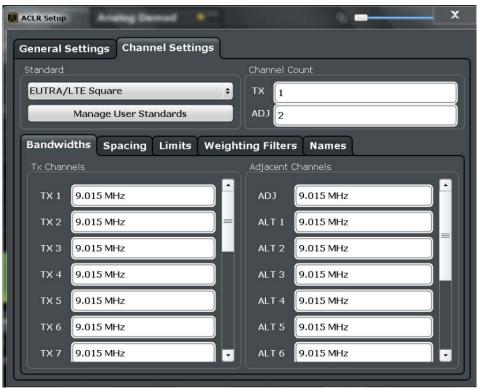
In addition to the specific channel settings, the general settings Standard and "Number of Channels (TX, ADJ)" on page 46 are also available in this tab.

The following settings are available in individual subtabs of the "Channel Settings" tab.

Channel Bandwidths	51
Channel Spacings	51
Limit Checking	
Weighting Filters	
Channel Names	53

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Channel Bandwidths



The transmission-channel bandwidth is normally defined by the transmission standard. The correct bandwidth is set automatically for the selected standard. The bandwidth for each channel is indicated by a colored bar in the display.

For measurements that require channel bandwidths which deviate from those defined in the selected standard, use the IBW method ("Fast ACLR Off"). With the IBW method, the channel bandwidth borders are right and left of the channel center frequency. Thus, you can visually check whether the entire power of the signal under test is within the selected channel bandwidth.

The value entered for any TX channel is automatically also defined for all subsequent TX channels. Thus, only one value needs to be entered if all TX channels have the same bandwidth.

The value entered for any ADJ or ALT channel is automatically also defined for all alternate (ALT) channels. Thus, only one value needs to be entered if all adjacent channels have the same bandwidth.

SCPI command:

```
[SENSe:]POWer:ACHannel:BANDwidth|BWIDth[:CHANnel<ch>] on page 470
[SENSe:]POWer:ACHannel:BANDwidth|BWIDth:ACHannel on page 470
[SENSe:]POWer:ACHannel:BANDwidth|BWIDth:ALTernate<ch> on page 470
```

Channel Spacings

Channel spacings are normally defined by the selected standard but can be changed.

If the spacings are not equal, the channel distribution according to the center frequency is as follows:

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Odd number of TX channels	The middle TX channel is centered to center frequency.
Even number of TX channels	The two TX channels in the middle are used to calculate the frequency between those two channels. This frequency is aligned to the center frequency.

The spacings between all TX channels can be defined individually. When you change the spacing for one channel, the value is automatically also defined for all subsequent TX channels in order to set up a system with equal TX channel spacing quickly. For different spacings, a setup from top to bottom is necessary.

TX1-2	spacing between the first and the second carrier
TX2-3	spacing between the second and the third carrier

If you change the adjacent-channel spacing (ADJ), all higher adjacent channel spacings (ALT1, ALT2, ...) are multiplied by the same factor (new spacing value/old spacing value). Again, only one value needs to be entered for equal channel spacing. For different spacing, configure the spacings from top to bottom.

For details see chapter 4.2.5.2, "How to Set up the Channels", on page 54 SCPI command:

```
[SENSe:]POWer:ACHannel:SPACing:CHANnel<ch> on page 472
[SENSe:]POWer:ACHannel:SPACing[:ACHannel] on page 471
[SENSe:]POWer:ACHannel:SPACing:ALTernate<ch> on page 471
```

Limit Checking

During an ACLR measurement, the power values can be checked whether they exceed user-defined or standard-defined limits. A relative or absolute limit can be defined, or both. Both limit types are considered, regardless whether the measured levels are absolute or relative values. The check of both limit values can be activated independently. If any active limit value is exceeded, the measured value is displayed in red and marked by a preceding asterisk in the result table.



SCPI command:

```
CALCulate<n>:LIMit<k>:ACPower[:STATe] on page 478

CALCulate<n>:LIMit<k>:ACPower:ACHannel:RESult? on page 476

CALCulate<n>:LIMit<k>:ACPower:ALTernate<ch>[:RELative] on page 477
```

Weighting Filters

Weighting filters allow you to determine the influence of individual channels on the total measurement result. For each channel you can activate or deactivate the use of the weighting filter and define an individual weighting factor ("Alpha" value).

Channel Power and Adjacent-Channel Power (ACLR) Measurement

Weighting filters are not available for all supported standards and cannot always be defined manually where they are available.

SCPI command:

Activating/Deactivating:

```
[SENSe:]POWer:ACHannel:FILTer[:STATe]:CHANnel<ch> on page 474
[SENSe:]POWer:ACHannel:FILTer[:STATe]:ACHannel on page 473
[SENSe:]POWer:ACHannel:FILTer[:STATe]:ALTernate<ch> on page 474
Alpha value:
[SENSe:]POWer:ACHannel:FILTer:ALPHa:CHANnel<ch> on page 473
[SENSe:]POWer:ACHannel:FILTer:ALPHa:ACHannel on page 472
```

[SENSe:]POWer:ACHannel:FILTer:ALPHa:ALTernate<ch> on page 473

Channel Names

In the R&S FSW's display, carrier channels are labelled "TX" by default; the first neighboring channel is labelled "Adj" (adjacent) channel; all others are labelled "Alt" (alternate) channels. You can define user-specific channel names for each channel which are displayed in the result diagram and result table.

SCPI command:

```
[SENSe:]POWer:ACHannel:NAME:ACHannel on page 470
[SENSe:]POWer:ACHannel:NAME:ALTernate<ch> on page 471
[SENSe:]POWer:ACHannel:NAME:CHANnel<ch> on page 471
```

4.2.5 How to Perform Channel Power Measurements

The following step-by-step instructions demonstrate the most common tasks when performing channel power measurements.

•	How to Perform a Standard Channel Power Measurement	53
	How to Set up the Channels	
	How to Manage User-Defined Configurations	
	How to Compare the TX Channel Power in Successive Measurements	56

4.2.5.1 How to Perform a Standard Channel Power Measurement

Performing a channel power or ACLR measurement according to common standards is a very easy and straightforward task with the R&S FSW.

- Press the MEAS key or tap "Select Measurement" in the "Overview".
- 2. Select "Channel Power ACLR".

The measurement is started immediately with the default settings.

Select the "CP / ACLR Standard" softkey and select a standard from the list.
 The measurement is restarted with the predefined settings for the selected standard.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

4. If necessary, edit the settings for your specific measurement as described in chapter 4.2.5.2, "How to Set up the Channels", on page 54, or load a user-defined configuration (see "To load a user-defined configuration" on page 55).

4.2.5.2 How to Set up the Channels

Channel definition is the basis for measuring power levels in certain frequency ranges. Usually, the power levels in one or more carrier (TX) channels and possibly the adjacent channels are of interest. Up to 18 carrier channels and up to 12 adjacent channels can be defined.

When a measurement standard is selected in the "Ch Power" menu or the "ACLR Setup" dialog box, all settings including the channel bandwidths and channel spacings are set according to the selected standard and can be adjusted afterwards.

Channel setup consists of the following settings:

- The number of transmission (TX) and adjacent channels
- The bandwidth of each channel
- For multi-carrier ACLR measurements: which TX channel is used as a reference
- The spacing between the individual channels
- Optionally: the names of the channels displayed in the diagram and result table
- Optionally: the influence of individual channels on the total measurement result ("Weighting Filter")
- Optionally: limits for a limit check on the measured power levels



Changes to an existing standard can be stored as a user-defined standard, see chapter 4.2.5.3, "How to Manage User-Defined Configurations", on page 55.

► In the "Ch Power" menu, select the "CP / ACLR Config" softkey, then select the "Channel Settings" tab to configure the channels in the "ACLR Setup" dialog box.



In the "Channel Setup" dialog box you can define the channel settings for all channels, independent of the defined number of *used* TX or adjacent channels.

To define channel spacings

Channel spacings are normally defined by the selected standard but can be changed.

► In the "Channel Settings" tab of the "ACLR Setup" dialog box, select the "Spacing" subtab.

The value entered for any TX channel is automatically also defined for all subsequent TX channels. Thus, only one value needs to be entered if all TX channels have the same spacing.

If the channel spacing for the adjacent or an alternate channel is changed, all higher alternate channel spacings are multiplied by the same factor (new spacing value/old

Channel Power and Adjacent-Channel Power (ACLR) Measurement

spacing value). The lower adjacent-channel spacings remain unchanged. Only one value needs to be entered for equal channel spacing.

Example: Defining channel spacing

In the default setting, the adjacent channels have the following spacing: 20 kHz ("ADJ"), 40 kHz ("ALT1"), 60 kHz ("ALT2"), 80 kHz ("ALT3"), 100 kHz ("ALT4"), ...

If the spacing of the first adjacent channel ("ADJ") is set to 40 kHz, the spacing of all other adjacent channels is multiplied by factor 2 to result in 80 kHz ("ALT1"), 120 kHz ("ALT2"), 160 kHz ("ALT3"), ...

If, starting from the default setting, the spacing of the 5th adjacent channel ("ALT4") is set to 150 kHz, the spacing of all higher adjacent channels is multiplied by factor 1.5 to result in 180 kHz ("ALT5"), 210 kHz ("ALT6"), 240 kHz ("ALT7"), ...

4.2.5.3 How to Manage User-Defined Configurations

You can define measurement configurations independently of a predefinded standard and save the current ACLR configuration as a "user standard" in an xml file. You can then load the file and thus the settings again at a later time.

User-defined standards are not supported for "Fast ACLR" and Multi-Carrier ACLR measurements.



Compatibility to R&S FSP

User standards created on an analyzer of the R&S FSP family are compatible to the R&S FSW. User standards created on an R&S FSW, however, are not necessarily compatible to the analyzers of the R&S FSP family and may not work there.

To store a user-defined configuration

- 1. In the "Ch Power" menu, select the "CP / ACLR Config" softkey to display the "ACLR Setup" dialog box.
- 2. Configure the measurement as required (see also chapter 4.2.5.2, "How to Set up the Channels", on page 54).
- 3. In the "General Settings" tab, select the "Manage User Standards" button to display the "Manage" dialog box.
- 4. Define a file name for the user standard and select its storage location. By default, the xml file is stored in C:\R_S\Instr\acp_std\. However, you can define any other storage location.
- 5. Select "Save".

To load a user-defined configuration

- 1. In the "General Settings" tab of the "ACLR Setup" dialog box, select the "Manage User Standards" button to display the "Manage" dialog box.
- 2. Select the user standard file.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

3. Select "Load".

The stored settings are automatically set on the R&S FSW and the measurement is restarted with the new parameters.

4.2.5.4 How to Compare the TX Channel Power in Successive Measurements

For pure channel power measurements, where no adjacent channels and only one TX channel is defined, you can define a fixed reference power and compare subsequent measurement results to the stored reference power.

- 1. Configure a measurement with only one TX channel and no adjacent channels (see also chapter 4.2.5.2, "How to Set up the Channels", on page 54).
- 2. Select the "Set CP Reference" softkey in the "Ch Power" menu, or the "Set CP Reference" button in the "ACLR Setup" dialog box.

The channel power currently measured on the TX channel is stored as a fixed reference power. The reference value is displayed in the "Reference" field of the result table (in relative ACLR mode).

3. Start a new measurement.

The resulting power is indicated relative to the fixed reference power.

- 4. Repeat this for any number of measurements.
- 5. To start a new measurement without the fixed reference, temporarily define a second channel or preset the instrument.

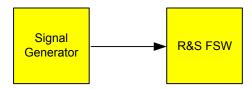
4.2.6 Measurement Examples

The R&S FSW has test routines for simple channel and adjacent channel power measurements. These routines give quick results without any complex or tedious setting procedures.

- Measurement Example 1 ACPR Measurement on an CDMA2000 Signal........56
- Measurement Example 2 Measuring Adjacent Channel Power of a W-CDMA Uplink Signal......58

4.2.6.1 Measurement Example 1 – ACPR Measurement on an CDMA2000 Signal

Test setup:



Channel Power and Adjacent-Channel Power (ACLR) Measurement

Signal generator settings (e.g. R&S SMU):

Frequency:	850 MHz
Level:	0 dBm
Modulation:	CDMA2000

Procedure:

- 1. Preset the R&S FSW.
- 2. Set the center frequency to 850 MHz.
- 3. Set the span to 4 MHz.
- 4. Set the reference level to +10 dBm.
- Select the "Channel Power ACLR" measurement function from the "Select Measurement" dialog box.
- 6. Set the "CDMA2000 1X" standard for adjacent channel power measurement in the "ACLR Setup" dialog box.

The R&S FSW sets the channel configuration according to the 2000 standard with 2 adjacent channels above and 2 below the transmit channel. The spectrum is displayed in the upper part of the screen, the numeric values of the results and the channel configuration in the lower part of the screen. The various channels are represented by vertical lines on the graph.

The frequency span, resolution bandwidth, video bandwidth and detector are selected automatically to give correct results. To obtain stable results – especially in the adjacent channels (30 kHz bandwidth) which are narrow in comparison with the transmission channel bandwidth (1.23 MHz) – the RMS detector is used.

- 7. Set the optimal reference level and RF attenuation for the applied signal level using the "Auto Level" function in the AUTO SET menu.
- 8. Activate "Fast ACLR" mode in the "ACLR Setup" dialog box to increase the repeatability of results.

The R&S FSW sets the optimal RF attenuation and the reference level based on the transmission channel power to obtain the maximum dynamic range. The figure 4-5 shows the result of the measurement.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

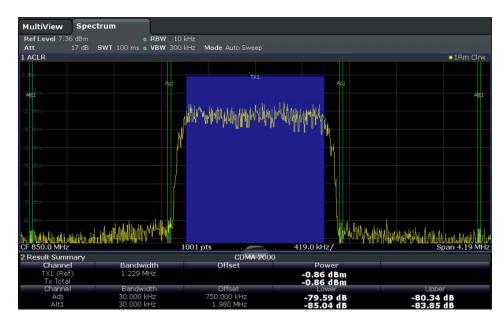
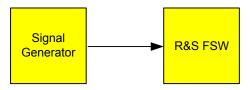


Fig. 4-5: Adjacent channel power measurement on a CDMA2000 1x signal

4.2.6.2 Measurement Example 2 – Measuring Adjacent Channel Power of a W-CDMA Uplink Signal

Test setup:



Signal generator settings (e.g. R&S FSW SMU):

Frequency:	1950 MHz
Level:	4 dBm
Modulation:	3 GPP W-CDMA Reverse Link

Procedure:

- 1. Preset the R&S FSW.
- 2. Set the center frequency to 1950 MHz.
- 3. Select the "Channel Power ACLR" measurement function from the "Select Measurement" dialog box.
- 4. Set the "W-CDMA 3GPP REV" standard for adjacent channel power measurement in the "ACLR Setup" dialog box.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

The R&S FSW sets the channel configuration to the 3GPP W-CDMA standard for mobiles with two adjacent channels above and below the transmit channel. The frequency span, the resolution and video bandwidth and the detector are automatically set to the correct values. The spectrum is displayed in the upper window and the channel power, the level ratios of the adjacent channel powers and the channel configuration in the lower window. The individual channels are displayed as bars in the graph.

5. Set the optimal reference level and RF attenuation for the applied signal level using the "Auto Level" function.

The R&S FSW sets the optimum RF attenuation and the reference level for the power in the transmission channel to obtain the maximum dynamic range. The following figure shows the result of the measurement.



Fig. 4-6: Measuring the relative adjacent channel power on a W-CDMA uplink signal

The R&S FSW measures the power of the individual channels with zero span. A root raised cosine filter with the parameters α = 0.22 and chip rate 3.84 Mcps (= receive filter for 3GPP W-CDMA) is used as channel filter.

Optimum Level Setting for ACLR Measurements on W-CDMA Signals

The dynamic range for ACLR measurements is limited by the thermal noise floor, the phase noise and the intermodulation (spectral regrowth) of the signal analyzer. The power values produced by the R&S FSW due to these factors accumulate linearly. They depend on the applied level at the input mixer. The three factors are shown in the figure below for the adjacent channel (5 MHz carrier offset).

Channel Power and Adjacent-Channel Power (ACLR) Measurement

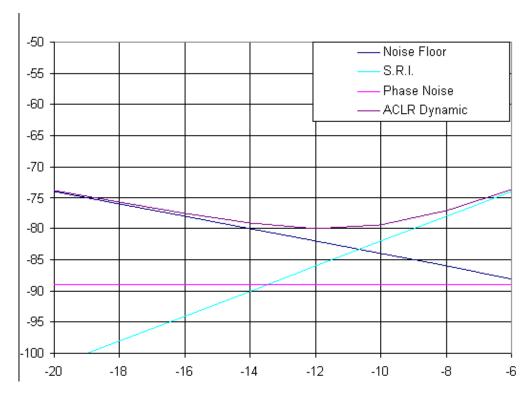


Fig. 4-7: Dynamic range for ACLR measurements on W-CDMA uplink signals as a function of the mixer

The level of the W-CDMA signal at the input mixer is shown on the horizontal axis, i.e. the measured signal level minus the selected RF attenuation. The individual components which contribute to the power in the adjacent channel and the resulting relative level (total ACPR) in the adjacent channel are displayed on the vertical axis. The optimum mixer level is -12 dBm. The relative adjacent channel power (ACPR) at an optimum mixer level is -77 dBc. Since, at a given signal level, the mixer level is set in 1 dB steps with the 1 dB RF attenuator, the optimum range spreads from -10 dBm to -14 dBm.

To set the attenuation parameter manually, the following method is recommended:

➤ Set the RF attenuation so that the mixer level (= measured channel power – RF attenuation) is between -10 dBm and -14 dBm.

This method is automated with the "Auto Level" function. Especially in remote control mode, e.g. in production environments, it is best to correctly set the attenuation parameters prior to the measurement, as the time required for automatic setting can be saved.



To measure the R&S FSW's intrinsic dynamic range for W-CDMA adjacent channel power measurements, a filter which suppresses the adjacent channel power is required at the output of the transmitter. A SAW filter with a bandwidth of 4 MHz, for example, can be used.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

4.2.6.3 Measurement Example 3 – Measuring the Intrinsic Noise of the R&S FSW with the Channel Power Function

Noise in any bandwidth can be measured with the channel power measurement functions. Thus the noise power in a communication channel can be determined, for example. If the noise spectrum within the channel bandwidth is flat, the noise marker can be used to determine the noise power in the channel by considering the channel bandwidth. If, however, phase noise and noise that normally increases towards the carrier is dominant in the channel to be measured, or if there are discrete spurious signals in the channel, the channel power measurement method must be used to obtain correct measurement results.

Test setup:

Leave the RF input of the R&S FSW open-circuited or terminate it with 50 Ω.

Procedure:

- 1. Preset the R&S FSW.
- 2. Set the center frequency to 1 GHz and the span to 1 MHz.
- 3. To obtain maximum sensitivity, set RF attenuation to 0 dB and the reference level to -40 dBm.
- Select the "Channel Power ACLR" measurement function from the "Select Measurement" dialog box.
- 5. In the "ACLR Setup" dialog box, set up a single TX channel with the channel bandwidth 1.23 MHz.
- Select the "Adjust Settings" softkey.
 The settings for the frequency span, the bandwidth (RBW and VBW) and the detector are automatically set to the optimum values required for the measurement.
- 7. Stabilize the measurement result by increasing the sweep time. Set the sweep time to 1 s.

The trace becomes much smoother because of the RMS detector and the channel power measurement display is much more stable.

Channel Power and Adjacent-Channel Power (ACLR) Measurement

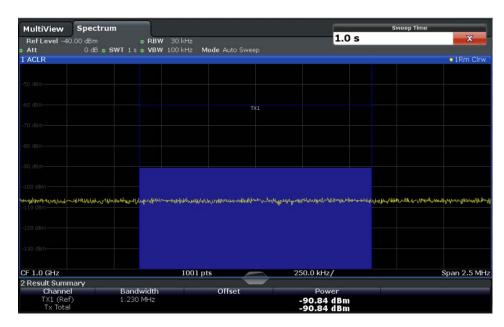


Fig. 4-8: Measurement of the R&S FSW's intrinsic noise power in a 1.23 MHz channel bandwidth.

4.2.7 Reference: Predefined CP/ACLR Standards

When using predefined standards for ACLR measurement, the test parameters for the channel and adjacent-channel measurements are configured automatically.

You can select a predefined standard via the "CP / ACLR Standard" softkey in the "Ch Power" menu or the selection list in the "General Settings" tab of the "ACLR Setup" dialog box (see "Standard" on page 45).

Table 4-2: Predefined CP / ACLR standards with remote command parameters

Standard	Remote parameter
None	NONE
EUTRA/LTE Square	EUTRa
EUTRA/LTE Square/RRC	REUTra
W-CDMA 3GPP FWD	FW3Gppcdma
W-CDMA 3GPP REV	RW3Gppcdma
CDMA IS95A FWD	F8CDma
CDMA IS95A REV	R8CDma
CDMA IS95C Class 0 FWD	FIS95c0
CDMA IS95C Class 0 REV	RIS95c0
CDMA J-STD008 FWD	F19Cdma
CDMA J-STD008 REV	R19Cdma
CDMA IS95C Class 1 FWD	FIS95c1

Carrier-to-Noise Measurements

Standard	Remote parameter
CDMA IS95C Class 1 REV	RIS95c1
CDMA2000	S2CDma
TD-SCDMA FWD	FTCDma
TD-SCDMA REV	TRCDma
WLAN 802.11A	AWLAN
WLAN 802.11B	BWLAN
WIMAX	WIMax
WIBRO	WIBRo
GSM	GSM
RFID 14443	RFID14443
TETRA	TETRa
PDC	PDC
PHS	PHS
CDPD	CDPD
APCO-25 P2	PAPCo25
User Standard	USER
Customized Standard	<string></string>



For the R&S FSW, the channel spacing is defined as the distance between the center frequency of the adjacent channel and the center frequency of the transmission channel. The definition of the adjacent-channel spacing in standards IS95C and CDMA 2000 is different. These standards define the adjacent-channel spacing from the center of the transmission channel to the closest border of the adjacent channel. This definition is also used by the R&S FSW for the standards marked with an asterisk *).

4.3 Carrier-to-Noise Measurements

The R&S FSW can easily determine the carrier-to-noise ratio, also normalized to a 1 Hz bandwidth.

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Carrier-to-Noise Measurements

4.3.1 About the Measurement

The largest signal in the frequency span is the carrier. It is searched when the C/N or C/NO function is activated and is marked using a fixed reference marker ("FXD").

To determine the noise power, a channel with a defined bandwidth at the defined center frequency is analyzed. The power within this channel is integrated to obtain the noise power level. (If the carrier is within this channel, an extra step is required to determine the correct noise power level, see below.)

The noise power of the channel is subtracted from the maximum carrier signal level, and in the case of a C/N_O measurement, it is referred to a 1 Hz bandwidth.



For this measurement, the RMS detector is activated.

The carrier-to-noise measurements are only available in the frequency domain (span >0).

Measurement process

Depending on whether the carrier is inside or outside the analyzed channel, the measurement process for the carrier-to-noise ratio varies:

- The carrier is outside the analyzed channel: In this case, it is sufficient to switch on the desired measurement function and to set the channel bandwidth. The carrier/noise ratio is displayed on the screen.
- The carrier is inside the analyzed channel: In this case, the measurement must be performed in two steps:
 - First, perform the reference measurement by switching on either the C/N or the C/NO measurement and waiting for the end of the next measurement run. The fixed reference marker is set to the maximum of the measured carrier signal.
 - Then, switch off the carrier so that only the noise of the test setup is active in the channel. The carrier-to-noise ratio is displayed after the subsequent measurement has been completed.

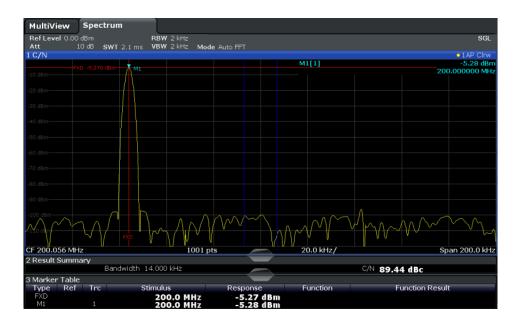
Frequency Span

The frequency span should be set to approximately 4 times the channel bandwidth in order to measure the carrier-to-noise ratio correctly. This setting is defined automatically by the "Adjust Settings" function.

4.3.2 Carrier-to-Noise Results

As a result of the carrier-to-noise measurement the evaluated bandwidth and the calculated C/N ratio are displayed in the result window. The fixed reference marker is indicated in the diagram.

Carrier-to-Noise Measurements



SCPI command:

You can also query the determined carrier-to-noise ratio via the remote command CALC:MARK:FUNC:POW:RES? CN or CALC:MARK:FUNC:POW:RES? CN0, see CALCulate<n>:MARKer<m>:FUNCtion:POWer:RESult? on page 464.

4.3.3 Carrier-to-Noise Configuration

The Carrier-to-noise ratio (C/N) and the Carrier-to-noise ratio in relation to the bandwidth (C/N_0) measurements are selected via the corresponding button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "Carrier Noise" configuration dialog box, which is displayed as a tab in the "Analysis" dialog box or when you select the "Carrier Noise Config" softkey from the "Carrier Noise" menu.



Carrier-to-noise measurements are not available in zero span mode.



The easiest way to configure a measurement is using the configuration "Overview", see chapter 5.1, "Configuration Overview", on page 159.

Carrier-to-Noise Measurements

The remote commands required to perform these tasks are described in chapter 10.3.4, "Measuring the Carrier-to-Noise Ratio", on page 483.

C/No	66
Channel Bandwidth	
Adjust Settings	

C/N

Switches the measurement of the carrier/noise ratio on or off. If no marker is active, marker 1 is activated.

The measurement is performed on the trace that marker 1 is assigned to. To shift marker 1 and measure another trace, use the "Marker to Trace" softkey in the "Marker" menu (see "Assigning the Marker to a Trace" on page 278).

SCPI command:

```
CALCulate<n>:MARKer<m>:FUNCtion:POWer:SELect on page 465
CALCulate<n>:MARKer<m>:FUNCtion:POWer:RESult? on page 464
CALCulate<n>:MARKer<m>:FUNCtion:POWer[:STATe] on page 466
```

C/No

Switches the measurement of the carrier/noise ratio with reference to a 1 Hz bandwidth on or off. If no marker is active, marker 1 is activated.

The measurement is performed on the trace that marker 1 is assigned to. To shift marker 1 and measure another trace, use the "Marker to Trace" softkey in the "Marker" menu (see "Assigning the Marker to a Trace" on page 278).

SCPI command:

```
CALCulate<n>:MARKer<m>:FUNCtion:POWer:SELect on page 465
CALCulate<n>:MARKer<m>:FUNCtion:POWer:RESult? on page 464
CALCulate<n>:MARKer<m>:FUNCtion:POWer[:STATe] on page 466
```

Channel Bandwidth

Defines the measurement channel bandwidth.

The default setting is 14 kHz.

SCPI command:

```
[SENSe:]POWer:ACHannel:BANDwidth|BWIDth[:CHANnel<ch>] on page 470
```

Adjust Settings

Enables the RMS detector and adjusts the span to the selected channel bandwidth according to:

"4 x channel bandwidth + measurement margin"

The adjustment is performed once; if necessary, the setting can be changed later on.

```
SCPI command:
```

```
[SENSe:] POWer: ACHannel: PRESet on page 466
```

Occupied Bandwidth Measurement (OBW)

4.3.4 How to Determine the Carrier-to-Noise Ratio

- 1. Press the "C/N, C/NO" softkey to configure the carrier-to-noise ratio measurement.
- 2. To change the channel bandwidth to be analyzed, press the "Channel Bandwidth" softkey.
- 3. To optimize the settings for the selected channel configuration, press the "Adjust Settings" softkey.
- To activate the measurements without reference to the bandwidth, press the "C/N" softkev.
 - To activate the measurements with reference to the bandwidth, press the "C/NO" softkey .
- If the carrier signal is located within the analyzed channel bandwidth, switch off the carrier signal so that only the noise is displayed in the channel and perform a second measurement.

The carrier-to-noise ratio is displayed after the measurement has been completed.

4.4 Occupied Bandwidth Measurement (OBW)

An important characteristic of a modulated signal is its occupied bandwidth. In a radio communications system, for instance, the occupied bandwidth must be limited to enable distortion-free transmission in adjacent channels.

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4.4.1 About the Measurement

The occupied bandwidth is defined as the bandwidth containing a defined percentage of the total transmitted power. A percentage between 10 % and 99.9 % can be set.

Measurement principle

The bandwidth containing 99% of the signal power is to be determined, for example. The algorithm first calculates the total power of all displayed points of the trace. In the next step, the points from the right edge of the trace are summed up until 0.5 % of the total power is reached. Auxiliary marker 1 is positioned at the corresponding frequency. Then the points from the left edge of the trace are summed up until 0.5 % of the power is reached. Auxiliary marker 2 is positioned at this point. 99 % of the power is now between the two markers. The distance between the two frequency markers is the occupied bandwidth which is displayed in the marker field.

Occupied Bandwidth Measurement (OBW)



New: OBW now also possible within defined search limits - multi-carrier OBW measurement in one sweep

As of R&S FSW firmware version 1.30, the occupied bandwidth of the signal can be determined within defined search limits instead of for the entire signal. Thus, only a single sweep is required to determine the OBW for a multi-carrier signal. To do so, search limits are defined for an individual carrier and the OBW measurement is restricted to the frequency range contained within those limits. Then the search limits are adapted for the next carrier and the OBW is automatically re-calculated for the new range.



For step-by-step instructions see "How to determine the OBW for a multi-carrier signal using search limits" on page 72.

Prerequisites

To ensure correct power measurement, especially for noise signals, and to obtain the correct occupied bandwidth, the following prerequisites and settings are necessary:

- Only the signal to be measured is displayed in the window, or search limits are defined to include only one (carrier) signal. An additional signal would falsify the measurement.
- RBW << occupied bandwidth (approx. 1/20 of occupied bandwidth, for voice communication type: 300 Hz or 1 kHz)
- VBW ≥ 3 x RBW
- RMS detector
- Span ≥ 2 to 3 x occupied bandwidth

Some of the measurement specifications (e.g. PDC, RCR STD-27B) require measurement of the occupied bandwidth using a peak detector. The detector setting of the R&S FSW has to be changed accordingly then.

Occupied Bandwidth Measurement (OBW)

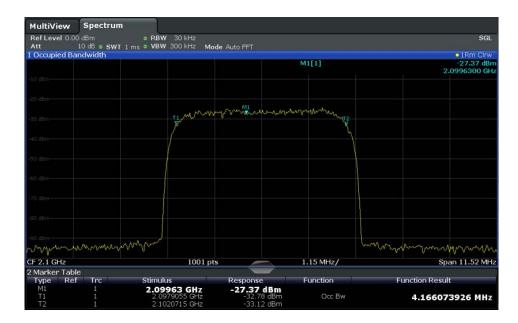
4.4.2 OBW Results

As a result of the OBW measurement the occupied bandwidth ("Occ BW") is indicated in the marker results. Furthermore, the marker at the center frequency and the temporary markers are indicated.

The measurement is performed on the trace with marker 1. In order to evaluate another trace, marker 1 must be placed on another trace (see Assigning the Marker to a Trace).



The OBW calculation is repeated if the Search Limits are changed, without performing a new sweep. Thus, the OBW for a multi-carrier signal can be determined using only one sweep.



SCPI command:

The determined occupied bandwidth can also be queried using the remote command CALC: MARK: FUNC: POW: RES? OBW or CALC: MARK: FUNC: POW: RES? AOBW. While the OBW parameter returns only the occupied bandwidth, the AOBW parameter also returns the position and level of the temporary markers T1 and T2 used to calculate the occupied bandwidth.

```
CALCulate<n>:MARKer<m>:FUNCtion:POWer:SELect on page 465

CALCulate<n>:MARKer<m>:FUNCtion:POWer:RESult? on page 464

CALCulate<n>:MARKer<m>:FUNCtion:POWer[:STATe] on page 466
```

4.4.3 OBW Configuration

OBW measurements are selected via the "OBW" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be

Occupied Bandwidth Measurement (OBW)

configured via the MEAS CONFIG key or in the "Occupied Bandwidth" dialog box, which is displayed as a tab in the "Analysis" dialog box or when you select the "OBW Config" softkey from the "OBW" menu.



This measurement is not available in zero span.



Configuring search limits for OBW measurement

The OBW measurement uses the same search limits as defined for marker search (see "Search Limits" on page 282). However, only the left and right limits are considered.

The remote commands required to perform these tasks are described in chapter 10.3.5, "Measuring the Occupied Bandwidth", on page 483.

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% Power Bandwidth

Defines the percentage of total power in the displayed frequency range which defines the occupied bandwidth. Values from 10% to 99.9% are allowed.

SCPI command:

[SENSe:] POWer:BANDwidth|BWIDth on page 484

Channel Bandwidth

Defines the channel bandwidth for the transmission channel in single-carrier measurements. This bandwidth is used to optimize the test parameters (for details see "Adjust Settings" on page 71). The default setting is 14 kHz.

Occupied Bandwidth Measurement (OBW)

For measurements according to a specific transmission standard, define the bandwidth specified by the standard for the transmission channel.

For multi-carrier measurements this setting is irrelevant.

SCPI command:

```
[SENSe:]POWer:ACHannel:BANDwidth|BWIDth[:CHANnel<ch>] on page 470
```

Adjust Settings

Optimizes the instrument settings for the measurement of the occupied bandwidth according to the specified channel bandwidth.

This function is only useful for single carrier measurements.

All instrument settings relevant for power measurement within a specific frequency range are optimized:

- Frequency span: 3 × channel bandwidth
- RBW ≤ 1/40 of channel bandwidth
- VBW ≥ 3 × RBW
- Detector: RMS

The reference level is not affected by "Adjust Settings". For an optimum dynamic range it should be selected such that the signal maximum is close to the reference level (see "Setting the Reference Level Automatically (Auto Level)" on page 189).

The adjustment is carried out only once. If necessary, the instrument settings can be changed later.

SCPI command:

```
[SENSe:] POWer: ACHannel: PRESet on page 466
```

Search Limits (Left / Right)

If activated, limit lines are defined and displayed for the search. Only results within the limited search range are considered.

For details on limit lines for searches see "Peak search limits" on page 269.

SCPI command:

```
CALCulate:MARKer:X:SLIMits[:STATe] on page 634
CALCulate:MARKer:X:SLIMits:LEFT on page 635
CALCulate:MARKer:X:SLIMits:RIGHT on page 635
```

Deactivating All Search Limits

Deactivates the search range limits.

SCPI command:

```
CALCulate:MARKer:X:SLIMits[:STATe] on page 634 CALCulate:THReshold:STATe on page 636
```

4.4.4 How to Determine the Occupied Bandwidth

How to determine the OBW for a single signal

1. Select the "OBW" measurement function from the "Select Measurement" dialog box.

Occupied Bandwidth Measurement (OBW)

- 2. Select the "OBW Config" softkey to display the "Occupied Bandwidth" configuration dialog box.
- 3. Define the percentage of power ("% Power Bandwidth") that defines the bandwidth to be determined.
- 4. If necessary, change the channel bandwidth for the transmission channel.
- 5. To optimize the settings for the selected channel configuration, select "Adjust Settings".
- 6. Start a sweep.

The result is displayed as OBW in the marker results.

How to determine the OBW for a multi-carrier signal using search limits

- 1. Select the "OBW" measurement function from the "Select Measurement" dialog box.
- 2. Select the "OBW Config" softkey to display the "Occupied Bandwidth" configuration dialog box.
- 3. Define the percentage of power ("% Power Bandwidth") that defines the bandwidth to be determined.
- 4. Define search limits so the search area contains only the first carrier signal:
 - a) Enter values for the left or right limits, or both.
 - b) Enable the use of the required limits.
- 5. Start a sweep.

The result for the first carrier is displayed as OBW in the marker results.

- 6. Change the search limits so the search area contains the next carrier signal as described in step step 4.
 - The OBW is re-calculated and the result for the next carrier is displayed. A new sweep is not necessary!
- 7. Continue in this way until all carriers have been measured.

4.4.5 Measurement Example

In the following example, the bandwidth that occupies 99% of the total power of a PDC signal at 800 MHz, level 0 dBm is measured.

- 1. Preset the R&S FSW.
- 2. Set the center frequency to 800 MHz.
- 3. Set the reference level to -10 dBm.
- 4. Select the "OBW" measurement function from the "Select Measurement" dialog box.
- 5. Set the percentage of power to 99%.

Spectrum Emission Mask (SEM) Measurement

- 6. Set the channel bandwidth to 21 kHz as specified by the PDC standard.
- Optimize the settings for the selected channel configuration by selecting "Adjust Settings".
- 8. Adjust the reference level to the measured total power by selecting the "Auto Level" softkey in the AUTO SET menu.
- 9. The PDC standard requires the peak detector for OBW measurement. In the "Traces" configuration dialog, set the trace detector to "Positive Peak".
- 10. Start a sweep.

The result is displayed as OBW in the marker results.

4.5 Spectrum Emission Mask (SEM) Measurement

The R&S FSW supports Spectrum Emission Mask (SEM) measurements.

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SEM Configuration	
How to Perform a Spectrum Emission Mask Measurement	
Reference: SEM File Descriptions	

4.5.1 About the Measurement

The Spectrum Emission Mask (SEM) measurement defines a measurement that monitors compliance with a spectral mask. The mask is defined with reference to the input signal power. The R&S FSW allows for a flexible definition of all parameters in the SEM measurement. The analyzer performs measurements in predefined frequency ranges with settings that can be specified individually for each of these ranges.

SEM measurement configurations can be saved to an xml file which can then be exported to another application or loaded on the R&S FSW again at a later time. Some predefined XML files are provided that contain ranges and parameters according to the selected standard.

In order to improve the performance of the R&S FSW for spectrum emission mask measurements, a "Fast SEM" mode is available.

Monitoring compliance of the spectrum is supported by a special limit check for SEM measurements.

4.5.2 Typical Applications

Spectrum Emission Mask measurements are typically performed to ensure that modulated signals remain within the valid signal level ranges defined by a particular transmis-

Spectrum Emission Mask (SEM) Measurement

sion standard, both in the transmission channel and neighboring channels. Any violations of the mask may interfere with other transmissions.

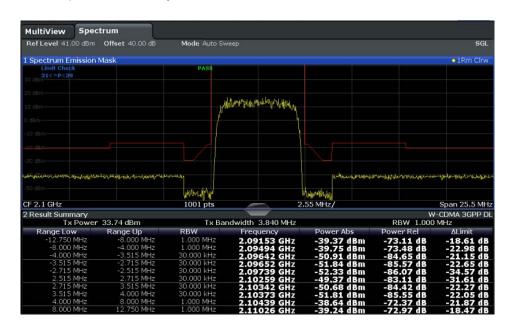
The 3GPP TS 34.122 standard, for example, defines a mask for emissions outside the transmission channel. This mask is defined relative to the input signal power. Three frequency ranges to each side of the transmission channel are defined.

4.5.3 SEM Results

As a result of the Spectrum Emission Mask measurement, the measured signal levels, the result of the limit check (mask monitoring) and the defined limit lines are displayed in a diagram (see also chapter 4.5.4.2, "Limit Lines in SEM Measurements", on page 78). Furthermore, the TX channel power "P" is indicated with the used power class.

Example:

For example, "P<31" is indicated if the lowest power class is defined from infinity to 31 and the power is currently 17 dBm.



In addition to the graphical results of the SEM measurement displayed in the diagram, a result table is displayed to evaluate the limit check results (see also chapter 4.5.4.2, "Limit Lines in SEM Measurements", on page 78).

The following information is provided in the result table:

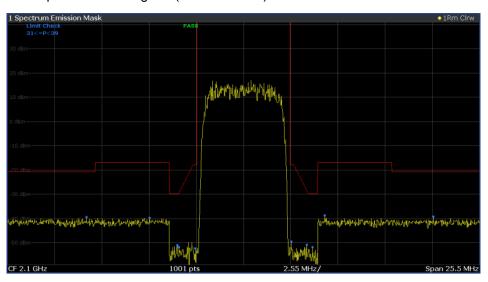
Label	Description
General Information	
Standard	Loaded standard settings
Tx Power	Power of the reference range

Spectrum Emission Mask (SEM) Measurement

Label	Description
Tx Bandwidth	Tx bandwidth used by the reference range
RBW	RBW used by the reference range
Range results	
Range Low	Frequency range start for the range the peak value belongs to
Range Up	Frequency range end for the range the peak value belongs to
RBW	RBW of the range
Frequency	Frequency
Power Abs	Absolute power level
Power Rel	Power level relative to the TX channel power
ΔLimit	Deviation of the power level from the defined limit

In which detail the data is displayed in the result table can be defined in the "List Evaluation" settings (see chapter 4.5.5.6, "List Evaluation", on page 93). By default, one peak per range is displayed. However, you can change the settings to display only peaks that exceed a threshold ("Margin").

In addition to listing the peaks in the list evaluation, detected peaks can be indicated by blue squares in the diagram ("Show Peaks").



Furthermore, you can save the evaluation list to a file which can be exported to another application for further analysis.

Retrieving Results via Remote Control

The measurement results of the spectrum emission mask test can be retrieved using the CALC:LIM:FAIL? command from a remote computer (see CALCulate<n>: LIMit<k>:FAIL on page 676 for a detailed description).

Spectrum Emission Mask (SEM) Measurement

The power result for the reference range can be queried using CALC:MARK:FUNC:POW:RES? CPOW, the peak power for the reference range using CALC:MARK:FUNC:POW:RES? PPOW. see CALCulate<n>:MARKer<m>:FUNCtion:

POWer: RESult? on page 464:

4.5.4 SEM Basics

Some background knowledge on basic terms and principles used in SEM measurements is provided here for a better understanding of the required configuration settings.

•	Ranges and Range Settings	76
	Limit Lines in SEM Measurements	
•	Fast SEM Measurements	80
•	Multi-Standard Radio (MSR) SEM Measurements	81

4.5.4.1 Ranges and Range Settings

In the Spectrum Emission Mask measurements, a range defines a segment for which you can define the following parameters separately:

- Start and stop frequency
- RBW
- VBW
- Sweep time
- Sweep points
- Reference level
- Attenuator settings
- Preamplifier settings
- Transducer settings
- Limit values

Via the sweep list, you define the ranges and their settings. For details on settings refer to chapter 4.5.5.1, "Sweep List", on page 82.

For details on defining the limits (masks) see chapter 4.5.4.2, "Limit Lines in SEM Measurements", on page 78.

For details on defining the limits (masks) see the base unit description "Working with Lines in SEM".

Range definition

After a preset, the sweep list contains a set of default ranges and parameters. For each range, you can change the parameters listed above. You can insert or delete ranges.

The changes of the sweep list are only kept until you load another parameter set (by pressing PRESET or by loading an XML file). If you want a parameter set to be available permanently, create an XML file for this configuration (for details refer to "How to save a user-defined SEM settings file" on page 96).

Spectrum Emission Mask (SEM) Measurement

If you load one of the provided XML files, the sweep list contains ranges and parameters according to the selected standard.

Reference range

The range centered around the center frequency is defined as the reference range for all other ranges in the sweep list. All range limits are defined in relation to the reference range. Power levels in the result table are also calculated in relation to the reference range. You can define whether the power used for reference is the peak power level or the integrated power of the reference range. In the "Sweep List", the reference range is highlighted in blue and cannot be deleted.

Rules

The following rules apply to ranges:

- The minimum span of a range is 20 Hz.
- The individual ranges must not overlap (but may have gaps).
- The maximum number of ranges is 20.
- The minimum number of three ranges is 3.
- The reference range cannot be deleted.
- The reference range has to be centered on the center frequency.
- The minimum span of the reference range is given by the current TX Bandwidth.
- Frequency values for each range have to be defined relative to the center frequency.

In order to change the start frequency of the first range or the stop frequency of the last range, select the appropriate span with the SPAN key. If you set a span that is smaller than the overall span of the ranges, the measurement includes only the ranges that lie within the defined span and have a minimum span of 20 Hz. The first and last ranges are adapted to the given span as long as the minimum span of 20 Hz is not violated.

Symmetrical ranges

You can easily define a sweep list with symmetrical range settings, i.e. the ranges to the left and right of the reference range are defined symmetrically. When symmetrical setup is activated, the current sweep list configuration is changed to define a symmetrical setup regarding the reference range. The number of ranges to the left of the reference range is reflected to the right, i.e. any missing ranges on the right are inserted, while superfluous ranges are removed. The values in the ranges to the right of the reference range are adapted symmetrically to those in the left ranges.

Symmetrical ranges fulfull the conditions required for "Fast SEM" mode (see chapter 4.5.4.3, "Fast SEM Measurements", on page 80).

Power classes

If the signal power level to be monitored may vary and the limits will vary accordingly, you can define power classes, which can then be assigned to the frequency ranges. Thus, the limits for the signal levels can be defined differently for varying input levels. For instance, for higher input levels a transmission standard may allow for higher power levels

Spectrum Emission Mask (SEM) Measurement

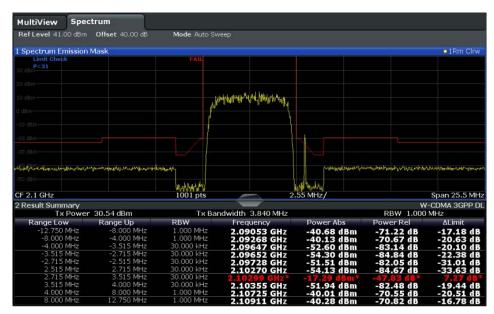
in adjacent channels, whereas for lower input levels the allowed deviation may be stricter. Up to four different power classes can be defined.

4.5.4.2 Limit Lines in SEM Measurements

On the R&S FSW, the spectrum emission mask is defined using limit lines. Limit lines allow you to check the measured data against specified limit values. Generally, it is possible to define limit lines for any measurement in the Spectrum application using the LINES key. For SEM measurements, however, special limit lines are available via the "Sweep List", and it is strongly recommended that you use only these limit line definitions.

In the "Sweep List" you can define a limit line for each power class that varies its level according to the specified frequency ranges. Distinguished limit lines ("_SEM_LINE_ABS<0...3>"/ "_SEM_LINE_REL<0...3>") are automatically defined for each power class according to the current "Sweep List" settings every time the settings change.

The limit line defined for the currently used power class is indicated by a red line in the display, and the result of the limit check is indicated at the top of the diagram. Note that only "Pass" or "Fail" is indicated; a "margin" function as for general limit lines is not available.



The indicated limit line depends on the settings in the "Sweep List". Several types of limit checks are possible:

Table 4-3: Limit check types

Limit check type	Pass/fail criteria	Limit line definition
Absolute	Absolute power levels may not exceed limit line	Defined by the "Abs Limit Start"/ "Abs Limit Stop" values for each range
Relative	Power deviations relative to the TX channel power may not exceed limit line	Defined by the "Rel Limit Start"/ "Rel Limit Stop" values (relative to the TX channel power), fixed for each range.

Spectrum Emission Mask (SEM) Measurement

Limit check type	Pass/fail criteria	Limit line definition
Relative with function f(x)	If the power exceeds both the absolute and the relative limits, the check fails.	Defined by the maximum of the absolute or relative (relative to the TX channel power) "Rel Limit Start"/ "Rel Limit Stop" values for each range. Thus, the start or stop point of the limit range, or both, are variable (since the maximum may vary).
Abs and Rel	If the power exceeds both the absolute and the relative limits, the check fails.	The less strict (higher) limit line is displayed for each range. If you use a function to define the relative limit start or stop value, the signal is checked against an additional condition: the power must exceed the absolute limit, as well as the absolute and relative function values.
Abs or Rel	If the power exceeds either the absolute or the relative limits, the check fails.	The stricter (lower) limit line is displayed for each range. If you use a function to define the relative limit start or stop value, the signal is checked against an additional condition: if the power exceeds the absolute limit, or the higher of the absolute and relative function values, the check fails.

Relative limit line functions

A new function allows you to define limit lines whose start or end points (or both) are variable, depending on the carrier power. Thus, the resulting limit line may change its slope within the range, depending on the carrier power. Common relative limit lines are calculated once for the defined start and end points and maintain a constant slope.

If the relative limit value function is used in combination with the "Abs and Rel" or "Abs or Rel" limit check types, an additional condition is considered for the limit check (see table 4-3).

Limit check results in the evaluation list

The largest deviations of the power from the limit line for each range are displayed in the evaluation list. Furthermore, the absolute powers for those values, as well as the relative deviation from the TX channel power are displayed. Values that exceed the limit are indicated in red and by an asterisk (*).





Although a margin functionality is not available for the limit check, a margin (threshold) for the peak values to be displayed in the evaluation list can be defined in the list evaluation settings. For details see chapter 4.5.5.6, "List Evaluation", on page 93.

Spectrum Emission Mask (SEM) Measurement

4.5.4.3 Fast SEM Measurements

In order to improve the performance of the R&S FSW for spectrum emission mask measurements, a "Fast SEM" mode is available. If this mode is activated, several consecutive ranges with identical sweep settings are combined to one sweep internally, which makes the measurement considerably more efficient. The displayed results remain unchanged and still consist of several ranges. Thus, measurement settings that apply only to the results, such as limits or transducer factors, can nevertheless be defined individually for each range.

Prerequisites

"Fast SEM" mode is available if the following criteria apply:

- The frequency ranges are consecutive, without frequency gaps
- The following sweep settings are identical (for details see chapter 4.5.5.1, "Sweep List", on page 82):
 - Filter Type
 - RBW
 - VBW
 - Sweep Time Mode
 - Reference Level
 - Rf Attenuation Mode
 - RF Attenuation
 - Preamplificiation

Activating Fast SEM mode

"Fast SEM" mode is activated in the sweep list (see chapter 4.5.5.1, "Sweep List", on page 82) or using a remote command. Activating the mode for one range automatically activates it for all ranges in the sweep list.

SCPI command:

[SENSe:]ESPectrum:HighSPeed on page 488

Consequences

When the "Fast SEM" mode is activated, the ranges for which these criteria apply are displayed as one single range. The sweep time is defined as the sum of the individual sweep times, initially, but can be changed.



If "Symmetrical Setup" mode is active when "Fast SEM" mode is activated, not all sweep list settings can be configured symmetrically automatically (see also "Symmetric Setup" on page 86).

Any other changes to the sweep settings of the combined range are applied to each included range and remain changed even after deactivating "Fast SEM" mode.

Spectrum Emission Mask (SEM) Measurement

Example

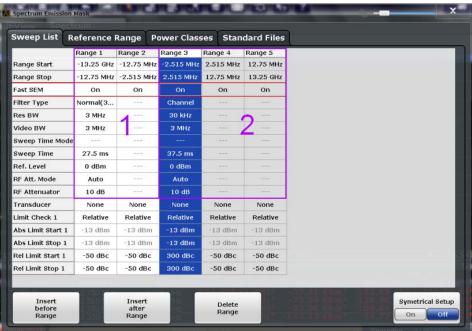


Fig. 4-9: Sweep list using Fast SEM mode

In figure 4-9, a sweep list is shown for which Fast SEM is activated. The formerly 5 separately defined ranges are combined to 2 sweep ranges internally.

4.5.4.4 Multi-Standard Radio (MSR) SEM Measurements

Multi-standard radio (MSR) measurements allow you to perform SEM tests on signals with multiple carriers using different digital standards. MSR measurements are described in the specification 3GPP TS 37.141. Various typical combinations of standards for base station tests are described, e.g. LTE FDD and WCDMA carriers. By performing an MSR SEM measurement you can determine if or how the different carriers affect each other, i.e. if unwanted emissions occur. On the R&S FSW, the MSR SEM measurement is a standard measurement as for single carriers. The MSR settings merely provide a convenient way of configuring the sweep list for all required ranges according to the specification very quickly.

4.5.5 SEM Configuration

SEM measurements are selected via the "Spectrum Emission Mask" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "Spectrum Emission Mask" configuration dialog box, which is displayed when you select the "SEM Setup" button in the "Overview" or one of the softkeys from the "SEMask" menu.

The remote commands required to perform these tasks are described in chapter 10.3.6, "Measuring the Spectrum Emission Mask", on page 485.

Spectrum Emission Mask (SEM) Measurement

The following settings are available in individual tabs of the "Spectrum Emission Mask" configuration dialog box.

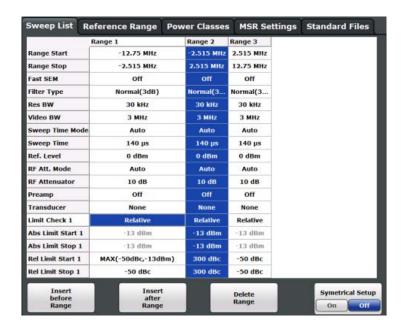
•	Sweep List	82
	Reference Range	
	Power Classes	
•	MSR Settings.	89
	Standard Files	
	List Evaluation	

4.5.5.1 Sweep List

For SEM measurements, the input signal is split into several frequency ranges which are swept individually and for which different limitations apply. In the "Sweep List" tab of the "Spectrum Emission Mask" dialog box you configure the individual frequency ranges and mask limits.



If you edit the sweep list, always follow the rules and consider the limitations described in chapter 4.5.4.1, "Ranges and Range Settings", on page 76.



```
      Range Start / Range Stop
      83

      Fast SEM
      83

      Filter Type
      83

      RBW
      83

      VBW
      84

      Sweep Time Mode
      84

      Sweep Time
      84

      Ref. Level
      84

      RF Att. Mode
      84

      RF Attenuator
      84
```

Spectrum Emission Mask (SEM) Measurement

Preamp	84
Transd. Factor	
Limit Check 1-4	
Abs Limit Start/Stop	
Rel Limit Start/Stop	
Insert before/after Range	
Delete Range	
Symmetric Setup	

Range Start / Range Stop

Sets the start frequency/stop frequency of the selected range.

In order to change the start/stop frequency of the first or last range, respectively, select the appropriate span with the SPAN key. If you set a span that is smaller than the overall span of the ranges, the measurement includes only the ranges that lie within the defined span and have a minimum span of 20 Hz. The first and last ranges are adapted to the given span as long as the minimum span of 20 Hz is not violated.

Frequency values for each range have to be defined relative to the center frequency. The reference range has to be centered on the center frequency. The minimum span of the reference range is given by the current Channel Power Settings.

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>[:FREQuency]:STARt on page 490 [SENSe:]ESPectrum:RANGe<range>[:FREQuency]:STOP on page 490
```

Fast SEM

Activates "Fast SEM" mode for all ranges in the sweep list. For details see chapter 4.5.4.3, "Fast SEM Measurements", on page 80.

Note: If "Fast SEM" mode is deactivated while "Symmetrical Setup" mode is on, "Symmetrical Setup" mode is automatically also deactivated.

If "Fast SEM" mode is activated while "Symmetrical Setup" mode is on, not all range settings can be set automatically.

SCPI command:

```
[SENSe:]ESPectrum:HighSPeed on page 488
```

Filter Type

Sets the filter type for this range.

For details on filter types see chapter 5.5.1.6, "Which Data May Pass: Filter Types", on page 196.

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>:FILTer:TYPE on page 489
```

RBW

Sets the RBW value for this range.

For details on the RBW see chapter 5.5.1.1, "Separating Signals by Selecting an Appropriate Resolution Bandwidth", on page 194.

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>:BANDwidth[:RESolution] on page 488
```

Spectrum Emission Mask (SEM) Measurement

VBW

Sets the VBW value for this range.

For details on the VBW see chapter 5.5.1.2, "Smoothing the Trace Using the Video Bandwidth", on page 195.

SCPI command:

[SENSe:]ESPectrum:RANGe<range>:BANDwidth:VIDeo on page 489

Sweep Time Mode

Activates or deactivates the auto mode for the sweep time.

For details on the sweep time mode see chapter 5.5.1.7, "How Long the Data is Measured: Sweep Time", on page 197

SCPI command:

[SENSe:]ESPectrum:RANGe<range>:SWEep:TIME:AUTO on page 498

Sweep Time

Sets the sweep time value for the range.

For details on the sweep time see chapter 5.5.1.7, "How Long the Data is Measured: Sweep Time", on page 197

SCPI command:

[SENSe:]ESPectrum:RANGe<range>:SWEep:TIME on page 498

Ref. Level

Sets the reference level for the range.

For details on the reference level see chapter 5.4.1.1, "Reference Level", on page 185.

SCPI command:

[SENSe:]ESPectrum:RANGe<range>:RLEVel on page 498

RF Att. Mode

Activates or deactivates the auto mode for RF attenuation.

For details on attenuation see chapter 5.4.1.2, "RF Attenuation", on page 185.

SCPI command:

[SENSe:]ESPectrum:RANGe<range>:INPut:ATTenuation:AUTO on page 491

RF Attenuator

Sets the attenuation value for that range.

For details on attenuation see chapter 5.4.1.2, "RF Attenuation", on page 185.

SCPI command:

[SENSe:]ESPectrum:RANGe<range>:INPut:ATTenuation on page 491

Preamp

Switches the preamplifier on or off.

For details on the preamplifier see "Preamplifier (option B24)" on page 190.

SCPI command:

[SENSe:]ESPectrum:RANGe<range>:INPut:GAIN:STATe on page 492

Spectrum Emission Mask (SEM) Measurement

Transd. Factor

Sets a transducer for the specified range. You can only choose a transducer that fulfills the following conditions:

- The transducer overlaps or equals the span of the range.
- The x-axis is linear.
- The unit is dB.

For details on transducers see chapter 8.2, "Basics on Transducer Factors", on page 342.

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>:TRANsducer on page 499
```

Limit Check 1-4

Sets the type of limit check for all ranges.

For details on limit checks see chapter 4.5.4.2, "Limit Lines in SEM Measurements", on page 78.

The limit state affects the availability of all limit settings.

Depending on the number of active power classes (see chapter 4.5.5.3, "Power Classes", on page 88), the number of limits that can be set varies. Up to four limits are possible. The sweep list is extended accordingly.

SCPI command:

```
[SENSe:]ESPectrum:RANGe:LIMit<PClass>:STATe on page 497
CALCulate<n>:LIMit<k>:FAIL on page 676
```

Abs Limit Start/Stop

Sets an absolute limit value at the start or stop frequency of the range [dBm].

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:ABSolute:STARt
on page 493
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:ABSolute:STOP
on page 493
```

Rel Limit Start/Stop

Sets a relative limit value at the start or stop frequency of the range [dBc].

By default, this value is a fixed relative level, i.e. no function is defined. To define a function for the relative limit, tap the input field for "Rel Limit Start" or "Rel Limit Stop" and select the f(x) icon that appears.

Spectrum Emission Mask (SEM) Measurement



If the function is set to "MAX", you can define a relative *and* an absolute level. In this case, the maximum of the two values is used as the limit level.

For more information see "Relative limit line functions" on page 79.

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:RELative:STARt
on page 494
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:RELative:STOP
on page 495
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:RELative:STARt:
FUNCtion on page 495
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:RELative:STOP:
FUNCtion on page 496
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:RELative:STARt:ABS
on page 494
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:RELative:STARt:ABS
on page 494
[SENSe:]ESPectrum:RANGe<range>:LIMit<PClass>:RELative:STOP:
ABSolute on page 496
```

Insert before/after Range

Inserts a new range to the left of the currently focused range (before) or to the right (after). The range numbers of the currently focused range and all higher ranges are increased accordingly. The maximum number of ranges is 20.

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>:INSert on page 492
```

Delete Range

Deletes the currently focused range, if possible (The reference range cannot be deleted. A minimum of 3 ranges is required.) The range numbers are updated accordingly.

SCPI command:

```
[SENSe:]ESPectrum:RANGe<range>:DELete on page 489
```

Symmetric Setup

Any changes to the range settings in active "Symmetric Setup" mode lead to symmetrical changes in the other ranges (where possible). In particular, this means:

 Inserting ranges: a symmetrical range is inserted on the other side of the reference range

Spectrum Emission Mask (SEM) Measurement

- Deleting ranges: the symmetrical range on the other side of the reference range is also deleted
- Editing range settings: the settings in the symmetrical range are adapted accordingly

Note: If "Fast SEM" mode is deactivated while "Symmetric Setup" mode is on, "Sym Setup" mode is automatically also deactivated.

If "Fast SEM" mode is activated while "Symmetric Setup" mode is on, not all range settings can be set automatically.

4.5.5.2 Reference Range

The range centered around the center frequency is defined as the reference range for all other ranges in the sweep list.

In the "Reference Range" tab of the "Spectrum Emission Mask" dialog box you define the general settings for the reference range.



Power Reference Type	87
Channel Power Settings	
L Tx Bandwidth	
L RRC Filter State	
L Alpha	

Power Reference Type

Defines how the reference power is calculated.

"Channel Measures the channel power within the reference range using the inte-Power" gral bandwidth method (see also "IBW method" on page 37). Additional

settings can be configured for this method.

"Peak Power" Determines the peak power within the reference range.

SCPI command:

[SENSe:]ESPectrum:RTYPe on page 500

Spectrum Emission Mask (SEM) Measurement

Channel Power Settings

If the Power Reference Type "Channel Power" was selected, additional parameters can be configured.

Tx Bandwidth ← Channel Power Settings

Defines the bandwidth used for measuring the channel power, with:

minimum span ≤ Tx Bandwidth ≤ span of reference range

SCPI command:

[SENSe:]ESPectrum:BWID on page 499

RRC Filter State ← Channel Power Settings

Activates or deactivates the use of an RRC filter.

SCPI command:

[SENSe:]ESPectrum:FILTer[:RRC][:STATe] on page 500

Alpha ← Channel Power Settings

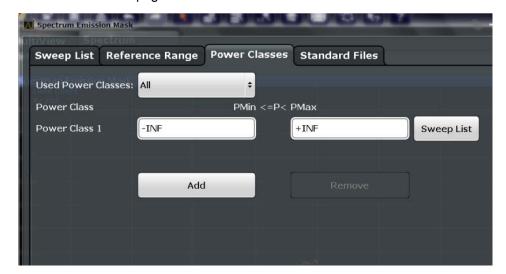
Sets the alpha value of the RRC filter (if activated).

SCPI command:

[SENSe:]ESPectrum:FILTer[:RRC]:ALPHa on page 499

4.5.5.3 Power Classes

In the "Power Classes" tab of the "Spectrum Emission Mask" dialog box you configure power classes which can then be assigned to the sweep list ranges. For details see "Power classes" on page 77.



Used Power Classes	89
PMin/PMax	89
Sweep List	
Adding or Removing a Power Class	

Spectrum Emission Mask (SEM) Measurement

Used Power Classes

Defines which power classes are considered for the SEM measurement. Limits can be defined only for used power classes. It is only possible to select either one specific power class or all of the defined power classes.

If "All" is selected, the power class that corresponds to the currently measured power in the reference range is used for monitoring. The limits assigned to that power class are applied (see "Limit Check 1-4" on page 85).

SCPI command:

```
CALCulate:LIMit:ESPectrum:PCLass<class>[:EXCLusive] on page 503 To define all limits in one step:
```

```
CALCulate:LIMit:ESPectrum:PCLass<class>:LIMit[:STATe] on page 503
```

PMin/PMax

Defines the level limits for each power class. The range always starts at -200 dBm (-INF) and always stops at 200 dBm (+INF). These fields cannot be modified. If more than one power class is defined, the value of "PMin" must be equal to the value of "PMax" of the previous power class and vice versa.

Note that the power level may be equal to the lower limit, but must be lower than the upper limit:

```
P<sub>min</sub>≦P<P<sub>max</sub>
```

SCPI command:

```
CALCulate:LIMit:ESPectrum:PCLass<class>:MINimum on page 504
CALCulate:LIMit:ESPectrum:PCLass<class>:MAXimum on page 504
```

Sweep List

Switches to the "Sweep List" tab of the "Spectrum Emission Mask" dialog box and focuses the "Limit Check" setting for the corresponding power class (1-4) in the reference range (see "Limit Check 1-4" on page 85).

Adding or Removing a Power Class

Adds a new power class at the end of the list or removes the last power class. After adding or removing, the last power class is adapted to end at "+INF".

SCPI command:

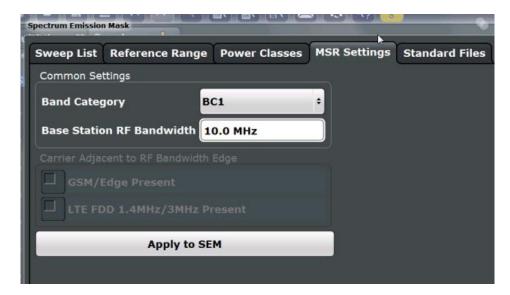
```
CALCulate:LIMit:ESPectrum:PCLass<class>[:EXCLusive] on page 503
```

4.5.5.4 MSR Settings

In the "MSR Settings" tab of the "Spectrum Emission Mask" dialog box you configure multi-standard radio (MSR) measurements, which allow you to perform SEM tests on multiple carriers using different digital standards.

For details see chapter 4.5.4.4, "Multi-Standard Radio (MSR) SEM Measurements", on page 81.

Spectrum Emission Mask (SEM) Measurement



Band Category	90
Base Station RF Bandwidth	
Carrier Adjacent to RF Bandwidth Edge	90
Apply to SEM	

Band Category

Defines the band category for MSR measurements, i.e. the combination of available carriers to measure.

"BC1" LTE FDD and WCDMA

"BC2" LTE FDD, WCDMA and GSM/EDGE

"BC3" LTE TDD and TD-SCDMA

SCPI command:

[SENSe:]ESPectrum:MSR:BCATegory on page 505

Base Station RF Bandwidth

Defines the relevant RF bandwidth (span) required to measure all available carriers in MSR SEM measurements.

SCPI command:

[SENSe:]ESPectrum:MSR:RFBWidth on page 506

Carrier Adjacent to RF Bandwidth Edge

For particular measurement setups the specification demands specific limits for the SEM ranges.

These settings are only available for Band Category 2.

"GSM/ Edge A GSM/EDGE carrier is located at the edge of the RF bandwidth. present"

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"LTE FDD 1.4 An LTE FDD 1.4 MHz or 3 MHz carrier is located at the edge of the RF MHz / 3 MHz bandwidth. present"

SCPI command:

[SENSe:]ESPectrum:MSR:GSM:CPResent on page 505 [SENSe:]ESPectrum:MSR:LTE:CPResent on page 506

Apply to SEM

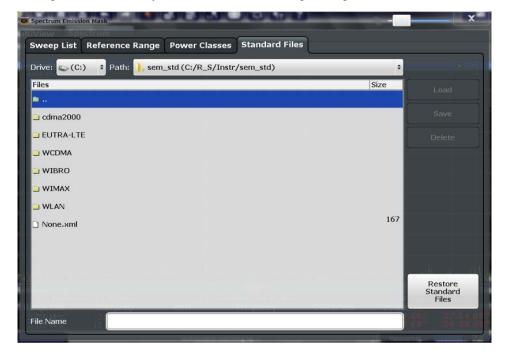
Configures the SEM sweep list according to the specified MSR settings.

SCPI command:

[SENSe:]ESPectrum:MSR:APPLy on page 505

4.5.5.5 Standard Files

In the "Standard Files" tab of the "Spectrum Emission Mask" dialog box you can save the current measurement settings as a user-defined standard, or load stored measurement settings. Furthermore, you can delete an existing settings file.



For details see chapter 4.5.6.1, "How to Manage SEM Settings Files", on page 96.

Selecting the Storage Location - Drive/ Path/ Files

Select the storage location of the settings file on the instrument or an external drive.

The "Drive" indicates the internal (C:) or any connected external drives (e.g. a USB storage device).

The "Path" contains the drive and the complete file path to the currently selected folder.

The "Files" list contains all subfolders and files of the currently selected path.

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The default storage location for the SEM settings files is: $C:\R_s\in\L$

SCPI command:

MMEMory: CATalog? on page 678

File Name

Contain the name of the data file without the path or extension.

By default, the name of a settings file consists of a base name followed by an underscore. Multiple files with the same base name are extended by three numbers, e.g. limit lines 005.

For details on the file name and location see chapter 7.2.2.2, "Storage Location and File Name", on page 323.

Load Standard

Loads the selected measurement settings file.

Save Standard

Saves the current measurement settings for a specific standard as a file with the defined name.

Delete Standard

Deletes the selected standard. Standards predefined by Rohde & Schwarz can also be deleted. A confirmation query is displayed to avoid unintentional deletion of the standard.

Note: Restoring predefined standard files. The standards predefined by Rohde & Schwarz available at the time of delivery can be restored using the "Restore Standards" softkey.

(See "Restore Standard Files" on page 92).

Restore Standard Files

Restores the standards predefined by Rohde & Schwarz available at the time of delivery.

The XML files from the C: $\R_S\$ backup folder are copied to the C: $\R_S\$ sem_std folder.

Note that this function will overwrite customized standards that have the same name as predefined standards.

SCPI command:

[SENSe:] ESPectrum: PRESet: RESTore on page 486

Restore Standard Files

Restores the standards predefined by Rohde & Schwarz available at the time of delivery.

The XML files from the C:\R_S\instr\sem_backup folder are copied to the C: $R_S \in \mathbb{C}$.

Note that this function will overwrite customized standards that have the same name as predefined standards.

SCPI command:

[SENSe:]ESPectrum:PRESet:RESTore on page 486

Spectrum Emission Mask (SEM) Measurement

4.5.5.6 List Evaluation

In the "List Evaluation" dialog box, which is displayed when you select the "Evaluations" button in the "Overview" or the "List Evaluation" softkey in the "SEMAsk" menu, you configure the contents and display of the result list.



List Evaluation State	93
Show Peaks	93
Margin	93
Saving the Evaluation List	

List Evaluation State

Activates or deactivates the list evaluation.

SCPI command:

CALCulate<n>:ESPectrum:PSEarch|PEAKsearch:AUTO on page 506 TRACe<n>[:DATA] on page 625

Show Peaks

If activated, all peaks that have been detected during an active list evaluation are marked with blue squares in the diagram.

SCPI command:

CALCulate<n>:ESPectrum:PSEarch|PEAKsearch:PSHow on page 507

Margin

Although a margin functionality is not available for the limit check, a margin (threshold) for the peak values to be displayed in the evaluation list (and diagram, if activated) can be defined. Only peaks that exceed the margin value are displayed.

SCPI command:

CALCulate<n>:ESPectrum:PSEarch|PEAKsearch:MARGin on page 507

Saving the Evaluation List

Exports the evaluation list of the SEM measurement to an ASCII file for evaluation in an external application. If necessary, change the decimal separator for evaluation in other languages.

Spectrum Emission Mask (SEM) Measurement

Define the file name and storage location in the file selection dialog box that is displayed when you select the "Save" function.

For details see chapter 4.5.7.2, "ASCII File Export Format (Spectrum Emission Mask)", on page 103.

SCPI command:

MMEMory: STORe: LIST on page 696

FORMat: DEXPort: DSEParator on page 678

4.5.6 How to Perform a Spectrum Emission Mask Measurement

SEM measurements can be performed according to a specific standard or freely configured. Configuration for signals with a very regular channel definition can be configured very quickly and easily. Selecting the SEM measurement is a prerequisite for all other tasks. For multi-standard radio SEM measurements, configuration for specified scenarios can be done automatically.

The following tasks are described:

- "To select an SEM measurement" on page 94
- "To perform an SEM measurement according to a standard" on page 94
- "To configure a user-defined SEM measurement" on page 94
- "To perform an MSR SEM measurement" on page 96

To select an SEM measurement

▶ Press the MEAS key, then select the "Spectrum Emission Mask" measurement.

To perform an SEM measurement according to a standard

► Load the settings file as described in "How to load an SEM settings file" on page 96 and start a measurement.

To configure a user-defined SEM measurement

- 1. Define the span of the signal to be monitored in the general span settings.
- Split the frequency span of the measurement into ranges for signal parts with similar characteristics.

Starting from the center frequency, determine which sections of the signal to the left and right can be swept and monitored using the same parameters. Criteria for such a range definition may be, for example:

- The signal power level
- The required resolution bandwidth or sweep time
- Transducer factors
- Permitted deviation from the defined signal level, i.e. the required limit values for monitoring

If the signal consists of a transmission channel and adjacent channels, the channel ranges can usually be used for the range definition.

Spectrum Emission Mask (SEM) Measurement

- If the signal power level to be monitored may vary and the limits will vary accordingly, define power classes. For each range of levels that can be monitored in the same way, define a power class.
 - a) Select the "Overview" softkey, then select the "SEM Setup" button and swtich to the "Power Classes" tab.
 - b) Add a power class by selecting the "Add" button.
 - c) Enter the start and stop power levels to define the class.
 - d) Select the power classes to be used for the current measurement: either a specific class, or all classes, to have the required class selected automatically according to the input level measured in the reference range.
- Select the "Sweep List" tab of the "Spectrum Emission Mask" dialog box.
- 5. Insert the required ranges using the "Insert before Range" and "Insert after Range" buttons, which refer to the currently selected range (the reference range by default). If the signal trace is symmetric to the center frequency, activate the "Sym Setup" option to make setup easier and quicker.
- 6. Define the measurement parameters for each range as required. If symmetrical setup is activated, you only have to configure the ranges to one side of the center range. In particular, define the limits for each range of the signal, i.e. the area in which the signal level may deviate without failing the limit check. If several power classes were defined (see step 3), define limits for each power class.
 - a) Define the type of limit check, i.e. whether absolute values or relative values are to be checked, or both. The type of limit check is identical for all power classes.
 - b) Define the limit start and stop values.
- 7. If the sweep list settings other than the limit and transducer values are identical for several adjacent ranges, activate "Fast SEM" mode to speed up the measurement. You only have to activate the mode for one range, the others are adapted automatically.
- 8. If necessary, change the settings for the reference power to which all SEM results refer in the "Reference Range" tab.
- 9. To indicate the determined peaks in the display during an SEM measurement, select the "Evaluations" button in the "Overview" and activate the "Show Peaks" option.
- 10. To save the current SEM measurement settings to a file to re-use them later, save a settings file as described in "How to save a user-defined SEM settings file" on page 96.
- 11. Start a sweep.
 - The determined powers and limit deviations for each range are indicated in the evaluation list. If activated, the peak power levels for each range are also indicated in the diagram.
- 12. To save the evaluation list, export the results to a file as described in chapter 4.5.6.2, "How to Save SEM Result Files", on page 97.

Spectrum Emission Mask (SEM) Measurement

To perform an MSR SEM measurement

- 1. Select the "MSR Config" softkey.
- Select the band category that determines the digital standards used in the measurement setup (see "Band Category" on page 90).
- 3. Define the bandwidth that contains all relevent carrier signals to be measured.
- For measurements with GSM/EDGE, LTE FDD and WCDMA carriers (BC2), define whether a GSM/EDGE or an LTE FDD carrier, or both, are located at the edge of the bandwidth.
- 5. Select the "Apply to SEM" button.
 - The Sweep list is configured according to the MSR specification, with the required number of ranges and defined limits.
- 6. Start a sweep.
 - The determined powers and limit deviations for each range are indicated in the evaluation list. If activated, the peak power levels for each range are also indicated in the diagram.
- 7. To save the evaluation list, export the results to a file as described in chapter 4.5.6.2, "How to Save SEM Result Files", on page 97.

4.5.6.1 How to Manage SEM Settings Files

SEM measurement settings can be saved to an xml file which can then be exported to another application or loaded on the R&S FSW again at a later time. Some predefined XML files are provided that contain ranges and parameters according to the selected standard. All XML files are stored under C:\r s\instr\sem std.

For details on the file format of the SEM settings file, see chapter 4.5.7.1, "Format Description of SEM XML Files", on page 98.

SEM settings or standard files are managed in the "Standards" tab of the "Spectrum Emission Mask" dialog box. To display this dialog box, select the "Overview" softkey and then the "SEM Setup" button.

How to load an SEM settings file

- 1. From the file selection dialog box, select the settings file (with an ".xml" extension).
- 2. Select the "Load" button.

The settings from the selected file are restored to the R&S FSW and you can repeat the SEM measurement with the stored settings.

How to save a user-defined SEM settings file

1. Configure the SEM measurement as required (see chapter 4.5.6, "How to Perform a Spectrum Emission Mask Measurement", on page 94).

Spectrum Emission Mask (SEM) Measurement

2. In the "Standard Files" tab of the "Spectrum Emission Mask" dialog box, define a file name and storage location for the settings file.

3. Select the "Save" button.

The settings are stored to a file with the extension ".xml" as specified.

How to delete an SEM settings file

- 1. In the "Standard Files" tab of the "Spectrum Emission Mask" dialog box, select the file you want to delete.
- 2. Select the "Delete" button.
- 3. Confirm the message.

The settings file is removed from the R&S FSW.

How to restore default SEM settings files

The R&S FSW is delivered with predefined settings files which can be edited and overwritten. However, you can restore the original files.

► In the "Standard Files" tab of the "Spectrum Emission Mask" dialog box, select the "Restore Standard Files" button.

The original predefined settings files are available for selection on the R&S FSW.

4.5.6.2 How to Save SEM Result Files

The evaluation list from an SEM measurement can be saved to a file, which can be exported to another application for further analysis, for example.

For details on the file format of the SEM export file, see chapter 4.5.7.2, "ASCII File Export Format (Spectrum Emission Mask)", on page 103.

- Configure and perform an SEM measurement as described in chapter 4.5.6, "How to Perform a Spectrum Emission Mask Measurement", on page 94.
- 2. In the "Overview", select the "Evaluation" button.
- 3. If necessary, change the "Decimal Separator" to "COMMA" for evaluation in other languages.
- 4. Select the "Save" button.
- 5. In the file selection dialog box, select a storage location and file name for the result file.
- 6. Select the "Save" button.

The file with the specified name and the extension .dat is stored in the defined storage location.

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4.5.7 Reference: SEM File Descriptions

This reference provides details on the format of the SEM settings and result files.

- ASCII File Export Format (Spectrum Emission Mask)......103

4.5.7.1 Format Description of SEM XML Files

The SEM XML files offer a quick way to change the measurement settings. A set of ready-made XML files for different standards is already provided. You can also create and use your own XML files. Alternatively, edit the settings directly in the "Spectrum Emission Mask" dialog box and save the XML file afterwards. This way, no modifications have to be done in the XML file itself.

In addition to saving the current settings to a file, settings files can also be created independently of the R&S FSW, in an exernal application. When creating your own XML files, be sure to comply with the following conventions because the R&S FSW can only interpret XML files of a known structure. For sample files look in the $C: \r_s\$ directory of the R&S FSW.

To load a settings file, use the "Load" function in the "Standard Files" tab of the "Spectrum Emission Mask" dialog box (see "How to load an SEM settings file" on page 96). All XML files are stored under C:\r s\instr\sem std.

The files for importing range settings obey the rules of the XML standard. The child nodes, attributes, and structure defined for the data import are described here.



Be sure to follow the structure exactly as shown below or else the R&S FSW is not able to interpret the XML file and error messages are shown on the screen. It is recommended that you make a copy of an existing file and edit the copy of the file.

Basically, the file consists of three elements that can be defined:

- The "BaseFormat" element
- The "PowerClass" element
- The "Range" element

The "BaseFormat" element

It carries information about basic settings. In this element only the "ReferencePower" child node has any effects on the measurement itself. The other attributes and child nodes are used to display information about the Spectrum Emission Mask Standard on the measurement screen. The child nodes and attributes of this element are shown in table 4-4.

Spectrum Emission Mask (SEM) Measurement

Example:

In the sample file PowerClass_39_43.xml under
C:\r s\instr\sem std\WCDMA\3GPP, these attributes are defined as follows:

- Standard="W-CDMA 3GPP"
- LinkDirection="DL"
- PowerClass="(39,43)dBm"

The "PowerClass" element

It is embedded in the "BaseFormat" element and contains settings information about the power classes. Up to four different power classes can be defined. For details refer to chapter 4.5.5.3, "Power Classes", on page 88. The child nodes and attributes of this element are shown in table 4-5.

The "Range" element

This element is embedded in the "PowerClass" element. It contains the settings information of the range. There have to be at least three defined ranges: one reference range and at least one range to either side of the reference range. The maximum number of ranges is 20. Note that the R&S FSW uses the same ranges in each power class. Therefore, the contents of the ranges of each defined power class have to be identical to the first power class. An exception are the Start and Stop values of the two Limit nodes that are used to determine the power class. Note also, that there are two Limit nodes to be defined: one that gives the limit in absolute values and one in relative values. Make sure units for the Start and Stop nodes are identical for each Limit node.

For details refer to chapter 4.5.5.1, "Sweep List", on page 82. The child nodes and attributes of this element are shown in table 4-6.

The following tables show the child nodes and attributes of each element and show if a child node or attribute is mandatory for the R&S FSW to interpret the file or not. Since the hierarchy of the XML can not be seen in the tables, either view one of the default files already stored on the R&S FSW in the "C:\r_s\instr\sem_std" directory or check the structure as shown below.

Below, a basic example of the structure of the file is shown, containing all mandatory attributes and child nodes. Note that the "PowerClass" element and the range element are themselves elements of the "BaseFormat" element and are to be inserted where noted. The separation is done here simply for reasons of a better overview. Also, no example values are given here to allow a quick reference to the tables above. Italic font shows the placeholders for the values.

- The "BaseFormat" element is structured as follows:
 - <RS SEM ACP FileFormat Version=""1.0.0.0"">
 - <Name>"Standard"</Name>
 - <Instrument>
 - <Type>"Instrument Type"</Type>
 - <Application>"Application"</Application>

 - <LinkDirection Name=""Name"">
 - <ReferencePower>

Spectrum Emission Mask (SEM) Measurement

```
<Method>"Method"</Method>
   </ReferencePower>
   <PowerClass Index=""n"">
   <!-- For contents of the PowerClass node see table 4-5 -->
   <!-- Define up to four PowerClass nodes -->
   </PowerClass>
   </LinkDirection>
   </RS SEM ACP File>
The "PowerClass" element is structured as follows:
   <PowerClass Index=""n"">
   <StartPower Unit=""dBm"" InclusiveFlag=""true"" Value=""StartPowerValue""/>
   <StopPower Unit=""dBm"" InclusiveFlag=""false"" Value=""StopPowerValue""/>
   <DefaultLimitFailMode>"Limit Fail Mode"</DefaultLimitFailMode>
   <Range Index=""n"">
   <!-- For contents of the Range node see table 4-6 -->
   <!-- Define up to twenty Range nodes -->
   </Range>
   </PowerClass>
The "Range" element is structured as follows:
   <Range Index=""n"">
   <Name=""Name"">
   <ChannelType>"Channel Type"
   <WeightingFilter>
   <Type>"FilterType"</Type>
   <RollOffFactor>"Factor"</RollOffFactor>
   <Bandwith>"Bandwidth"</Bandwidth>
   </WeightingFilter>
   <FrequencyRange>
   <Start>"RangeStart"</Start>
   <Stop>"RangeStop"</Stop>
   </FrequencyRange>
   <Limit>
   <Start Unit=""Unit"" Value=""Value""/>
   <Stop Unit=""Unit"" Value=""Value""/>
   </Limit>
   <Limit>
   <Start Unit=""Unit"" Value=""Value""/>
   <Stop Unit=""Unit"" Value=""Value""/>
   </Limit>
   <RBW Bandwidth=""Bandwidth"" Type=""FilterType""/>
   <VBW Bandwidth=""Bandwidth""/>
   <Detector>"Detector"</Detector>
   <Sweep Mode=""SweepMode"" Time=""SweepTime""/>
   <Amplitude>
   <ReferenceLevel Unit=""dBm"" Value=""Value""/>
   <RFAttenuation Mode=""Auto"" Unit=""dB"" Value=""Value""/>
   <Pre><Pre>reamplifier State=""State""/>
   </Amplitude>
```

Spectrum Emission Mask (SEM) Measurement

</Range>

Table 4-4: Attributes and child nodes of the BaseFormat element

Child Node	Attribute	Value	Parameter Description	Mand.
	FileFormatVersion	1.0.0.0		Yes
	Date	YYYY-MM-DD HH:MM:SS	Date in ISO 8601 format	No
Name		<string></string>	Name of the standard	Yes
Instrument	Туре	FSL	Name of the instrument	No
	Application	SA K72 K82	Name of the application	No
LinkDirection	Name	Downlink Uplink None		Yes
	ShortName	DL UL		No
Reference- Power				Yes
Method	TX Channel Power TX Channel Peak Power			Yes
Reference- Channel	<string></string>			No

Table 4-5: Attributes and child nodes of the PowerClass element

Child Node	Attribute	Value	Parameter Description	Mand.
StartPower	Value	<power dbm="" in=""></power>	The start power must be equal to the stop power of the previous power class. The Start-Power value of the first range is -200	Yes
	Unit	dBm		Yes
	InclusiveFlag	true		Yes
StopPower	Value	<power dbm="" in=""></power>	The stop power must be equal to the start power of the next power class. The StopPower value of the last range is 200	Yes
	Unit	dBm		
	InclusiveFlag	false		Yes
DefaultLimitFailMode		Absolute Relative Absolute and Rela- tive Absolute or Relative		Yes

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Table 4-6: Attributes and child nodes of the Range element (normal ranges)

CeChannel to tains a name the range is the reference range. Short-Name TX Adjacent TX Adjacent TX Adjacent TX Adjacent TX Adjacent TX Adjacent Pess Only if Reference Power med is TX Channel Power and the range is the r	d Node	Attribute	Value	Parameter Description	Mand.
CeChannel of tains a name of the range is the reference range. Short-Name Short-Name TX Adjacent TX Adjacent TX Adjacent TX Adjacent Only if Reference Power met is TX Channel Power and the range is the rence range. Type RRC CFitter Type of the weighting filter Fitter Type of the weighting filter Yes Roll Off Factor O1 Excess bandwidth of the filter bandwidth of the filter Shandwidth Shandwidth in Hz> Fitter bandwidth Only if the filtype is RRC FrequencyRange Start Start Start value of the range Yes Start Stop Start Start value of the range Yes A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value Snumeric_value> Unit dBm/Hz dBm dBc dBr dB dBr		Index	019		Yes
Name ChannelType TX Adjacent Yes WeightingFilter WeightingFilter RRC CFilter Type of the weighting filter Type RRC CFilter Type of the weighting filter Yes Roll Off Factor 01 Excess bandwidth of the filter type is RRC Bandwidth Shandwidth in Hz> Filter bandwidth Only if the filter type is RRC FrequencyRange Start Start value of the range Yes Stop A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value Start Value Start Value Start Value Start Value Start Value Start Value Power limit at start frequency Yes Stop Value Start Value Power limit at stop frequency Unit dBm/Hz dBm dBc dBr dBc dBr dBm dBr		Name	<string></string>	Name of the range	Only if Referen- ceChannel con- tains a name and the range is the reference range
WeightingFilter WeightingFilter RRC CFilter Type of the weighting filter Type RRC CFilter Type of the weighting filter Yes Roll Off Factor 01 Excess bandwidth of the filtype is RRC Bandwidth Sbandwidth in Hz> Filter bandwidth Only if the filtype is RRC FrequencyRange Start Start value of the range Yes Stop Stop Stop value of the range Yes A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value Start Value A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value A Range must contain exactly two limit nodes; one of the limit nodes; one of the limit nodes has to have a relative unit (e.g. dBm) Start Value A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBc), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the other one must have an absolute unit (e.g. dBr), the			<string></string>	Short name of the range	No
cePower mei is TX Chann- Power and tr range is the rence range Type RRC CFilter Type of the weighting filter Yes Roll Off Factor 01 Excess bandwidth of the filtype is RRC Bandwidth Sbandwidth in Hz> Filter bandwidth Only if the filtype is RRC FrequencyRange Yes Start Start Start Start value of the range Yes Stop Start Stop Value of the range Yes Limit Start Stop Value of the range Yes Limit Stop A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value Stop Power limit at start frequency Yes Unit Start Sets the unit of the start value Stop Value Sets the unit of the stop value Indir of the stop value Stop Value Sets the unit of the stop value Indir of the stop value Indir of the stop value Indir of the stop value Stop Unit Sets the unit of the stop value Indir of the stop value Indir of the stop value Stop Value Sets the unit of the stop value	inelType		TX Adjacent		Yes
Roll Off Factor 01 Excess bandwidth of the filtype is RRC Bandwidth	htingFilter				Only if ReferencePower method is TX Channel Power and the range is the reference range
ter type is RRC Bandwidth			RRC CFilter	Type of the weighting filter	Yes
type is RRC FrequencyRange Start Start Stop	Off Factor		01		Only if the filter type is RRC
Start	width		<bandwidth hz="" in=""></bandwidth>	Filter bandwidth	Only if the filter type is RRC
Stop	uencyRange				Yes
Limit dBm/Hz dBm dBc A Range must contain exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value <numeric_value> Power limit at start frequency Yes Unit dBm/Hz dBm dBc Sets the unit of the start value Stop Value <numeric_value> Power limit at stop frequency Unit dBm/Hz dBm dBc Sets the unit of the stop value dBr dB Sets the unit of the stop value Sets the unit of the stop value Sets the unit of the stop value</numeric_value></numeric_value>			<frequency hz="" in=""></frequency>	Start value of the range	Yes
dBr dB exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an absolute unit (e.g. dBm) Start Value <numeric_value> Power limit at start frequency Yes Unit dBm/Hz dBm dBc Sets the unit of the start value Stop Value <numeric_value> Power limit at stop frequency Unit dBm/Hz dBm dBc Sets the unit of the stop value Unit dBm/Hz dBm dBc Sets the unit of the stop value </numeric_value></numeric_value>			<frequency hz="" in=""></frequency>	Stop value of the range	Yes
Unit dBm/Hz dBm dBc Sets the unit of the start value Stop Value <numeric_value> Power limit at stop frequency Unit dBm/Hz dBm dBc Sets the unit of the stop value dBr dB</numeric_value>				exactly two limit nodes; one of the limit nodes has to have a relative unit (e.g. dBc), the other one must have an	Yes
Stop Value value Value Power limit at stop frequency Unit dBm/Hz dBm dBc Sets the unit of the stop value dBr dB	,	Value	<numeric_value></numeric_value>	Power limit at start frequency	Yes
Unit dBm/Hz dBm dBc Sets the unit of the stop value dBr dB		Unit			
dBr dB		Value	<numeric_value></numeric_value>	Power limit at stop frequency	
Limit Fri Made		Unit	' '	Sets the unit of the stop value	
LimitFailMode Absolute Relative If used, it has to be identical to DefaultLimitFailMode tive Absolute or Relative	FailMode		tive Absolute or	If used, it has to be identical to DefaultLimitFailMode	No
RBW Bandwidth 	,	Bandwidth	<bandwidth hz="" in=""></bandwidth>	"RBW" on page 83	Yes
Type NORM PULS No CFIL RRC		Туре			No
VBW Bandwidth 		Bandwidth	<bandwidth hz="" in=""></bandwidth>	"VBW" on page 84	Yes

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Child Node	Attribute	Value	Parameter Description	Mand.
Detector		NEG POS SAMP RMS AVER QUAS	If used, it has to be identical in all ranges.	No
Sweep	Mode	Manual Auto	"Sweep Time Mode" on page 84	Yes
	Time	<time in="" sec=""></time>	"Sweep Time" on page 84	No
Amplitude				No
ReferenceLevel	Value	<power dbm="" in=""></power>	"Ref. Level" on page 84	Yes, if the ReferenceLevel child node is used
	Unit	dBm	Defines dBm as unit	Yes, if the ReferenceLevel node is used
RFAttenuation	Mode	Manual Auto	"RF Att. Mode" on page 84	Yes, if the ReferenceLevel child node is used
Preamplifier		ON OFF	"Preamp" on page 84	Yes

4.5.7.2 ASCII File Export Format (Spectrum Emission Mask)

When trace data from an SEM measurement is exported, the data is stored in ASCII format as described below. The first part of the file lists information about the signal analyzer and the general setup.

File contents	Explanation
File header	
Type;FSW-26;	Model
Version;1.00;	Firmware version
Date;31.Mar 11;	Storage date of data set
Mode;ANALYZER;SEM;	Operating mode and measurement function
Center Freq;13250000000.000000;Hz	X-axis settings
Freq Offset;0.000000;Hz	
Span;25500000.000000;Hz	
x-Axis;LIN;	
Start;13237250000.000000;Hz	
Stop;13262750000.000000;Hz	
Level Offset;0.000000;dB	Y-axis settings
Ref Position;100.000000;%	
y-Axis;LOG;	

Spurious Emissions Measurement

File contents	Explanation
Level Range;100.000000;dB	
Trace settings	
Trace Mode;CLR/WRITE;	
Detector;RMS;	
Sweep Count;0;	
Trace 1:;	
x-Unit;Hz;	
y-Unit;dBm;	
List evaluation settings	
Margin;200;	Peak List margin
Reference range settings	
RefType; CPOWER;	Reference power type
TxBandwidth;3840000;;Hz	Channel power settings
Filter State; ON;	
Alpha;0.22;	
PeaksPerRange;1;	Max. number of peaks per range to be detected
Values;2;	Number of detected peaks
File data section	
0;-12750000;-2515000;30000;13242367500;-43.844	Measured peak values:
722747802734;-0.33028793334960938;49.6697120 66650391;FAIL;	<range number="">;</range>
, ,	<start frequency="">;</start>
2;2515000;12750000;30000;13257632500;-43.8447 22747802734;-0.33028793334960938;49.66971206	<stop frequency="">;</stop>
6650391;FAIL;	<pre><resolution bandwidth="" of="" range="">;</resolution></pre>
	<frequency of="" peak="">;</frequency>
	<pre><absolute dbm="" in="" of="" peak="" power="">;</absolute></pre>
	<pre><relative dbc="" in="" of="" peak="" power="">; (related to the chan- nel power)</relative></pre>
	<pre><distance db="" in="" limit="" line="" the="" to="">; (positive value means above the limit)</distance></pre>
	<pre>limit fail (pass = 0, fail =1)>;</pre>

4.6 Spurious Emissions Measurement

The R&S FSW supports Spurious Emissions measurements.

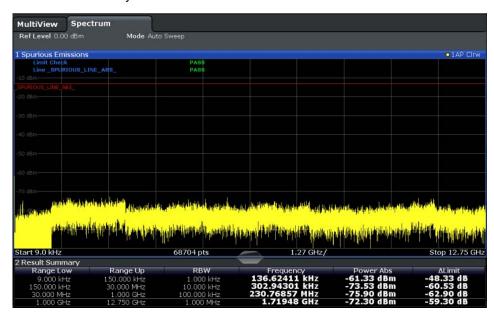
•	About the Measurement	105
•	Spurious Emissions Measurement Results	105
	Spurious Emissions Basics	106

Spurious Emissions Measurement

•	Spurious Emissions Measurement Configuration	.108
	How to Perform a Spurious Emissions Measurement	
	Reference: ASCII Export File Format (Spurious)	

4.6.1 About the Measurement

The Spurious Emissions measurement monitors unwanted RF products outside the assigned frequency band generated by an amplifier. The spurious emissions are usually measured across a wide frequency range. The Spurious Emissions measurement allows a flexible definition of all parameters. A result table indicates the largest deviations of the absolute power from the limit line for each range, and the results can be checked against defined limits automatically.



4.6.2 Spurious Emissions Measurement Results

The measured signal, including any spurious emissions, and optionally the detected peaks are displayed in the Spurious Emissions measurement diagram. If defined, the limit lines and the limit check results are also indicated. In addition to the graphical results, a result table can be displayed to evaluate the measured powers and limit check results (see also chapter 4.6.3.2, "Limit Lines in Spurious Measurements", on page 107). The details of the evaluation list can be configured.



The following information is provided in the evaluation list for each range:

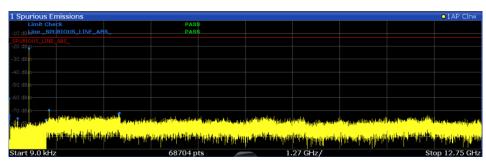
Spurious Emissions Measurement

Column	Description
Range Low	Frequency range start for the range the peak value belongs to
Range Up	Frequency range end for the range the peak value belongs to
RBW	RBW of the range
Frequency	Frequency at the peak value
Power Abs	Absolute power level at the peak value
ΔLimit	Deviation of the absolute power level from the defined limit for the peak value

By default, one peak per range is displayed. However, you can change the settings to:

- Display all peaks
- Display a certain number of peaks per range
- Display only peaks that exceed a threshold ("Margin")

In addition to listing the peaks in the list evaluation, detected peaks can be indicated by blue squares in the diagram.



Furthermore, you can save the evaluation list to a file.

Retrieving Results via Remote Control

The measured spurious values of the displayed trace can be retrieved using the TRAC: DATA? SPUR command (see TRACe<n>[:DATA] on page 625).

4.6.3 Spurious Emissions Basics

Some background knowledge on basic terms and principles used in Spurious Emissions measurements is provided here for a better understanding of the required configuration settings.

Spurious Emissions Measurement

4.6.3.1 Ranges and Range Settings

Conditions for ranges

The following rules apply to ranges:

- The minimum span of a range is 20 Hz.
- The individual ranges must not overlap (but may have gaps).
- The maximum number of ranges is 20.
- The maximum number of sweep points in all ranges is limited to 100001.

If you set a span that is smaller than the overall span of the ranges, the measurement includes only the ranges that lie within the defined span and have a minimum span of 20 Hz.



Defining ranges by remote control

In Spurious Emissions measurements, there are no remote commands to insert new ranges between existing ranges directly. However, you can delete or re-define the existing ranges to create the required order.

A remote command example for defining parameters and ranges in Spurious Emissions measurements is described in chapter 10.3.7.5, "Programming Example: Spurious Emissions Measurement", on page 520.

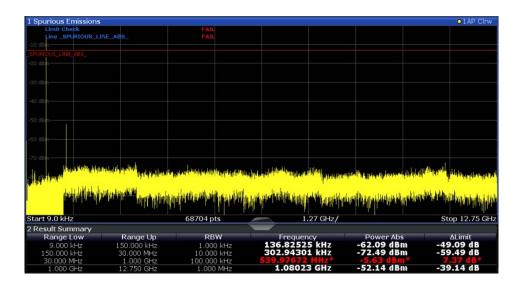
4.6.3.2 Limit Lines in Spurious Measurements

Limit lines allow you to check the measured data against specified limit values. Generally, it is possible to define limit lines for any measurement in the Spectrum application using the LINES key. For Spurious measurements, however, a special limit line is available via the "Sweep List", and it is strongly recommended that you use only this limit line definition.

In the "Sweep List" you can define a limit line that varies its level according to the specified frequency ranges. A distinguished limit line ("_SPURIOUS_LINE_ABS") is automatically defined according to the current "Sweep List" settings every time the settings change.

If a limit check is activated in the "Sweep List", the "_SPURIOUS_LINE_ABS" limit line is indicated by a red line in the display, and the result of the limit check is indicated at the top of the diagram. Note that only "Pass" or "Fail" is indicated; a "margin" function as for general limit lines is not available. Also, only absolute limits can be checked, not relative ones.

Spurious Emissions Measurement





As for general limit lines, the results of each limit line check are displayed (here: "_SPU-RIOUS_LINE_ABS"), as well as the combined result for all defined limit lines ("Limit Check").

The limit check is considered to be "failed" if any signal level outside the absolute limits is measured.

In addition to the limit line itself, the largest deviations of the absolute power from the limit line for each range are displayed in the evaluation list if the limit check is activated. Values that exceed the limit are indicated in red and by an asterisk (*).



Although a margin functionality is not available for the limit check, a margin (threshold) for the peak values to be displayed in the evaluation list can be defined in the list evaluation settings. Furthermore, you can define how many peaks per range are listed. For details see chapter 4.6.4.3, "List Evaluation", on page 113.

4.6.4 Spurious Emissions Measurement Configuration

Spurious emissions measurements are selected via the "Spurious Emissions" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "Spurious Emissions" dialog box, which is displayed when you select the "Spurious Setup" button in the "Overview" or the "Sweep List" softkey from the "Spurious Emissions" menu.

For details on using the configuration "Overview", see chapter 5.1, "Configuration Overview", on page 159.

The remote commands required to perform these tasks are described in chapter 10.3.7, "Measuring Spurious Emissions", on page 511.

The following settings are available in individual tabs of the "Spurious Emissions" configuration dialog box, or via softkeys in the "SpurEm" menu.

Spurious Emissions Measurement

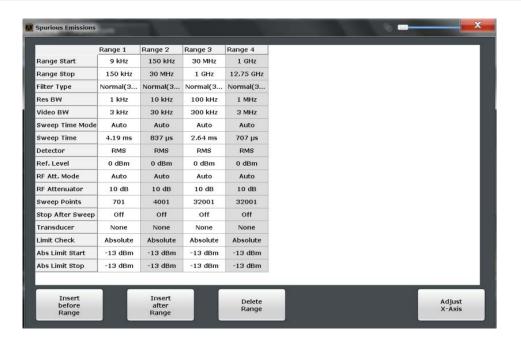
•	Sweep List	.109
•	Adjusting the X-Axis to the Range Definitions	112
	List Evaluation.	

4.6.4.1 **Sweep List**

For Spurious Emissions measurements, the input signal is split into several frequency ranges which are swept individually and for which different limitations apply. In the "Sweep List" dialog box you configure the individual frequency ranges and limits.



If you edit the sweep list, always follow the rules and consider the limitations described in chapter 4.6.3.1, "Ranges and Range Settings", on page 107.



Range Start / Range Stop	110
Filter Type	110
RBW	
VBW	110
Sweep Time Mode	110
Sweep Time	
Detector	
Ref. Level	111
RF Att. Mode	111
RF Attenuator	111
Preamp	111
Sweep Points	
Stop After Sweep	
Transducer	
Limit Check	

Spurious Emissions Measurement

Abs Limit Start/Stop	112
Insert before/after Range	
Delete Range	

Range Start / Range Stop

Sets the start frequency/stop frequency of the selected range.

If you set a span that is smaller than the overall span of the ranges, the measurement includes only the ranges that lie within the defined span and have a minimum span of 20 Hz.

SCPI command:

```
[SENSe:]LIST:RANGe<range>[:FREQuency]:STARt on page 514
[SENSe:]LIST:RANGe<range>[:FREQuency]:STOP on page 514
```

Filter Type

Sets the filter type for this range.

For details on filter types see chapter 5.5.1.6, "Which Data May Pass: Filter Types", on page 196.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:FILTer:TYPE on page 513
```

RRW

Sets the RBW value for this range.

For details on the RBW see chapter 5.5.1.1, "Separating Signals by Selecting an Appropriate Resolution Bandwidth", on page 194.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:BANDwidth[:RESolution] on page 512
```

VBW

Sets the VBW value for this range.

For details on the VBW see chapter 5.5.1.2, "Smoothing the Trace Using the Video Bandwidth", on page 195.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:BANDwidth:VIDeo on page 512
```

Sweep Time Mode

Activates or deactivates the auto mode for the sweep time.

For details on the sweep time mode see chapter 5.5.1.7, "How Long the Data is Measured: Sweep Time", on page 197

SCPI command:

```
[SENSe:]LIST:RANGe<range>:SWEep:TIME:AUTO on page 518
```

Sweep Time

Sets the sweep time value for the range.

Spurious Emissions Measurement

For details on the sweep time see chapter 5.5.1.7, "How Long the Data is Measured: Sweep Time", on page 197

SCPI command:

```
[SENSe:]LIST:RANGe<range>:SWEep:TIME on page 518
```

Detector

Sets the detector for the range. For details refer to chapter 6.3.1.1, "Mapping Samples to Sweep Points with the Trace Detector", on page 237.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:DETector on page 513
```

Ref. Level

Sets the reference level for the range.

For details on the reference level see chapter 5.4.1.1, "Reference Level", on page 185.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:RLEVel on page 517
```

RF Att. Mode

Activates or deactivates the auto mode for RF attenuation.

For details on attenuation see chapter 5.4.1.2, "RF Attenuation", on page 185.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:INPut:ATTenuation:AUTO on page 515
```

RF Attenuator

Sets the attenuation value for that range.

For details on attenuation see chapter 5.4.1.2, "RF Attenuation", on page 185.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:INPut:ATTenuation on page 515
```

Preamp

Switches the preamplifier on or off.

For details on the preamplifier see "Preamplifier (option B24)" on page 190.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:INPut:GAIN:STATe on page 516
```

Sweep Points

Sets the number of sweep points for the specified range.

For details on sweep points see chapter 5.5.1.8, "How Much Data is Measured: Sweep Points and Sweep Count", on page 198.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:POINts on page 517
```

Stop After Sweep

This command configures the sweep behavior.

Spurious Emissions Measurement

"ON" The R&S FSW stops after one range is swept and continues only if you

confirm (a message box is displayed).

"OFF" The R&S FSW sweeps all ranges in one go.

SCPI command:

```
[SENSe:]LIST:RANGe:BREak on page 512
```

Transducer

Sets a transducer for the specified range. You can only choose a transducer that fulfills the following conditions:

- The transducer overlaps or equals the span of the range.
- The x-axis is linear.
- The unit is dB.

For details on transducers see chapter 8.2, "Basics on Transducer Factors", on page 342.

SCPI command:

```
[SENSe:]LIST:RANGe<range>:TRANsducer on page 518
```

Limit Check

Activates or deactivates the limit check for all ranges.

For details on limit checks see chapter 4.6.3.2, "Limit Lines in Spurious Measurements", on page 107.

"Absolute" Signal is checked against absolute limit values

"None" No limit check is performed.

SCPI command:

```
[SENSe:]LIST:RANGe:LIMit:STATe on page 517
CALCulate<n>:LIMit<k>:FAIL on page 676
```

Abs Limit Start/Stop

Sets an absolute limit value at the start or stop frequency of the range [dBm].

SCPI command:

```
[SENSe:]LIST:RANGe<range>:LIMit:STARt on page 516
[SENSe:]LIST:RANGe<range>:LIMit:STOP on page 517
```

Insert before/after Range

Inserts a new range to the left of the currently focused range (before) or to the right (after). The range numbers of the currently focused range and all higher ranges are increased accordingly. The maximum number of ranges is 20.

Delete Range

Deletes the currently focused range. The range numbers are updated accordingly.

4.6.4.2 Adjusting the X-Axis to the Range Definitions

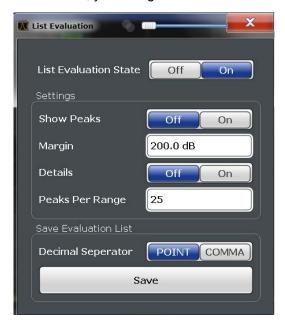
The frequency axis of the measurement diagram can be adjusted automatically so that the span of all sweep list ranges corresponds to the displayed span. Thus, the x-axis

Spurious Emissions Measurement

range is set from the start frequency of the first sweep range to the stop frequency of the last sweep range.

4.6.4.3 List Evaluation

In the "List Evaluation" dialog box, which is displayed when you select the "Evaluations" button in the "Overview" or the "List Evaluation" softkey in the "Spurious Emissions" menu, you configure the contents and display of the result list.



List Evaluation State	113
Show Peaks	113
Margin	114
Details	
Peaks per Range	114
Saving the Evaluation List	

List Evaluation State

Activates or deactivates the list evaluation.

SCPI command:

CALCulate<n>:ESPectrum:PSEarch|PEAKsearch:AUTO on page 506 TRACe<n>[:DATA] on page 625

Show Peaks

If activated, all peaks that have been detected during an active list evaluation are marked with blue squares in the diagram.

SCPI command:

CALCulate<n>:ESPectrum:PSEarch|PEAKsearch:PSHow on page 507

Spurious Emissions Measurement

Margin

Although a margin functionality is not available for the limit check, a margin (threshold) for the peak values to be displayed in the evaluation list (and diagram, if activated) can be defined. Only peaks that exceed the margin value are displayed.

SCPI command:

CALCulate<n>:ESPectrum:PSEarch|PEAKsearch:MARGin on page 507

Details

Configures how detailed the list is.

On	Includes all detected peaks (up to a maximum defined by "Peaks per Range").
Off	Includes only one peak per range.

Peaks per Range

Defines the maximum number of peaks per range that are stored in the list. Once the selected number of peaks has been reached, the peak search is stopped in the current range and continued in the next range. The maximum value is 50.

SCPI command:

CALCulate<n>: PSEarch | PEAKsearch: SUBRanges on page 520

Saving the Evaluation List

Exports the evaluation list of the Spurious Emissions measurement to an ASCII file for evaluation in an external application. If necessary, change the decimal separator for evaluation in other languages.

Define the file name and storage location in the file selection dialog box that is displayed when you select the "Save" function.

For details see "How to Save the Spurious Emissions Evaluation List" on page 115.

SCPI command:

MMEMory:STORe:LIST on page 696

FORMat:DEXPort:DSEParator on page 678

4.6.5 How to Perform a Spurious Emissions Measurement

- 1. Press the MEAS key, then select the "Spurious Emissions" measurement.
- 2. Define the span of the signal to be monitored in the general span settings.
- 3. Select the "Overview" softkey, then select the "Spurious Setup" button.
 - The "Spurious Emissions" dialog box is displayed.
- Split the frequency span of the measurement into ranges for signal parts with similar characteristics.
 - Define the required ranges in the "Sweep List" using the "Insert before Range" and "Insert after Range" buttons, which refer to the currently selected range.
- Define the measurement parameters for each range as required.

Spurious Emissions Measurement

- 6. Optionally, define a limit check.
 - Activate the limit check by setting "Limit Check" to "Absolute". The limit check is always activated or deactivated for all ranges simultaneously.
 - b) Define the limit line's start and stop values for each range of the signal. If a signal level higher than the defined limit is measured, the limit check fails, which may indicate a spurious emission.
- 7. Configure the peak detection during a Spurious Emissions measurement: select the "Evaluations" button in the "Overview".
 - To indicate the determined peaks in the display, activate the "Show Peaks" option.
 - To restrict peak detection, define a "Margin". Only peaks that exceed this value are detected.
 - To allow for more peaks per range to be detected than the default 1, increase the "Peaks Per Range" value and set "Details" to "On".
- Start a sweep.

The determined powers and limit deviations for each range are indicated in the evaluation list. If activated, the peak power levels for each range are also indicated in the diagram.

9. To save the evaluation list, export the results to a file as described in "How to Save the Spurious Emissions Evaluation List" on page 115.

How to Save the Spurious Emissions Evaluation List

The evaluation list from a Spurious Emissions measurement can be saved to a file, which can be exported to another application for further analysis, for example.

- 1. Configure and perform an Spurious Emissions measurement as described in chapter 4.6.5, "How to Perform a Spurious Emissions Measurement", on page 114.
- 2. Select the "Evaluations" button in the "Overview".
- 3. If necessary, change the "Decimal Separator" to "COMMA" for evaluation in other languages.
- 4. Select the "Save" button.
- 5. In the file selection dialog box, select a storage location and file name for the result file.
- 6. Select the "Save" button.

The file with the specified name and the extension .dat is stored in the defined storage location.

4.6.6 Reference: ASCII Export File Format (Spurious)

The file has a header containing important parameters for scaling, several data sections containing the sweep settings per range, and a data section containing the peak list.

Spurious Emissions Measurement

The header data is made up of three columns, separated by ';', with the syntax: parameter name; numeric value; basic unit

File contents	Explanation
File header	
Type;FSW-26;	Model
Version;1.00;	Firmware version
Date;31.Mar 11;	Storage date of data set
Mode;ANALYZER; SPURIOUS;	Operating mode and measurement function
Center Freq;13250000000.000000;Hz	X-axis settings
Freq Offset;0.000000;Hz	
Span;26499982000.000000;Hz	
x-Axis;LIN;	
Start;9000.000000;Hz Stop;80000000000.000000;Hz	
Level Offset;0.000000;dB	Y-axis settings
Ref Position;100.000000;%	
y-Axis;LOG;	
Level Range;100.000000;dB	
Trace settings	
Trace Mode;CLR/WRITE;	
Sweep Count;1;	
TRACE 1:	
Trace Mode;CLR/WRITE;	
x-Unit;Hz;	
y-Unit;dBm;	
List evaluation settings	
Margin;6.000000;s	Peak List margin
PeaksPerRange;25;	Max. number of peaks per range to be detected
Values;3;	Number of detected peaks

Statistical Measurements (APD, CCDF)

File contents	Explanation
File data section	
0;9000;150000;1000;79500;-25.006643295288086;-	Measured peak values:
12.006643295288086;PASS;	<range number="">;</range>
0;9000;150000;1000;101022.11126961483;-47.075 111389160156;-34.075111389160156;PASS;	<start frequency="">;</start>
0:9000;150000;1000;58380.171184022824;-47.079	<stop frequency="">;</stop>
341888427734;-34.079341888427734;PASS;	<resolution bandwidth="" of="" range="">;</resolution>
	<frequency of="" peak="">;</frequency>
	<absolute dbm="" in="" of="" peak="" power="">;</absolute>
	<pre><distance db="" in="" limit="" line="" the="" to="">; (positive value means above the limit)</distance></pre>
	<pre>fail (pass = 0, fail =1)>;</pre>

4.7 Statistical Measurements (APD, CCDF)

To measure the amplitude distribution, the R&S FSW has simple measurement functions to determine both the Amplitude Probability Distribution (APD) and the Complementary Cumulative Distribution Function (CCDF). Only one of the signal statistic functions can be switched on at a time.

 About the Measurer 	ments	117
 Typical Applications 	S	118
	sults	
	sics - Gated Triggering	
	nfiguration	
	APD or CCDF Measurement	
• Examples		129
	ubleshooting the Measurement	

4.7.1 About the Measurements

The probability of amplitude values can be measured with the Amplitude Probability Distribution function (APD). During a selectable measurement time all occurring amplitude values are assigned to an amplitude range. The number of amplitude values in the individual ranges is counted and the result is displayed as a histogram.

Alternatively, the Complementary Cumulative Distribution Function (CCDF) can be displayed. It shows the probability that the mean signal power amplitude will be exceeded in percent.

Only one of the signal statistic functions can be switched on at a time. When a statistic function is switched on, the R&S FSW is set into zero span mode automatically. The R&S FSW measures the statistics of the signal applied to the RF input with the defined analysis bandwidth. To avoid affecting the peak amplitudes the video bandwidth is automatically set to 10 times the analysis bandwidth. The sample detector is used for detecting the video voltage.

Statistical Measurements (APD, CCDF)

Statistic measurements on pulsed signals can be performed using a gated trigger. For details see chapter 4.7.4, "APD and CCDF Basics - Gated Triggering", on page 121.

4.7.2 Typical Applications

Digital modulated signals are similar to white noise within the transmit channel, but are different in their amplitude distribution. In order to transmit the modulated signal without distortion, all amplitudes of the signal have to be transmitted linearly from the output power amplifier. Most critical are the peak amplitude values. Degradation in transmit quality caused by a transmitter two port network is dependent on the amplitude of the peak values as well as on their probability.

If modulation types are used that do not have a constant envelope in zero span, the transmitter has to handle peak amplitudes that are greater than the average power. This includes all modulation types that involve amplitude modulation, QPSK for example. CDMA transmission modes in particular may have power peaks that are large compared to the average power.

For signals of this kind, the transmitter must provide large reserves for the peak power to prevent signal compression and thus an increase of the bit error rate at the receiver. The peak power or the crest factor of a signal is therefore an important transmitter design criterion. The crest factor is defined as the peak power to mean power ratio or, logarithmically, as the peak level minus the average level of the signal. To reduce power consumption and cut costs, transmitters are not designed for the largest power that could ever occur, but for a power that has a specified probability of being exceeded (e.g. 0.01 %).

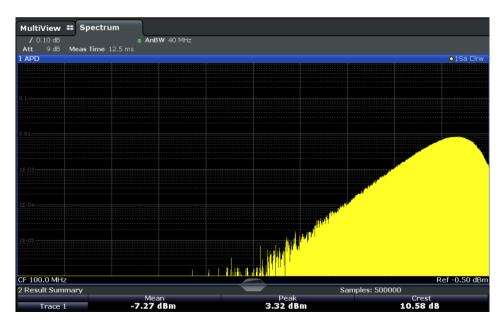
The statistical functions provide information on such signal criteria.

4.7.3 APD and CCDF Results

Amplitude Probability Distribution (APD)

As a result of the Amplitude Probability Distribution (APD) function, the probability of measured amplitude values is displayed. During a selectable measurement time all measured amplitude values are assigned to an amplitude range. The number of amplitude values in the specific ranges is counted and the result is displayed as a histogram. Each bar of the histogram represents the percentage of measured amplitudes within the specific amplitude range. The x-axis represents the amplitude values and is scaled in absolute values (dBm).

Statistical Measurements (APD, CCDF)



In addition to the histogram, a result table is displayed containing the following information:

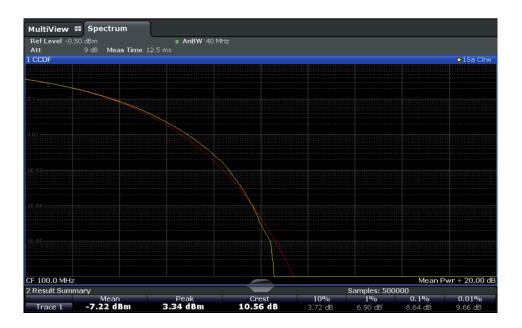
- Number of samples used for calculation
- For each displayed trace:
 - Mean amplitude
 - Peak amplitude
 - Crest factor

The crest factor is defined as the peak power to mean power ratio or, logarithmically, as the peak level minus the average level of the signal.

Complementary Cumulative Distribution Function (CCDF)

The Complementary Cumulative Distribution Function (CCDF) shows the probability that the mean signal power amplitude will be exceeded in percent. The level above the mean power is plotted along the x-axis of the graph. The origin of the axis corresponds to the mean power level. The probability that a level will be exceeded is plotted along the y-axis.

Statistical Measurements (APD, CCDF)





A red line indicates the ideal Gaussian distribution for the measured amplitude range.

The displayed amplitude range is indicated as "Mean Pwr + <x dB>"

In addition to the histogram, a result table is displayed containing the following information:

- Number of samples used for calculation
- For each displayed trace:

Mean	Mean power
Peak	Peak power
Crest	Crest factor (peak power – mean power)
10 %	Level values over 10 % above mean power
1 %	Level values over 1 % above mean power
0,1 %	Level values over 0,1 % above mean power
0,01 %	Level values over 0,01 % above mean power

Percent marker

In addition to the results for specific percentages in the table, a percent marker can be activated for a freely selectable percentage. This marker indicates how many level values are over <x> % above the mean power.

Statistical Measurements (APD, CCDF)



Percent marker

As all markers, the percent marker can be moved simply by selecting it with a finger or mouse cursor and dragging it to the desired position.

Diagram Scaling

The scaling for both the x-axis and y-axis of the statistics diagram can be configured. In particular, you can restrict the range of amplitudes to be evaluated and the probabilities to be displayed.

4.7.4 APD and CCDF Basics - Gated Triggering

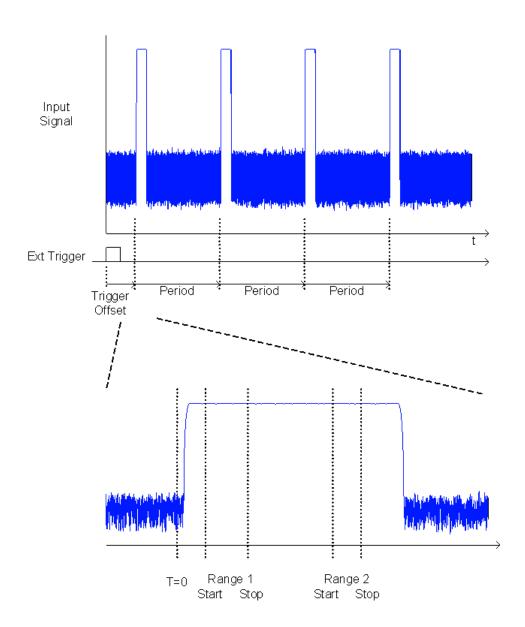
Statistic measurements on pulsed signals can be performed using a gated trigger. An external frame trigger is required as a time (frame) reference.

The gate ranges define the part of the measured data taken into account for the statistics calculation. These ranges are defined relative to a reference point T=0. The gate interval is repeated for each period until the end of the capture buffer.

The reference point T=0 is defined by the external trigger event and the instrument's trigger offset.

For each trace you can define up to 3 separate ranges of a single period to be traced.

Statistical Measurements (APD, CCDF)



4.7.5 APD and CCDF Configuration

Configuration consists of the following settings:

•	Basic Settings	122
	Gate Range Definition for APD and CCDF	
	Scaling for Statistics Diagrams	126

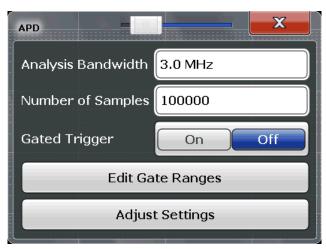
4.7.5.1 Basic Settings

APD measurements are selected via the "APD" button in the "Select Measurement" dialog box. CCDF measurements are selected via the "CCDF" button in the "Select Measurement" dialog box. The measurements are started immediately with the default settings. They can be configured via the MEAS CONFIG key or in the "APD/CCDF" dialog

Statistical Measurements (APD, CCDF)

boxes, which are displayed as a tab in the "Analysis" dialog box or when you select the "APD Config" softkey from the "APD" menu or the "CCDF Config" softkey from the "CCDF" menu.

The remote commands required to perform these tasks are described in chapter 10.3.8, "Analyzing Statistics (APD, CCDF)", on page 523.



Both dialog boxes are identical except for the "Percent Marker" setting, which is only available for CCDF measurements.

Percent Marker (CCDF only)	123
Analysis Bandwidth	123
Number of Samples	
Gated Trigger	124
Edit Gate Ranges	
Adjust Settings	

Percent Marker (CCDF only)

Defines a probability value. Thus, the power which is exceeded with a given probability can be determined very easily. If marker 1 is deactivated, it is switched on automatically.

SCPI command:

CALCulate<n>:MARKer<m>:Y:PERCent on page 524

Analysis Bandwidth

Defines the analysis bandwidth.

For correct measurement of the signal statistics, the analysis bandwidth has to be wider than the signal bandwidth in order to measure the peaks of the signal amplitude correctly. To avoid influencing the peak amplitudes, the video bandwidth is automatically set to 10 MHz. The sample detector is used for detecting the video voltage.

The calculated measurement time is displayed for reference only.

SCPI command:

[SENSe:]BANDwidth|BWIDth[:RESolution] on page 568

Number of Samples

Defines the number of power measurements that are taken into account for the statistics.

Statistical Measurements (APD, CCDF)

For statistics measurements with the R&S FSW, the number of samples to be measured is defined instead of the sweep time. Since only statistically independent samples contribute to statistics, the sweep or measurement time is calculated automatically and displayed in the channel bar ("Meas Time"). The samples are statistically independent if the time difference is at least 1/RBW. The measurement time is, therefore, expressed as follows:

Meas Time = $N_{Samples}/RBW$

SCPI command:

CALCulate<n>:STATistics:NSAMples on page 524

Gated Trigger

Activates and deactivates gating for statistics functions for the ACP and the CCDF measurements. If activated, the trigger source is changed to "External Trigger 1". The gate ranges are defined using the Edit Gate Ranges function.

SCPI command:

[SENSe:]SWEep:EGATe:TRACe<k>[:STATe<range>] on page 526

Edit Gate Ranges

Opens a dialog box to configure up to 3 gate ranges for each trace. For details see chapter 4.7.5.2, "Gate Range Definition for APD and CCDF", on page 124.

Adjust Settings

Adjusts the level settings according to the measured difference between peak and minimum power for APD measurement or peak and mean power for CCDF measurement in order to obtain maximum power resolution. Adjusts the reference level to the current input signal.

SCPI command:

CALCulate<n>:STATistics:SCALe:AUTO ONCE on page 527

4.7.5.2 Gate Range Definition for APD and CCDF

Gate ranges for gated triggering in statistical measurements can be configured in the "Gate Ranges" dialog box, which is displayed when you select the "Edit Gate Ranges" button in the "APD" or "CCDF" configuration dialog boxes.

For background information on defining gate ranges see chapter 4.7.4, "APD and CCDF Basics - Gated Triggering", on page 121.

The remote commands required to perform these tasks are described in chapter 10.3.8.3, "Using Gate Ranges for Statistical Measurements", on page 524.

Statistical Measurements (APD, CCDF)



Up to three ranges can be defined for each of the six available traces.

Comment	125
Period.	
Range <x> Use</x>	125
Range <x> Start/Stop.</x>	

Comment

An optional comment can be defined for the gate range settings of each trace.

SCPI command:

[SENSe:]SWEep:EGATe:TRACe<k>:COMMent on page 525

Period

Length of the period to be traced. The period is the same for all traces. If you change the period for one trace, it is automatically changed for all traces.

Make sure the defined period is not longer than the total measurement time of the current measurement. Keep in mind that the measurement time depends on the bandwidth and the number of samples (see "Number of Samples" on page 123). The current measurement time is indicated as "Meas Time" in the channel bar.

SCPI command:

[SENSe:] SWEep:EGATe:TRACe:PERiod on page 525

Range <x> Use

Activates tracing of the defined range during a gated measurement.

SCPI command:

[SENSe:]SWEep:EGATe:TRACe<k>[:STATe<range>] on page 526

Range <x> Start/Stop

Defines the start and stop points of the range within the tracing period. Make sure the value for the stopping time is smaller than the length of the period.

Statistical Measurements (APD, CCDF)

Note: You can define the time values with a greater numerical resolution than is displayed; the values are only rounded for display.

SCPI command:

```
[SENSe:]SWEep:EGATe:TRACe<k>:STARt<range> on page 525
[SENSe:]SWEep:EGATe:TRACe<k>:STOP<range> on page 526
```

4.7.5.3 Scaling for Statistics Diagrams

The diagram scaling for statistical measurements can be configured in the "Scaling" dialog box, which is displayed when you select the AMPT key and then the "Scale Config" softkey.

The remote commands required to perform these tasks are described in chapter 10.3.8.4, "Scaling the Diagram", on page 526.





In statistical diagrams, the x-axis displays the signal level values (= y-axis in standard display), while the y-axis displays the probability of the values.

X-Axis	127
L Range	127
L Ref Level	127
L Shifting the Display (Offset)	127
Y-Axis	127
L Y-Unit	
L Y-Max / Y-Min	127
Default Settings	127
Adjust Settings	128

Statistical Measurements (APD, CCDF)

X-Axis

Defines the scaling settings for signal level values.

Range \leftarrow X-Axis

Defines the level range in dB to be evaluated by the statistics measurement.

SCPI command:

CALCulate<n>:STATistics:SCALe:X:RANGe on page 528

Ref Level ← X-Axis

Defines the reference level for the signal levels in the currently active unit (dBm, dB μ V, etc).

For the APD function this value corresponds to the right diagram border. For the CCDF function there is no direct representation of this value on the diagram as the x-axis is scaled relatively to the measured mean power.

SCPI command:

CALCulate<n>:STATistics:SCALe:X:RLEVel on page 528

Shifting the Display (Offset) ← X-Axis

Defines an arithmetic level offset. This offset is added to the measured level irrespective of the selected unit. The scaling of the x-axis is changed accordingly. The setting range is ±200 dB in 0.1 dB steps.

SCPI command:

```
DISPlay[:WINDow<n>]:TRACe:Y[:SCALe]:RLEVel:OFFSet on page 576
```

Y-Axis

Defines the scaling settings for the probability distribution.

Y-Unit ← Y-Axis

Defines the scaling type of the y-axis as either percentage or absolute. The default value is absolute scaling.

SCPI command:

CALCulate<n>:STATistics:SCALe:Y:UNIT on page 528

Y-Max / Y-Min ← Y-Axis

Defines the upper (max) and lower (min) limit of the displayed probability range. Values on the y-axis are normalized which means that the maximum value is 1.0. The minimum value must be in the range:

1E-9 < Y-Min < 0.1

The distance between Y-max and Y-min must be at least one decade.

SCPI command:

```
CALCulate<n>:STATistics:SCALe:Y:UPPer on page 529
CALCulate<n>:STATistics:SCALe:Y:LOWer on page 528
```

Default Settings

Resets the x- and y-axis scalings to their preset values.

Statistical Measurements (APD, CCDF)

x-axis ref level:	-10 dBm
x-axis range APD:	100 dB
x-axis range CCDF:	20 dB
y-axis upper limit:	1.0
y-axis lower limit:	1E-6

SCPI command:

CALCulate<n>:STATistics:PRESet on page 527

Adjust Settings

Adjusts the level settings according to the measured difference between peak and minimum power for APD measurement or peak and mean power for CCDF measurement in order to obtain maximum power resolution. Adjusts the reference level to the current input signal.

SCPI command:

CALCulate<n>:STATistics:SCALe:AUTO ONCE on page 527

4.7.6 How to Perform an APD or CCDF Measurement

To start a basic statistic measurement

- 1. Press the MEAS key, then select the "APD" or "CCDF" measurement.
- 2. Start a sweep.

As soon as the defined number of samples have been measured, the statistical evaluation is displayed.

To perform a statistic measurement using gate ranges

For pulsed signals, the transmission intervals should not be included in the statistical evaluation. Thus, you must define gate ranges to be included in the measurement.

 Press the MEAS CONFIG key, then select the "APD Config" or "CCDF Config" softkey.

The "APD" or "CCDF" dialog box is displayed.

- Select the "Edit Gate Ranges" button.
- 3. Define the time period for which the input signal is to be analyzed, for example the duration of 3 signal pulses.
- 4. For each active trace, define up to three ranges within the time period to be measured. In the example covering 3 pulses, you could define one range for each pulse.
 - a) Assuming the external trigger determines T=0 as the start of the first pulse, define the start time of range 1 at 0 s.
 - b) Define the stop time of range 1 at the duration of the first pulse.

Statistical Measurements (APD, CCDF)

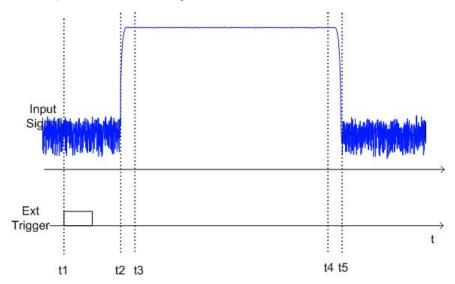
- c) Activate range 1 by setting "Range 1 Use" to On.
- d) Define the start time of range 2 as (duration of pulse 1 + duration of interval)
- e) Define the stop time of range 2 as (start time of range 2 + duration of pulse 2)
- f) Activate range 2 by setting "Range 2 Use" to On.
- g) Define the third range in the same way.
- 5. Start a sweep.

As soon as the defined number of samples have been measured, the statistical evaluation is displayed. Only the signal levels within the pulse periods are considered.

4.7.7 Examples

4.7.7.1 Configuration Example: Gated Statistics

A statistics evaluation has to be done over the useful part of the signal between t3 and t4. The period of the GSM signal is 4.61536 ms.



- t1: External positive trigger slope
- t2: Begin of burst (after 25 μs)
- t3: Begin of useful part, to be used for statistics (after 40 µs)
- t4: End of useful part, to be used for statistics (after 578 µs)
- t5: End of burst (after 602 µs)

The instrument has to be configured as follows:

Statistical Measurements (APD, CCDF)

Trigger Offset	t2 – t1 = 25 μs	now the gate ranges are relative to t2
Range1 Start	t3 – t2 = 15 μs	start of range 1 relative to t2
Range1 End	t4 – t2 = 553 μs	end of range 1 relative to t2

4.7.7.2 Measurement Example – Measuring the APD and CCDF of White Noise Generated by the R&S FSW



Setting the RBW

When the amplitude distribution is measured, the analysis bandwidth must be set so that the complete spectrum of the signal to be measured falls within the bandwidth. This is the only way of ensuring that all the amplitudes will pass through the IF filter without being distorted. If the selected bandwidth is too small for a digitally modulated signal, the amplitude distribution at the output of the IF filter becomes a Gaussian distribution according to the central limit theorem and thus corresponds to a white noise signal. The true amplitude distribution of the signal therefore cannot be determined.

- Preset the R&S FSW.
- Set the reference level to -60 dBm.
 The R&S FSW's intrinsic noise is displayed at the top of the screen.
- 3. Select the "APD" measurement function from the "Select Measurement" dialog box. The R&S FSW sets the frequency span to 0 Hz and measures the amplitude probability distribution (APD). The number of uncorrelated level measurements used for the measurement is 100000. The mean power and the peak power are displayed in dBm. The crest factor (peak power mean power) is output as well.

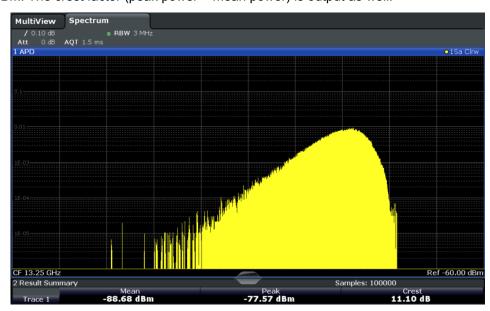


Fig. 4-10: Amplitude probability distribution of white noise

Time Domain Power Measurement

 Now select the "CCDF" measurement function from the "Select Measurement" dialog box.

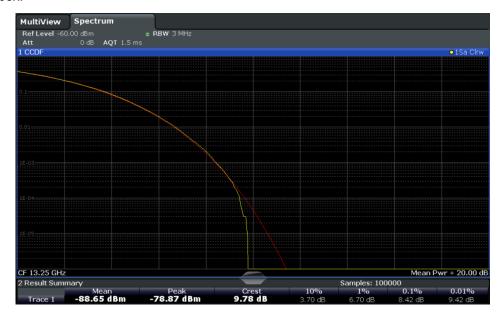


Fig. 4-11: CCDF of white noise

The CCDF trace indicates the probability that a level will exceed the mean power. The level above the mean power is plotted along the x-axis of the graph. The origin of the axis corresponds to the mean power level. The probability that a level will be exceeded is plotted along the y-axis.

4.7.8 Optimizing and Troubleshooting the Measurement

If the results do not meet your expectations, try the following methods to optimize the measurement:

- Make sure the defined bandwidth is wide enough for the signal bandwidth of the device under test to be fully analyzed (see "Analysis Bandwidth" on page 123).
- If the complete signal is be measured, increase the number of samples so that the resulting measurement time is longer than one period of a bursted signal.
- If only parts of the signal are to be examined, define a trigger source and a gate.

4.8 Time Domain Power Measurement

The R&S FSW can determine the power of a signal in the time domain using the Time Domain Power measurement function.

•	About the Measurement	132
•	Time Domain Power Results	132
•	Time Domain Power Basics - Range Definition Using Limit Lines	133

Time Domain Power Measurement

•	Time Domain Power Configuration	.133
•	How to Measure Powers in the Time Domain	134
•	Measurement Example	135

4.8.1 About the Measurement

Using the Time Domain Power measurement function, the R&S FSW determines the power of the signal in zero span by summing up the power at the individual measurement points and dividing the result by the number of measurement points. Thus it is possible to measure the power of TDMA signals during transmission, for example, or during the muting phase. Both the mean power and the RMS power can be measured.

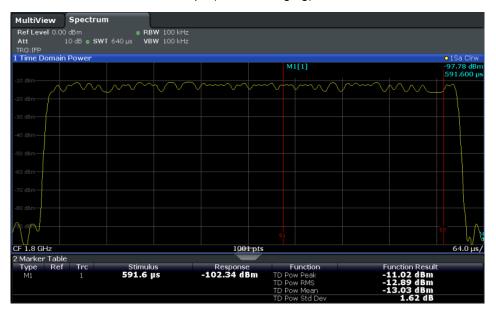
For this measurement, the sample detector is activated.

4.8.2 Time Domain Power Results

Several different power results can be determined simultaneously:

Mode	Description
Peak	Peak value from the points of the displayed trace or a segment thereof.
RMS	RMS value from the points of the displayed trace or a segment thereof.
Mean	Mean value from the points of the displayed trace or a segment thereof. The linear mean value of the equivalent voltages is calculated. For example to measure the mean power during a GSM burst
Std Dev	The standard deviation of the measurement points from the mean value.

The result is displayed in the marker results, indicated by "Power" and the selected power mode, e.g. "RMS". The measured values are updated after each sweep or averaged over a user-defined number of sweeps (trace averaging).



Time Domain Power Measurement

The results can also be queried using the remote commands described in chapter 10.3.9, "Measuring the Time Domain Power", on page 532.

4.8.3 Time Domain Power Basics - Range Definition Using Limit Lines

The range of the measured signal to be evaluated for the power measurement can be restricted using limit lines. The left and right limit lines (S1, S2) define the evaluation range and are indicated by vertical red lines in the diagram. If activated, the power results are only calculated from the levels within the limit lines.

For example, if both the on and off phase of a burst signal are displayed, the measurement range can be limited to the transmission or to the muting phase. The ratio between signal and noise power of a TDMA signal for instance can be measured by using a measurement as a reference value and then varying the measurement range.



In order to get stable measurement results for a limited evaluation range, usually a trigger is required.

4.8.4 Time Domain Power Configuration

Time Domain Power measurements are selected via the "Time Domain Power" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "Time Domain Power" dialog box, which is displayed as a tab in the "Analysis" dialog box or when you select the "Time Dom Power Config" softkey from the "Time Dom Pwr" menu.

The remote commands required to perform these tasks are described in chapter 10.3.9, "Measuring the Time Domain Power", on page 532.

Results	133
Limit State	134
Left Limit / Right Limit	134

Results

Activates the power results to be evaluated from the displayed trace or a limited area of the trace.

"Peak"	Peak power over several measurements (uses trace averaging, Max

Hold)

"RMS" RMS value from the points of the displayed trace or a segment thereof.

"Mean" Mean value from the points of the displayed trace or a segment thereof.

Mean value from the points of the displayed trace or a segment thereof.

The linear mean value of the equivalent voltages is calculated.

Time Domain Power Measurement

"Std Dev"

The standard deviation of the measurement points from the mean value.

The measurement of the mean power is automatically switched on at the same time.

SCPI command:

```
CALCulate<n>:MARKer<m>:FUNCtion:SUMMary:PPEak[:STATe] on page 536
CALCulate<n>:MARKer<m>:FUNCtion:SUMMary:PPEak:RESult? on page 535
CALCulate<n>:MARKer<m>:FUNCtion:SUMMary:RMS[:STATe] on page 537
CALCulate<n>:MARKer<m>:FUNCtion:SUMMary:RMS:RESult? on page 536
CALCulate<n>:MARKer<m>:FUNCtion:SUMMary:MEAN[:STATe] on page 534
CALCulate<n>:MARKer<m>:FUNCtion:SUMMary:MEAN:RESult? on page 534
```

Limit State

Switches the limitation of the evaluation range on or off. Default setting is off.

If deactivated, the entire sweep time is evaluated. If switched on, the evaluation range is defined by the left and right limit. If only one limit is set, it corresponds to the left limit and the right limit is defined by the stop frequency. If the second limit is also set, it defines the right limit.

SCPI command:

```
CALCulate: MARKer: X: SLIMits [:STATe] on page 634
```

Left Limit / Right Limit

Defines a power level limit for line S1 (left) or S2 (right).

SCPI command:

```
CALCulate:MARKer:X:SLIMits:LEFT on page 635
CALCulate:MARKer:X:SLIMits:RIGHT on page 635
```

4.8.5 How to Measure Powers in the Time Domain

To measure the power in the time domain

- Select the "Time Domain Power" measurement function from the "Select Measurement" dialog box.
- 2. Select the type of power measurement results to be determined by selecting the corresponding softkeys.
- 3. To restrict the power evaluation range, define limits:
 - Select the "Time Dom Power Config" softkey to display the "Time Domain Power" configuration dialog box.
 - b) Switch on the limits by setting the "Limit State" to "On". The limit lines S1 and S2 are displayed.
 - c) Define the left limit (limit line S1), the right limit (S2), or both.

Time Domain Power Measurement

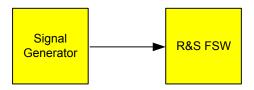
4. Start a sweep.

The measured powers are displayed in the marker results.

4.8.6 Measurement Example

This measurement example demonstrates the time domain power calculation for a GSM burst.

Test setup:



Signal generator settings (e.g. R&S FSW SMU):

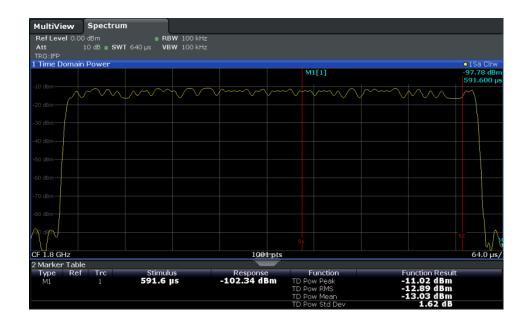
Frequency:	1.8 GHz
Level:	-10 dBm
Modulation:	GSM/EDGE

Procedure:

- 1. Preset the R&S FSW.
- 2. Set the center frequency to 1.8 GHz.
- 3. Set the RBW to 100 kHz.
- 4. Set the sweep time to 640 μ s.
- 5. Set the trigger source to "IF Power".
- 6. Define a trigger offset of -50 μ s.
- 7. Select the "Time Domain Power" measurement function from the "Select Measurement" dialog box.
- 8. In the Time Domain Power configuration dialog box, set all four results to "ON".
- 9. Set the "Limit State" to "ON".
- 10. Define the left limit at 326 μ s and the right limit at 538 μ s. This range corresponds to the useful part of the GSM burst.

The mean power of the useful part of the GSM burst is calculated to be -13 dBm.

Harmonic Distortion Measurement



4.9 Harmonic Distortion Measurement

The harmonics and their distortion can be measured using the "Harmonic Distortion" function.

•	About the Measurement	136
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•	Harmonic Distortion Results	139
•	Harmonic Distortion Configuration	140
		141

4.9.1 About the Measurement

With this measurement it is possible to measure the harmonics easily, for example from a VCO. In addition, the total harmonic distortion (THD) is calculated.

For measurements in the frequency domain, the Harmonic Distortion measurement starts with an automatic search for the first harmonic (= peak) within the set frequency range. The center frequency is set to this frequency and the reference level is adjusted accordingly.

For measurements in zero span, the center frequency remains unchanged.

The Harmonic Distortion measurement then performs zero span sweeps at the center frequency and at each harmonic, i.e. at frequencies that are a multiple of the center frequency.

As a result, the zero span sweeps on all harmonics are shown, as well as the RMS values and the total harmonic distortion (THD).

Harmonic Distortion Measurement

4.9.2 Harmonic Distortion Basics

Measuring the harmonics of a signal is a frequent problem which can be solved best using a signal analyzer. In general, every signal contains harmonics. Harmonics are generated by nonlinear characteristics, which add frequencies to a pure sinewave. They can often be reduced by low pass filters. Since the signal analyzer itself has a nonlinear characteristic, for example in its first mixer, measures must be taken to ensure that harmonics produced in the signal analyzer do not cause spurious results. If necessary, the fundamental wave must be attenuated selectively with respect to the other harmonics with a high pass filter. Harmonics are particularly critical regarding high-power transmitters such as transceivers because large harmonics can interfere with other radio services.

Harmonic distortion can be determined as the level of the individual components, or as the root mean square of all components together, the total harmonic distortion (THD). The THD is set in relation to the power of the fundamental frequency (= center frequency).

Obtainable dynamic range

When harmonics are being measured, the obtainable dynamic range depends on the second harmonic intercept of the signal analyzer. The second harmonic intercept is the virtual input level at the RF input mixer at which the level of the 2nd harmonic becomes equal to the level of the fundamental wave. In practice, however, applying a level of this magnitude would damage the mixer. Nevertheless the available dynamic range for measuring the harmonic distance of a DUT can be calculated relatively easily using the second harmonic intercept.

As shown in figure 4-12, the level of the 2nd harmonic drops by 20 dB if the level of the fundamental wave is reduced by 10 dB.

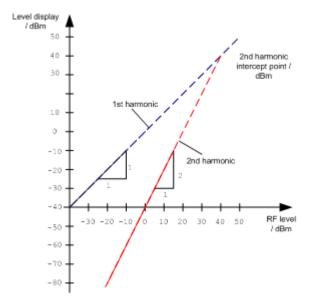


Fig. 4-12: Extrapolation of the 1st and 2nd harmonics to the 2nd harmonic intercept at 40 dBm

The following formula for the obtainable harmonic distortion d_2 in dB is derived from the straight-line equations and the given intercept point:

$$d_2 = S.H.I - P_1(1)$$

Harmonic Distortion Measurement

where:

d_2	=	harmonic distortion
S.H.I.	=	second harmonic intercept
Pı	=	mixer level/dBm



The mixer level is the RF level applied to the RF input minus the set RF attenuation.

The formula for the internally generated level P₁ at the 2nd harmonic in dBm is:

$$P_1 = 2 * P_1 - S.H.I.$$
 (2)

The lower measurement limit for the harmonic is the noise floor of the signal analyzer. The harmonic of the measured DUT should – if sufficiently averaged by means of a video filter – be at least 4 dB above the noise floor so that the measurement error due to the input noise is less than 1 dB.

Rules for measuring high harmonic ratios

The following rules for measuring high harmonic ratios can be derived:

- Select the smallest possible IF bandwidth for a minimal noise floor.
- Select an RF attenuation which is high enough to measure the harmonic ratio only.

The maximum harmonic distortion is obtained if the level of the harmonic equals the intrinsic noise level of the receiver. The level applied to the mixer, according to (2), is:

$$P_{I} = \frac{P_{noise} / dBm + IP2}{2}$$

At a resolution bandwidth of 10 Hz (noise level -143 dBm, S.H.I. = 40 dBm), the optimum mixer level is -51.5 dBm. According to (1) a maximum measurable harmonic distortion of 91.5 dB minus a minimum S/N ratio of 4 dB is obtained.



Detecting the origin of harmonics

If the harmonic emerges from noise sufficiently (approx. >15 dB), it is easy to check (by changing the RF attenuation) whether the harmonics originate from the DUT or are generated internally by the signal analyzer. If a harmonic originates from the DUT, its level remains constant if the RF attenuation is increased by 10 dB. Only the displayed noise is increased by 10 dB due to the additional attenuation. If the harmonic is exclusively generated by the signal analyzer, the level of the harmonic is reduced by 20 dB or is lost in noise. If both – the DUT and the signal analyzer – contribute to the harmonic, the reduction in the harmonic level is correspondingly smaller.

High-sensitivity harmonics measurements

If harmonics have very small levels, the resolution bandwidth required to measure them must be reduced considerably. The sweep time is, therefore, also increased considera-

Harmonic Distortion Measurement

bly. In this case, the measurement of individual harmonics is carried out with the R&S FSW set to a small span. Only the frequency range around the harmonics will then be measured with a small resolution bandwidth.

Required measurement time

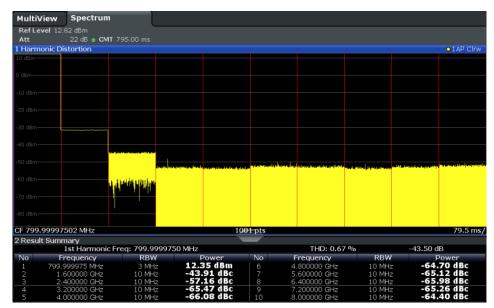
During the harmonics measurement, zero span sweeps are performed at the center frequency and at each harmonic. The duration of each sweep ("Harmonic Sweep Time", **SWT**) and the "Number of Harmonics" (n) are defined in the "Harmonic Distortion" configuration dialog box. Thus, the required measurement time for the harmonic distortion measurement (*Cumulated Measurement Time*, **CMT**) is:

CMT = n*SWT

The required measurement time is indicated as "CMT" in the channel bar.

4.9.3 Harmonic Distortion Results

As a result of the harmonics distortion measurement, the zero span sweeps of all detected harmonics are shown in the diagram, separated by red display lines. This provides a very good overview of the measurement.



In addition, a result table is displayed providing the following information:

- First harmonic frequency
- THD (total harmonic distortion), relative and absolute values
- For each detected harmonic:
 - Frequency
 - RBW
 - Power

Harmonic Distortion Measurement

Remote commands

The results can also be queried using remote commands.

The first harmonic frequency can be read out via the general center frequency command CALCulate<n>:MARKer<m>:FUNCtion:CENTer on page 563.

THD: CALCulate<n>:MARKer<m>:FUNCtion:HARMonics:DISTortion?
on page 541

List of harmonics: CALCulate<n>:MARKer<m>:FUNCtion:HARMonics:LIST?
on page 541

4.9.4 Harmonic Distortion Configuration

Harmonic Distortion measurements are selected via the "Harmonic Distortion" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "Harmonic Distortion" dialog box, which is displayed as a tab in the "Analysis" dialog box or when you select the "Harmonic Distortion Config" softkey from the "Harm Dist" menu.



The remote commands required to perform these tasks are described in chapter 10.3.10, "Measuring the Harmonic Distortion", on page 539.

No. of Harmonics	140
Harmonic Sweep Time	141
Harmonic RBW Auto	
Adjust Settings	141

No. of Harmonics

Defines the number of harmonics to be measured. The range is from 1 to 26. Default is 10.

SCPI command:

CALCulate<n>:MARKer<m>:FUNCtion:HARMonics:NHARmonics on page 540

Harmonic Distortion Measurement

Harmonic Sweep Time

Defines the sweep time for the zero span measurement on each harmonic frequency. This setting is identical to the normal sweep time for zero span, see also "Sweep Time" on page 201.

SCPI command:

[SENSe:]SWEep:TIME:AUTO on page 573

Harmonic RBW Auto

Enables/disables the automatic adjustment of the resolution bandwidth for Normal (3dB) (Gaussian) and 5-Pole filter types. The automatic adjustment is carried out according to:

"RBW_n = RBW₁ * n"

If RBW_n is not available, the next higher value is used.

SCPI command:

CALCulate<n>:MARKer<m>:FUNCtion:HARMonics:BANDwidth:AUTO on page 540

Adjust Settings

If harmonic measurement was performed in the frequency domain, a new peak search is started in the frequency range that was set before starting the harmonic measurement. The center frequency is set to this frequency and the reference level is adjusted accordingly.

If harmonic measurement was performed in the time domain, this function adjusts the reference level only.

SCPI command:

CALCulate<n>:MARKer<m>:FUNCtion:HARMonics:PRESet on page 541

4.9.5 How to Determine the Harmonic Distortion



In chapter 6.4.4, "Measurement Example: Measuring Harmonics Using Marker Functions", on page 302, measuring harmonics was described using marker functions. This task can be performed much simpler using the Harmonic Distortion measurement, as described in the following procedure.

- 1. Select the "Harmonic Distortion" measurement function from the "Select Measurement" dialog box.
- 2. Define the number of harmonics to be determined using the "No. of Harmonics" softkey.
- 3. Perform a sweep.

The trace for the determined harmonics are displayed in the diagram, separated by red display lines. The measured power for each harmonic in relation to the fundamental is indicated in the result table.

Third Order Intercept (TOI) Measurement

 If the signal changes significantly during or after the harmonics measurement, use the "Adjust Settings" function to adjust the settings automatically and restart the measurement.

4.10 Third Order Intercept (TOI) Measurement

The third order intercept point of the R&S FSW can be determined if a two-tone signal with equal carrier levels is applied to the input.

•	About the TOI Measurement	142
	TOI Basics	
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	J. T.	

4.10.1 About the TOI Measurement

If several signals are applied to a transmission two-port device with nonlinear characteristic, intermodulation products appear at its output at the sums and differences of the signals. The nonlinear characteristic produces harmonics of the useful signals which intermodulate at the characteristic. The intermodulation products of lower order have a special effect since their level is largest and they are near the useful signals. The intermodulation product of third order causes the highest interference. It is the intermodulation product generated from one of the useful signals and the 2nd harmonic of the second useful signal in case of two-tone modulation.

In order to measure the third order intercept point (TOI), a two-tone signal with equal carrier levels is expected at the R&S FSW input. Marker 1 and marker 2 (both normal markers) are set to the maximum of the two signals. Marker 3 and marker 4 are placed on the intermodulation products.

The R&S FSW calculates the third order intercept point from the level difference between the first 2 markers and the markers 3 and 4 and displays it in the marker field.

4.10.2 TOI Basics

If several signals are applied to a transmission two-port device with nonlinear characteristic, intermodulation products appear at its output at the sums and differences of the signals. The nonlinear characteristic produces harmonics of the useful signals which intermodulate at the characteristic.

The frequencies of the intermodulation products are above and below the useful signals. The figure 4-13 shows intermodulation products P_{S1} and P_{S2} generated by the two useful signals P_{U1} and P_{U2} .

Third Order Intercept (TOI) Measurement

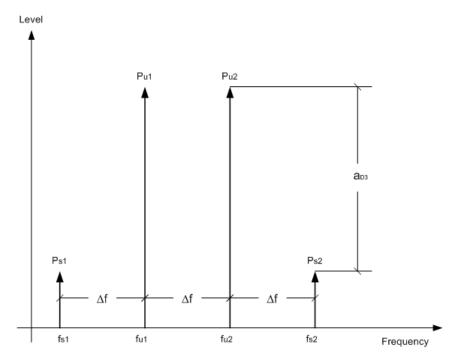


Fig. 4-13: Intermodulation products Ps1 and Ps2

The intermodulation product at f_{i2} is generated by mixing the 2nd harmonic of useful signal P_{U2} and signal P_{U1} .

Tthe intermodulation product at f_{i1} is generated by mixing the 2nd harmonic of useful signal P_{U1} and signal P_{U2} .

$$f_{i1} = 2 \times f_{u1} - f_{u2} (1)$$

$$f_{i2} = 2 \times f_{u2} - f_{u1} (2)$$

Dependency on level of useful signals

The level of the intermodulation products depends on the level of the useful signals. If the two useful signals are increased by 1 dB, the level of the intermodulation products increases by 3 dB, which means that the spacing a_{D3} between intermodulation signals and useful signals is reduced by 2 dB. This is illustrated in figure 4-14.

Third Order Intercept (TOI) Measurement

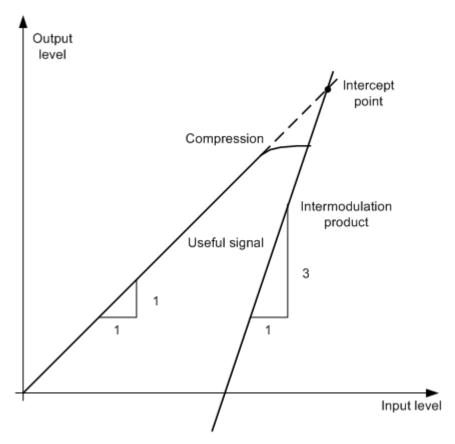


Fig. 4-14: Dependency of intermodulation products on level of useful signals

The useful signals at the two-port output increase proportionally with the input level as long as the two-port is in the linear range. A level change of 1 dB at the input causes a level change of 1 dB at the output. Beyond a certain input level, the two-port goes into compression and the output level stops increasing. The intermodulation products of the third order increase three times as quickly as the useful signals. The intercept point is the fictitious level where the two lines intersect. It cannot be measured directly since the useful level is previously limited by the maximum two-port output power.

Calculation method

However, the intercept point can be calculated from the known line slopes and the measured spacing a_{D3} at a given level according to the following formula:

$$IP3 = \frac{a_{D3}}{2} + P_N$$

The third order intercept point (TOI), for example, is calculated for an intermodulation of 60 dB and an input level P_U of -20 dBm according to the following formula:

$$IP3 = \frac{60}{2} + (-20dBm) = 10dBm$$

Third Order Intercept (TOI) Measurement

Intermodulation-free dynamic range

The "Intermodulation-free dynamic range", i.e. the level range in which no internal intermodulation products are generated if two-tone signals are measured, is determined by the third order intercept point, the phase noise and the thermal noise of the signal analyzer. At high signal levels, the range is determined by intermodulation products. At low signal levels, intermodulation products disappear below the noise floor, i.e. the noise floor and the phase noise of the signal analyzer determine the range. The noise floor and the phase noise depend on the resolution bandwidth that has been selected. At the smallest resolution bandwidth, the noise floor and phase noise are at a minimum and so the maximum range is obtained. However, a large increase in sweep time is required for small resolution bandwidths. It is therefore best to select the largest resolution bandwidth possible to obtain the range that is required. Since phase noise decreases as the carrier-offset increases, its influence decreases with increasing frequency offset from the useful signals.

The following diagrams illustrate the intermodulation-free dynamic range as a function of the selected bandwidth and of the level at the input mixer (= signal level – set RF attenuation) at different useful signal offsets.

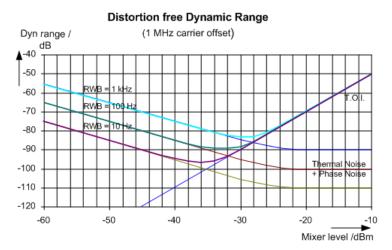


Fig. 4-15: Intermodulation-free range as a function of level at the input mixer and the set resolution bandwidth

(Useful signal offset = 1 MHz, DANL = -145 dBm/Hz, TOI = 15 dBm; typical values at 2 GHz)

The optimum mixer level, i.e. the level at which the intermodulation distance is at its maximum, depends on the bandwidth. At a resolution bandwidth of 10 Hz, it is approx. -35 dBm and at 1 kHz increases to approx. -30 dBm.

Phase noise has a considerable influence on the intermodulation-free range at carrier offsets between 10 and 100 kHz (see figure 4-16). At greater bandwidths, the influence of the phase noise is greater than it would be with small bandwidths. The optimum mixer level at the bandwidths under consideration becomes almost independent of bandwidth and is approx. -40 dBm.

Third Order Intercept (TOI) Measurement

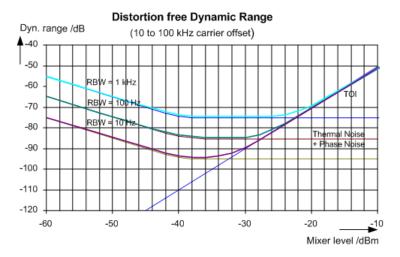


Fig. 4-16: Intermodulation-free dynamic range as a function of level at the input mixer and of the selected resolution bandwidth

(Useful signal offset = 10 to 100 kHz, DANL = -145 dBm/Hz, TOI = 15 dBm; typical values at 2 GHz).



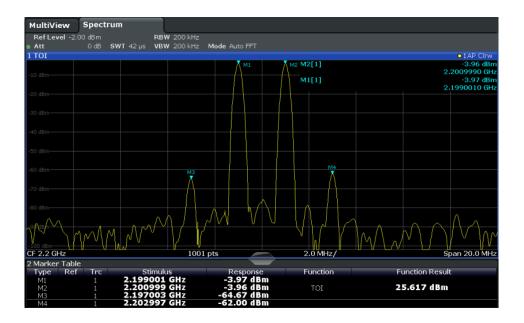
If the intermodulation products of a DUT with a very high dynamic range are to be measured and the resolution bandwidth to be used is therefore very small, it is best to measure the levels of the useful signals and those of the intermodulation products separately using a small span. The measurement time will be reduced, in particular if the offset of the useful signals is large. To find signals reliably when frequency span is small, it is best to synchronize the signal sources and the R&S FSW.

4.10.3 TOI Results

As a result of the TOI measurement, the following values are displayed in the marker area of the diagram:

Label	Description
TOI	Third-order intercept point
M1	Maximum of first useful signal
M2	Maximum of second useful signal
M3	First intermodulation product
M4	Second intermodulation product

Third Order Intercept (TOI) Measurement

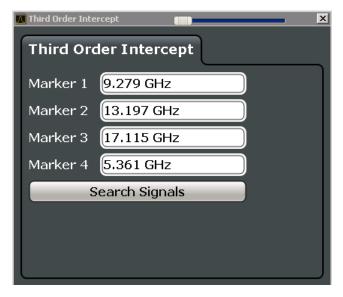


Remote command

The TOI can also be queried using the remote command CALCulate<n>: MARKer<m>: FUNCtion:TOI:RESult? on page 544.

4.10.4 TOI Configuration

Third Order Intercept (TOI) measurements are selected via the "Third Order Intercept" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "Third Order Intercept" dialog box, which is displayed as a tab in the "Analysis" dialog box, or when you select the "TOI Config" softkey from the "TOI" menu.



Third Order Intercept (TOI) Measurement

The remote commands required to perform these tasks are described in chapter 10.3.11, "Measuring the Third Order Intercept Point", on page 542.

Marker	1/2/3/4	148
Search	Signals	148

Marker 1/2/3/4

Indicates the detected characteristic values as determined by the TOI measurement (see chapter 4.10.3, "TOI Results", on page 146).

The marker positions can be edited; the TOI is then recalculated according to the new marker values.

To reset all marker positions automatically, use the Search Signals function.

SCPI command:

```
CALCulate<n>:MARKer<m>:X on page 632
CALCulate<n>:DELTamarker<m>:X on page 630
CALCulate<n>:DELTamarker<m>:X:RELative? on page 642
```

Search Signals

Performs a new search on the input signals and recalculates the TOI according to the measured values.

SCPI command:

CALCulate: MARKer: FUNCtion: TOI: SEARchsignal ONCE on page 543

4.10.5 How to Determine the Third Order Intercept



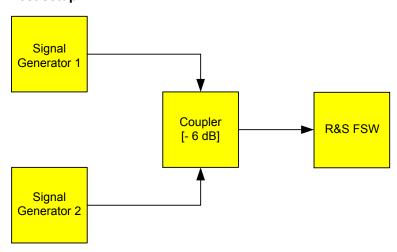
The precise TOI for the R&S FSW in relation to the input signals is provided in the data sheet.

- 1. Apply a two-tone signal with equal carrier levels to the R&S FSW input.
- 2. On the R&S FSW, press the MEAS key.
- 3. Select the "Third Order Intercept" measurement function from the "Select Measurement" dialog box.
 - The calculated TOI is indicated in the marker information. The markers required for calculation are displayed in the marker table.
- 4. If the signal changes significantly during or after the TOI measurement, use the "Search Signals" function to start a new signal search automatically and restart the calculation of the TOI.

Third Order Intercept (TOI) Measurement

4.10.6 Measurement Example – Measuring the R&S FSW's Intrinsic Intermodulation

Test setup:



Signal generator settings (e.g. R&S FSW SMU):

Device	Level	Frequency
Signal generator 1	-4 dBm	799.6 MHz
Signal generator 2	-4 dBm	800.4 MHz

Setting up the measurement

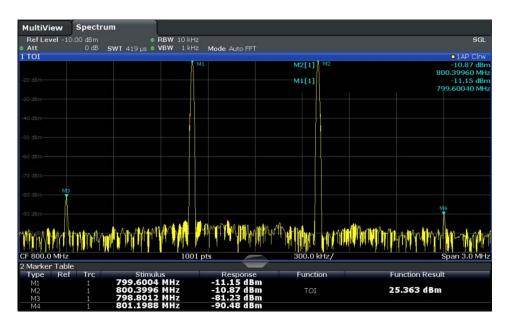
- 1. Preset the R&S FSW.
- 2. Set the center frequency to 800 MHz and the frequency span to 3 MHz.
- 3. Set the reference level to -10 dBm and RF attenuation to 0 dB.
- Set the resolution bandwidth to 10 kHz.
 The noise is reduced, the trace is smoothed further and the intermodulation products can be seen clearly.
- 5. Set the VBW to "1 kHz".

Measuring intermodulation using the Third Order Intercept (TOI) measurement function

1. Press the MEAS key and select the "Third Order Intercept" measurement function from the "Select Measurement" dialog box.

The R&S FSW activates four markers to measure the intermodulation distance. Two markers are positioned on the useful signals and two on the intermodulation products. The TOI is calculated from the level difference between the useful signals and the intermodulation products. It is then displayed on the screen:

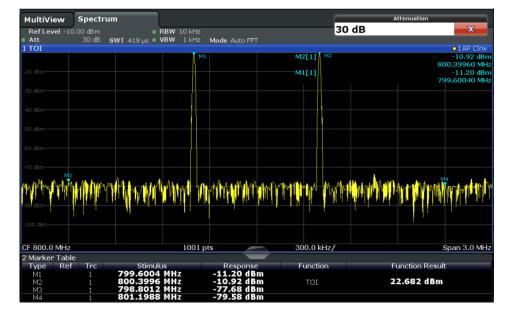
Third Order Intercept (TOI) Measurement



The third order intercept (TOI) is displayed in the marker information.

2. The level of a signal analyzer's intrinsic intermodulation products depends on the RF level of the useful signals at the input mixer. When the RF attenuation is added, the mixer level is reduced and the intermodulation distance is increased. With an additional RF attenuation of 10 dB, the levels of the intermodulation products are reduced by 20 dB. The noise level is, however, increased by 10 dB. Increase the RF attenuation to 20 dB to reduce intermodulation products.

The R&S FSW's intrinsic intermodulation products disappear below the noise floor.



AM Modulation Depth Measurement

4.11 AM Modulation Depth Measurement

Using the R&S FSW you can measure the AM modulation depth of a modulated signal.

•	About the Measurement	.151
•	AM Modulation Depth Results	.151
	AM Modulation Depth Configuration	
	Optimizing and Troubleshooting the Measurement	
	How to Determine the AM Modulation Depth	

4.11.1 About the Measurement

The AM modulation depth, also known as a modulation index, indicates how much the modulated signal varies around the carrier amplitude. It is defined as:

M_{Depth} = peak signal amplitude / unmodulated carrier amplitude

So for M_{Depth} = 0.5, for example, the carrier amplitude varies by 50% above and below its unmodulated level, and for M_{Depth} = 1.0 it varies by 100%.

When this measurement is activated, marker 1 is set to the peak level, which is considered to be the carrier level. Delta markers 2 and 3 are automatically set symmetrically to the carrier on the adjacent peak values of the trace. The markers can be adjusted manually, if necessary.

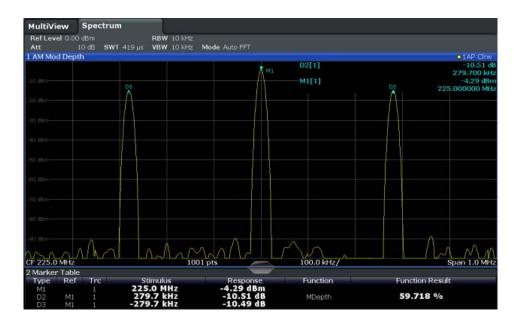
The R&S FSW calculates the power at the marker positions from the measured levels. The AM modulation depth is calculated as the ratio between the power values at the reference marker and at the delta markers. If the powers of the two AM side bands are unequal, the mean value of the two power values is used for AM modulation depth calculation.

4.11.2 AM Modulation Depth Results

As a result of the AM Modulation Depth measurement, the following values are displayed in the marker area of the diagram:

Label	Description
MDepth	AM modulation depth in percent
M1	Maximum of the signal (= carrier level)
D2	Offset of next peak to the right of the carrier
D3	Offset of the next peak to the left of the carrier

AM Modulation Depth Measurement



SCPI command:

The AM modulation depth can also be queried using the remote command CALCulate<n>:MARKer<m>:FUNCtion:MDEPth:RESult? on page 545.

4.11.3 AM Modulation Depth Configuration

AM Modulation Depth measurements are selected via the "AM Modulation Depth" button in the "Select Measurement" dialog box. The measurement is started immediately with the default settings. It can be configured via the MEAS CONFIG key or in the "AM Modulation Depth" dialog box, which is displayed as a tab in the "Analysis" dialog box or when you select the "AM Mod Depth Config" softkey from the "AM Mod Depth" menu.



The remote commands required to perform these tasks are described in chapter 10.3.12, "Measuring the AM Modulation Depth", on page 544.

Marker 1/2/315	3
Search Signals	3

AM Modulation Depth Measurement

Marker 1/2/3

Indicates the detected characteristic values as determined by the AM Modulation Depth measurement:

Marker	Description
M1	Maximum of the signal (= carrier level)
D2	Offset of next peak to the right of the carrier
D3	Offset of the next peak to the left of the carrier

The marker positions can be edited; the modulation depth is then recalculated according to the new marker values.

To reset all marker positions automatically, use the Search Signals function.

Note: Moving the marker positions manually. When the position of delta marker 2 is changed, delta marker 3 is moved symmetrically with respect to the reference marker 1. Delta marker 3, on the other hand, can be moved for fine adjustment independently of marker 2.

Marker 1 can also be moved manually for re-adjustment without affecting the position of the delta markers.

SCPI command:

```
CALCulate<n>:MARKer<m>:X on page 632
CALCulate<n>:DELTamarker<m>:X on page 630
CALCulate<n>:DELTamarker<m>:X:RELative? on page 642
```

Search Signals

Performs a new search on the input signal and recalculates the AM Modulation Depth according to the measured values.

SCPI command:

```
CALCulate<n>:MARKer<m>:FUNCtion:MDEPth:SEARchsignal ONCE
on page 545
```

4.11.4 Optimizing and Troubleshooting the Measurement

If the results do not meet your expectations, try the following methods to optimize the measurement:

- Set the center frequency to the frequency of the device under test.
- Adjust the span so the peaks to the left and right of the carrier, produced by the AM modulated signal, are clearly visible.
 - If the span is too wide, these signals may fall together with the carrier and the measurement can not be performed.
 - If the span is too narrow, theses signals are outside of the measured span and the delta markers can not find these peaks.

The rule of thumb is to set the span to three times the value of the AM modulation frequency.

Basic Measurements

4.11.5 How to Determine the AM Modulation Depth

- 1. Apply a modulated carrier signal to the R&S FSW input.
- 2. On the R&S FSW, press the MEAS key.
- Select the "AM Modulation Depth" measurement function from the "Select Measurement" dialog box.
 - The calculated AM Modulation Depth is indicated in the marker information. The markers required for calculation are displayed in the marker table.
- 4. If the signal changes significantly during or after the AM Modulation Depth measurement, use the "Search Signals" function to start a new peak search automatically and restart the calculation of the AM Modulation Depth.

4.12 Basic Measurements

Basic measurements are common sweeps in the time or frequency domain which provide an overview of the basic input signal characteristics.

If no other measurement function is selected, or if all measurement functions are switched off, the R&S FSW performs a basic frequency or time sweep. After a preset, a frequency sweep is performed.

Use the general measurement settings to configure the measurement, e.g. via the "Overview" (see chapter 5, "Common Measurement Settings", on page 159).

4.12.1 How to Perform a Basic Sweep Measurement

To perform one or more single sweeps

- Configure the frequency and span to be measured ("Frequency" dialog box, see chapter 5.3, "Frequency and Span Configuration", on page 177).
- 2. Configure the number of sweeps to be performed in a single measurement ("Sweep Config" dialog box, see "Sweep/Average Count" on page 203).
- 3. If necessary, configure how the signal is processed internally ("Bandwidth" dialog box, see "Sweep Type" on page 203).
- 4. If necessary, configure a trigger for the measurement ("Trigger/Gate Settings" dialog box, see chapter 5.6, "Trigger and Gate Configuration", on page 208).
- 5. Define how the results are evaluated for display ("Trace" dialog box, see chapter 6.3.2.1, "Trace Settings", on page 248).
- 6. If necessary, configure the vertical axis of the display ("Amplitude" dialog box, see chapter 5.4, "Amplitude and Vertical Axis Configuration", on page 184).

Basic Measurements

- 7. To start the measurement, select one of the following:
 - RUN SINGLE key
 - "Single Sweep" softkey in the "Sweep" menu

The defined number of sweeps are performed, then the measurement is stopped. While the measurement is running, the RUN SINGLE key is highlighted. To abort the measurement, press the RUN SINGLE key again. The key is no longer highlighted. The results are not deleted until a new measurement is started.

8. To repeat the same number of sweeps without deleting the last trace, select the "Continue Single Sweep" softkey in the "Sweep" menu.

To start continuous sweeping

- If you want to average the trace or search for a maximum over more (or less) than 10 sweeps, configure the "Average/Sweep Count" ("Sweep Config" dialog box, see "Sweep/Average Count" on page 203).
- To start the measurement, select one of the following:
 - RUN CONT key
 - "Continuous Sweep" softkey in the "Sweep" menu

After each sweep is completed, a new one is started automatically. While the measurement is running, the RUN CONT key is highlighted. To stop the measurement, press the RUN CONT key again. The key is no longer highlighted. The results are not deleted until a new measurement is started.

4.12.2 Measurement Example – Measuring Levels at Low S/N Ratios

The minimum signal level a signal analyzer can measure is limited by its intrinsic noise. Small signals can be swamped by noise and therefore cannot be measured. For signals that are just above the intrinsic noise, the accuracy of the level measurement is influenced by the intrinsic noise of the signal analyzer.

The displayed noise level of a signal analyzer depends on its noise figure, the selected RF attenuation, the selected reference level, the selected resolution and video bandwidth and the detector.

For details see:

- chapter 5.4.1.2, "RF Attenuation", on page 185
- chapter 5.4.1.1, "Reference Level", on page 185
- chapter 5.5.1.1, "Separating Signals by Selecting an Appropriate Resolution Bandwidth", on page 194
- chapter 5.5.1.2, "Smoothing the Trace Using the Video Bandwidth", on page 195
- chapter 6.3.1.1, "Mapping Samples to Sweep Points with the Trace Detector", on page 237

This measurement example shows the different factors influencing the S/N ratio.

Basic Measurements

Signal generator settings (e.g. R&S SMU):

Frequency:	128 MHz
Level:	- 95 dBm

Procedure:

- 1. Preset the R&S FSW.
- 2. Set the center frequency to 128 MHz.
- 3. Set the span to 100 MHz.
- 4. Set the reference level to-30 dBm.
- 5. Set the RF attenuation to 0 dB.

The signal is measured with the auto peak detector and is completely hidden in the intrinsic noise of the R&S FSW.

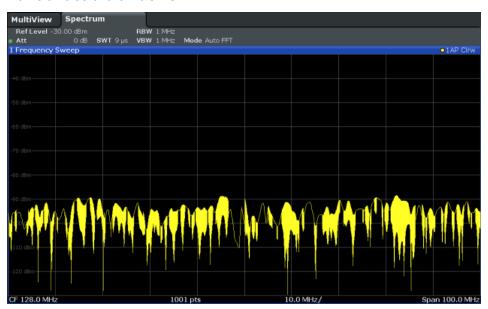


Fig. 4-17: Sine wave signal with low S/N ratio

6. To suppress noise spikes, average the trace. In the "Traces" configuration dialog, set the "Trace mode" to "Average" (see "Trace Mode" on page 249).

The traces of consecutive sweeps are averaged. To perform averaging, the R&S FSW automatically switches on the sample detector. The RF signal, therefore, can be more clearly distinguished from noise.

Basic Measurements

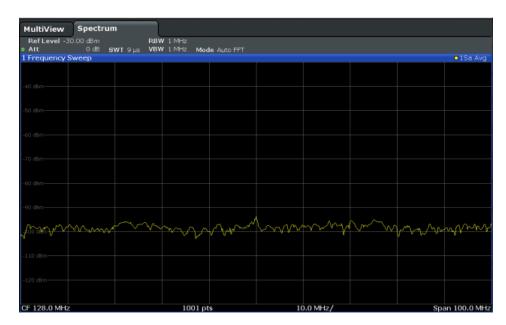
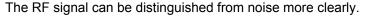


Fig. 4-18: RF sine wave signal with low S/N ratio with an averaged trace

7. Instead of trace averaging, you can select a video filter that is narrower than the resolution bandwidth. Set the trace mode back to "Clear Write", then set the VBW to 10 kHz manually in the "Bandwidth" configuration dialog.



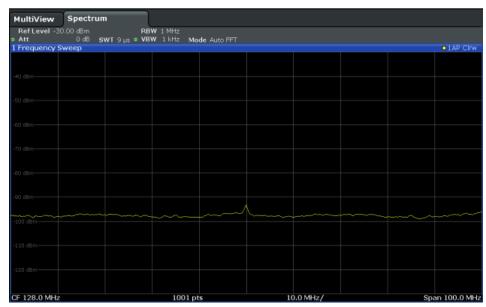


Fig. 4-19: RF sine wave signal with low S/N ratio with a smaller video bandwidth

8. By reducing the resolution bandwidth by a factor of 10, the noise is reduced by 10 dB. Set the RBW to 100 kHz.

Basic Measurements

The displayed noise is reduced by approx. 10 dB. The signal, therefore, emerges from noise by about 10 dB. Compared to the previous setting, the video bandwidth has remained the same, i.e. it has increased relative to the smaller resolution bandwidth. The averaging effect of the video bandwidth is therefore reduced. The trace will be noisier.

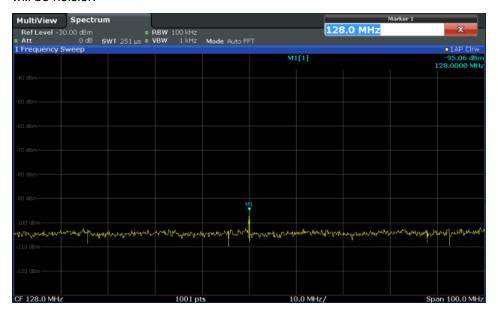


Fig. 4-20: Reference signal at a smaller resolution bandwidth

5 Common Measurement Settings

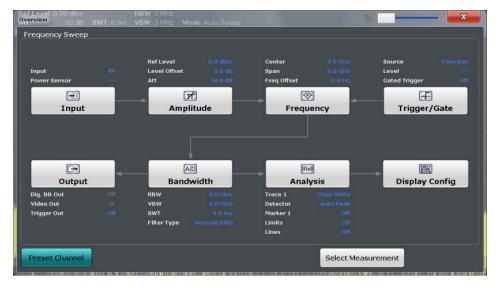
Basic measurement settings that are common to many measurement tasks, regardless of the application or operating mode, are described here. If you are performing a specific measurement task, using an operating mode other than Signal and Spectrum Analyzer mode, or an application other than the Spectrum application, be sure to check the specific application or mode description for settings that may deviate from these common settings.

Configuration Overview	159
Data Input and Output	
Frequency and Span Configuration	
Amplitude and Vertical Axis Configuration	
Bandwidth, Filter and Sweep Configuration	
Trigger and Gate Configuration	
Adjusting Settings Automatically	

5.1 Configuration Overview



Throughout the measurement channel configuration, an overview of the most important currently defined settings is provided in the configuration "Overview". The "Overview" is displayed when you select the "Overview" icon, which is available at the bottom of all softkey menus.



In addition to the main measurement settings, the "Overview" provides quick access to the main settings dialog boxes. Thus, you can easily configure an entire measurement channel from input over processing to output and analysis by stepping through the dialog boxes as indicated in the "Overview".

In particular, the "Overview" provides quick access to the following configuration dialog boxes (listed in the recommended order of processing):

1. "Select Measurement"

Configuration Overview

See chapter 4.1, "Available Measurement Functions", on page 30

2. Input

See chapter 5.2.2, "Input Settings", on page 163

3. Amplitude

See chapter 5.4, "Amplitude and Vertical Axis Configuration", on page 184

Frequency

See chapter 5.3, "Frequency and Span Configuration", on page 177

5. (Optionally:) Trigger/Gate

See chapter 5.6, "Trigger and Gate Configuration", on page 208

6. Bandwidth

See chapter 5.5.2, "Bandwidth, Filter and Sweep Settings", on page 198 (For SEM measurements: SEM Setup, see chapter 4.5.5, "SEM Configuration", on page 81)

(For Spurious measurements: Spurious Setup, see chapter 4.6.4, "Spurious Emissions Measurement Configuration", on page 108)

7. (Optionally:) Outputs

See chapter 5.2.3, "Data Output", on page 165

8. Analysis

See chapter 6, "Common Analysis and Display Functions", on page 228

9. Display

See chapter 6.1, "Result Display Configuration", on page 228

To configure settings

➤ Select any button to open the corresponding dialog box. To configure a particular setting displayed in the "Overview", simply select the setting on the touch screen. The corresponding dialog box is opened with the focus on the selected setting.

Preset Channel

Select the "Preset Channel" button in the lower lefthand corner of the "Overview" to restore all measurement settings in the current channel to their default values.

Note that the PRESET key on the front panel restores all measurements in all measurement channels on the R&S FSW to their default values!

For details see chapter 7.1, "Restoring the Default Instrument Configuration (Preset)", on page 318.

SCPI command:

SYSTem: PRESet: CHANnel [: EXECute] on page 690

5.2 Data Input and Output

The R&S FSW can analyze signals from different input sources (such as RF, power sensors etc.) and provide various types of output (such as video or trigger signals).

•	Receiving Data Input and Providing Data Output	161
•	Input Settings.	163
•	Data Output	165
•	Power Sensors	168

5.2.1 Receiving Data Input and Providing Data Output

The R&S FSW can analyze signals from different input sources and provide various types of output (such as noise or trigger signals).



Digital Baseband output is only available in the I/Q Analyzer application, and only if the optional Digital Baseband Interface (R&S FSW-B17) is installed.

For details see the R&S FSW I/Q Analyzer User Manual.

5.2.1.1 RF Input Protection

The RF input connector of the R&S FSW must be protected against signal levels that exceed the ranges specified in the data sheet. Therefore, the R&S FSW is equipped with an overload protection mechanism. This mechanism becomes active as soon as the power at the input mixer exceeds the specified limit. It ensures that the connection between RF input and input mixer is cut off.

When the overload protection is activated, an error message is displayed in the status bar ("INPUT OVLD"), and a message box informs you that the RF Input was disconnected. Furthermore, a status bit (bit 3) in the STAT: QUES: POW status register is set. In this case you must decrease the level at the RF input connector and then close the message box. Then measurement is possible again. Reactivating the RF input is also possible via the remote command INPut: ATTenuation: PROTection: RESet

5.2.1.2 Input from Noise Sources

The R&S FSW provides a connector (NOISE SOURCE CONTROL) with a voltage supply for an external noise source. By switching the supply voltage for an external noise source on or off in the firmware, you can activate or deactive the device as required.

External noise sources are useful when you are measuring power levels that fall below the noise floor of the R&S FSW itself, for example when measuring the noise level of an amplifier.

In this case, you can first connect an external noise source (whose noise power level is known in advance) to the R&S FSW and measure the total noise power. From this value you can determine the noise power of the R&S FSW. Then when you measure the power

level of the actual DUT, you can deduct the known noise level from the total power to obtain the power level of the DUT.

The noise source is controlled in the "Output" settings, see "Noise Source" on page 167

5.2.1.3 Receiving and Providing Trigger Signals

Using one of the variable TRIGGER INPUT/OUTPUT connectors of the R&S FSW, the R&S FSW can use a signal from an external reference as a trigger to capture data. Alternatively, the internal trigger signal used by the R&S FSW can be output for use by other connected devices. Using the same trigger on several devices is useful to synchronize the transmitted and received signals within a measurement.

For details on the connectors see the R&S FSW "Getting Started" manual.

External trigger as input

If the trigger signal for the R&S FSW is provided by an external reference, the reference signal source must be connected to the R&S FSW and the trigger source must be defined as "External" on the R&S FSW.

Trigger output

The R&S FSW can send output to another device either to pass on the internal trigger signal, or to indicate that the R&S FSW itself is ready to trigger.

The trigger signal can be output by the R&S FSW automatically, or manually by the user. If it is sent automatically, a high signal is output when the R&S FSW has triggered due to a sweep start ("Device Triggered"), or when the R&S FSW is ready to receive a trigger signal after a sweep start ("Trigger Armed").

Manual triggering

If the trigger output signal is initiated manually, the length and level (high/low) of the trigger pulse is also user-definable. Note, however, that the trigger pulse level is always opposite to the constant signal level defined by the output "Level" setting, e.g. for "Level = High", a constant high signal is output to the connector until the "Send Trigger" button is selected. Then, a low pulse is sent.



Providing trigger signals as output is described in detail in the R&S FSW User Manual.

5.2.1.4 IF and Video Signal Output

The measured IF signal or displayed video signal (i.e. the filtered and detected IF signal) can be sent to the IF/VIDEO/DEMOD output connector.

The **video output** is a signal of 1 V. It can be used, for example, to control demodulated audio frequencies.

The **IF output** is a signal of the measured level at a specified frequency.

Restrictions

Note the following restrictions for IF output:

- IF and video output is only available in the time domain (zero span).
- For I/Q data and in FFT mode, only IF output is available.
- F output is not available if any of the following conditions apply:
 - The Digital Baseband Interface (R&S FSW-B17) is active (for input or output)
 - MSRA operating mode is active
 - The wideband extension is used (hardware option R&S FSW-B160 / U160; used automatically for bandwidths > 80 MHz; in this case use the IF WIDE OUTPUT connector)
 - The sample rate is larger than 200 MHz (upsampling)

IF WIDE OUTPUT

If the optional hardware R&S FSW-B160/ -U160 for **bandwidth extension** is installed and activated (i.e. for bandwidths > 80 MHz), the IF output is not sent to the IF/VIDEO/ DEMOD output connector, but rather to the additional **IF WIDE OUTPUT** connector provided by the option.

In this case, the IF output frequency cannot be defined manually, but is determined automatically depending on the center frequency. For details on the used frequencies see the data sheet. The currently used output frequency is indicated in the field otherwise used to define the frequency manually (in the "Output" settings dialog box, see "IF (Wide) Out Frequency" on page 166).

5.2.2 Input Settings

The input signal determines which data the R&S FSW will analyze.

Input settings can be configured via the INPUT/OUTPUT key, in the "Input" dialog box. Some settings are also available in the "Amplitude" tab of the "Amplitude" dialog box.



The Digital IQ input source is only available in applications that support I/Q data processing and is described in detail in the R&S FSW I/Q Analyzer User Manual.

5.2.2.1 Radio Frequency Input

The default input source for the R&S FSW is "Radio Frequency", i.e. the signal at the RF INPUT connector on the front panel of the R&S FSW. If no additional options are installed, this is the only available input source.



Radio Frequency State	164
Input Coupling.	
Impedance	
High-Pass Filter 13 GHz	165
YIG-Preselector	165

Radio Frequency State

Activates input from the RF INPUT connector.

SCPI command:

INPut: SELect on page 597

Input Coupling

The RF input of the R&S FSW can be coupled by alternating current (AC) or direct current (DC).

AC coupling blocks any DC voltage from the input signal. This is the default setting to prevent damage to the instrument. Very low frequencies in the input signal may be distorted.

However, some specifications require DC coupling. In this case, you must protect the instrument from damaging DC input voltages manually. For details, refer to the data sheet.

SCPI command:

INPut:COUPling on page 596

Impedance

The reference impedance for the measured levels of the R&S FSW can be set to 50 Ω or 75 Ω .

75 Ω should be selected if the 50 Ω input impedance is transformed to a higher impedance using a 75 Ω adapter of the RAZ type (= 25 Ω in series to the input impedance of the instrument). The correction value in this case is 1.76 dB = 10 log (75 Ω /50 Ω).

This value also affects the unit conversion (see "Reference Level" on page 187).

SCPI command:

INPut:IMPedance on page 597

High-Pass Filter 1...3 GHz

Activates an additional internal high-pass filter for RF input signals from 1 GHz to 3 GHz. This filter is used to remove the harmonics of the R&S FSW in order to measure the harmonics for a DUT, for example.

This function requires option R&S FSW-B13.

(Note: for RF input signals outside the specified range, the high-pass filter has no effect. For signals with a frequency of approximately 4 GHz upwards, the harmonics are suppressed sufficiently by the YIG filter.)

SCPI command:

INPut:FILTer:HPASs[:STATe] on page 596

YIG-Preselector

Activates or deactivates the YIG-preselector.

An internal YIG-preselector at the input of the R&S FSW ensures that image frequencies are rejected. However, this is only possible for a restricted bandwidth. In order to use the maximum bandwidth for signal analysis you can deactivate the YIG-preselector at the input of the R&S FSW, which may lead to image-frequency display.

Note that the YIG-preselector is active only on frequencies greater than 8 GHz. Therefore, switching the YIG-preselector on or off has no effect if the frequency is below that value.

Note:

For the following measurements, the YIG-Preselector is off by default (if available).

- I/Q Analyzer (and thus in all applications in MSRA operating mode)
- Multi-Carrier Group Delay
- GSM

INPut:FILTer:YIG[:STATe] on page 596

5.2.3 Data Output

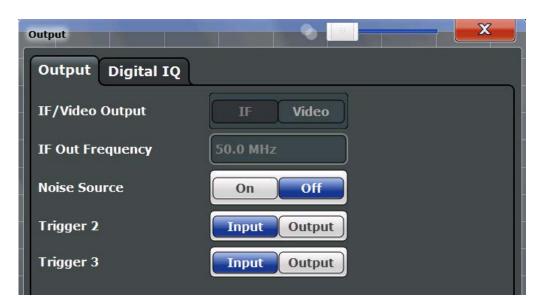
The R&S FSW can provide output to special connectors for other devices.

For details on connectors refer to the R&S FSW Getting Started manual, "Front / Rear Panel View" chapters.



Providing trigger signals as output is described in chapter 5.6.4, "How to Output a Trigger Signal", on page 225.

Output settings can be configured via the INPUT/OUTPUT key or in the "Outputs" dialog box.



IF/Video Output	166
IF (Wide) Out Frequency	166
Noise Source	167
Trigger 2/3	167
L Output Type	167
L Level	168
L Pulse Length	
L Send Trigger	

IF/Video Output

Defines the type of signal sent to the IF/VIDEO/DEMOD connector on the rear panel of the R&S FSW.

For restrictions and additional information see chapter 5.2.1.4, "IF and Video Signal Output", on page 162.

"IF" Sends the measured IF value at the frequency defined in "IF (Wide) Out

Frequency" on page 166 to the IF/VIDEO/DEMOD output connector.

"VIDEO" Sends the displayed video signal (i.e. the filtered and detected IF signal)

to the IF/VIDEO/DEMOD output connector.

This setting is required to send demodulated audio frequencies to the

output.

SCPI command:

OUTP: IF VID, see OUTPut: IF[:SOURce] on page 609

IF (Wide) Out Frequency

Defines the frequency at which the IF signal level is sent to the IF/VIDEO/DEMOD connector if IF/Video Output is set to "IF".

Note: The IF output frequency of the IF WIDE OUTPUT connector cannot be defined manually, but is determined automatically depending on the center frequency. It is indicated in this field when the IF WIDE OUTPUT connector is used. For details on the used frequencies see the data sheet.

The IF WIDE OUTPUT connector is used automatically instead of the IF/VIDEO/DEMOD connector if the bandwidth extension (hardware option R&S FSW-B160 / -U160) is activated (i.e. for bandwidths > 80 MHz).

For more information see chapter 5.2.1.4, "IF and Video Signal Output", on page 162.

SCPI command:

OUTPut: IF: IFFRequency on page 610

Noise Source

Switches the supply voltage for an external noise source on or off.

External noise sources are useful when you are measuring power levels that fall below the noise floor of the R&S FSW itself, for example when measuring the noise level of a DUT.

For details see chapter 5.2.1.2, "Input from Noise Sources", on page 161

SCPI command:

DIAGnostic<n>:SERVice:NSOurce on page 609

Trigger 2/3

Defines the usage of the variable TRIGGER INPUT/OUTPUT connectors, where:

"Trigger 2": TRIGGER INPUT/OUTPUT connector on the front panel

"Trigger 3": TRIGGER 3 INPUT/ OUTPUT connector on the rear panel

(Trigger 1 is INPUT only.)

Note: Providing trigger signals as output is described in detail in the R&S FSW User Manual.

"Input" The signal at the connector is used as an external trigger source by the

R&S FSW. No further trigger parameters are available for the connec-

tor.

"Output" The R&S FSW sends a trigger signal to the output connector to be used

by connected devices.

Further trigger parameters are available for the connector.

SCPI command:

OUTPut:TRIGger<port>:LEVel on page 590
OUTPut:TRIGger<port>:DIRection on page 589

Output Type ← Trigger 2/3

Type of signal to be sent to the output

"Device Trig- (Default) Sends a trigger when the R&S FSW triggers.

gered"

"Trigger Sends a (high level) trigger when the R&S FSW is in "Ready for trig-

Armed" ger" state.

This state is indicated by a status bit in the STATus:OPERation register (bit 5), as well as by a low level signal at the AUX port (pin 9). For details see "STATus:OPERation Register" on page 403 and the

R&S FSW Getting Started manual.

"User Defined" Sends a trigger when user selects "Send Trigger" button.
In this case, further parameters are available for the output signal.

SCPI command:

OUTPut: TRIGger<port>:OTYPe on page 590

Level ← Output Type ← Trigger 2/3

Defines whether a constant high (1) or low (0) signal is sent to the output connector.

SCPI command:

OUTPut:TRIGger<port>:LEVel on page 590

Pulse Length ← Output Type ← Trigger 2/3

Defines the length of the pulse sent as a trigger to the output connector.

SCPI command:

OUTPut:TRIGger<port>:PULSe:LENGth on page 591

Send Trigger ← Output Type ← Trigger 2/3

Sends a user-defined trigger to the output connector immediately. Note that the trigger pulse level is always opposite to the constant signal level defined by the output "Level" setting, e.g. for "Level = High", a constant high signal is output to the connector until the "Send Trigger" button is selected. Then, a low pulse is sent.

Which pulse level will be sent is indicated by a graphic on the button.

SCPI command:

OUTPut:TRIGger<port>:PULSe:IMMediate on page 591

5.2.4 Power Sensors

The R&S FSW can also analyze data from a connected power sensor.

•	Basics on Power Sensors	168
•	Power Sensor Settings	170
	How to Work With a Power Sensor	175

5.2.4.1 Basics on Power Sensors

For precise power measurement up to 4 power sensors can be connected to the instrument via the power sensor interface (on the front panel). Both manual operation and remote control are supported.



Currently, only R&S NRP-Zxy power sensors are supported. For a detailed list of supported sensors see the data sheet.

Power sensors can also be used to trigger a measurement at a specified power level, e.g. from a signal generator (see "Using a Power Sensor as an External Power Trigger" on page 169).

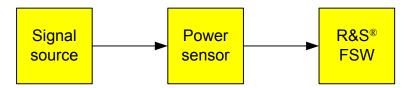


Fig. 5-1: Power sensor support - standard test setup

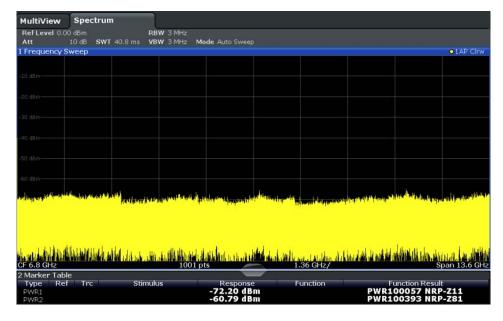


Using the power sensor with several applications

The power sensor cannot be used from the R&S FSW firmware and the R&S Power Viewer (virtual power meter for displaying results of the R&S NRP power sensors) simultaneously. After using the Power Viewer, close the application, then unplug and replug the sensor. Afterwards the power sensor can be used by the R&S FSW again.

Result display

The results of the power sensor measurements are displayed in the marker table. For each power sensor, a row is inserted. The sensor index is indicated in the "Type" column.



Using a Power Sensor as an External Power Trigger

Power sensors can be used to trigger a measurement at a specified power level, e.g. from a signal generator.



Currently, only the following power sensors are supported as power triggers:

- R&S NRP-Z81
- R&S NRP-Z85
- R&S NRP-Z86

With the R&S FSW, the power sensors can be connected to the "Power Sensor" interface directly, and no further cables are required. They can then be configured as an external power sensor trigger.



Fig. 5-2: Connecting a power sensor using the POWER SENSOR interface

The R&S FSW receives an external trigger signal when the defined trigger level is measured by the power sensor. Power measurement results are provided as usual.



The "Gate Mode" *Level* is not supported for R&S power sensors. The signal sent by these sensors merely reflects the instant the level is first exceeded, rather than a time period. However, only time periods can be used for gating in level mode. Thus, the trigger impulse from the sensors is not long enough for a fully gated measurement; the measurement cannot be completed. For details on gating see chapter 5.6.1.2, "Gated Measurements", on page 211.

For details see "How to Configure a Power Sensor as an External (PSE) Trigger" on page 177.

5.2.4.2 Power Sensor Settings

Power sensor settings are available in the "Power Sensor" tab of the "Input" dialog box. Each sensor is configured on a separate tab.



State	
Continuous Value Update	172
Select	172
Zeroing Power Sensor	172
Frequency Manual	172
Frequency Coupling	173
Unit/Scale	
Meas Time/Average	173
Setting the Reference Level from the Measurement (Meas->Ref)	173
Reference Value	173
Use Ref Lev Offset	174
Average Count (Number of Readings)	174
Duty Cycle	174
Using the power sensor as an external trigger	174
L External Trigger Level	174
L Hysteresis	
L Trigger Holdoff	
L Drop-Out Time	
L Slope	

State

Switches the power measurement for all power sensors on or off. Note that in addition to this general setting, each power sensor can be activated or deactivated individually by the Select setting on each tab. However, the general setting overrides the individual settings.

SCPI command:

[SENSe:]PMETer[:STATe] on page 605

Continuous Value Update

If activated, the power sensor data is updated continuously even after a single sweep has completed. For continuous sweeps this setting is irrelevant.

This function cannot be activated for individual sensors.

If the power sensor is being used as a trigger (see "Using the power sensor as an external trigger" on page 174), continuous update is not possible; this setting is ignored.

SCPI command:

```
[SENSe:]PMETer:UPDate[:STATe] on page 605
```

Select

Selects the individual power sensor for usage if power measurement is generally activated (State function).

The detected **serial numbers** of the power sensors connected to the instrument are provided in a selection list. For each of the four available power sensor indexes ("Power Sensor 1"..."Power Sensor 4"), which correspond to the tabs in the configuration dialog, one of the detected serial numbers can be assigned. The physical sensor is thus assigned to the configuration setting for the selected power sensor index.

By default, serial numbers not yet assigned are automatically assigned to the next free power sensor index for which "Auto Assignment" is selected.

Alternatively, you can assign the sensors manually by deactivating the "Auto" option and selecting a serial number from the list.

SCPI command:

```
[SENSe:]PMETer[:STATe] on page 605
SYSTem:COMMunicate:RDEVice:PMETer:DEFine on page 599
SYSTem:COMMunicate:RDEVice:PMETer:CONFigure:AUTO[:STATe]
on page 598
SYSTem:COMMunicate:RDEVice:PMETer:COUNt? on page 598
```

Zeroing Power Sensor

Starts zeroing of the power sensor.

For details on the zeroing process refer to "How to Zero the Power Sensor" on page 176.

SCPI command:

```
CALibration: PMETer: ZERO: AUTO ONCE on page 600
```

Frequency Manual

Defines the frequency of the signal to be measured. The power sensor has a memory with frequency-dependent correction factors. This allows extreme accuracy for signals of a known frequency.

SCPI command:

```
[SENSe:] PMETer: FREQuency on page 602
```

Frequency Coupling

Selects the coupling option. The frequency can be coupled automatically to the center frequency of the instrument or to the frequency of marker 1.

SCPI command:

```
[SENSe:] PMETer:FREQuency:LINK on page 603
```

Unit/Scale

Selects the unit with which the measured power is to be displayed. Available units are dBm, dB, W and %.

If dB or % is selected, the display is relative to the reference value that is defined with either the "Meas -> Ref" setting or the "Reference Value" setting.

SCPI command:

```
UNIT<n>:PMETer:POWer on page 605
UNIT<n>:PMETer:POWer:RATio on page 606
```

Meas Time/Average

Selects the measurement time or switches to manual averaging mode. In general, results are more precise with longer measurement times. The following settings are recommended for different signal types to obtain stable and precise results:

"Short" Stationary signals with high power (> -40dBm), because they require

only a short measurement time and short measurement time provides

the highest repetition rates.

"Normal" Signals with lower power or modulated signals

"Long" Signals at the lower end of the measurement range (<-50 dBm) or

Signals with lower power to minimize the influence of noise

"Manual" Manual averaging mode. The average count is set with the Average

Count (Number of Readings) setting.

SCPI command:

```
[SENSe:]PMETer:MTIMe on page 603
[SENSe:]PMETer:MTIMe:AVERage[:STATe] on page 604
```

Setting the Reference Level from the Measurement (Meas->Ref)

Sets the currently measured power as a reference value for the relative display. The reference value can also be set manually via the Reference Value setting.

SCPI command:

```
CALCulate<n>: PMETer: RELative[:MAGNitude]: AUTO ONCE on page 600
```

Reference Value

Defines the reference value for relative measurements in the unit dBm.

SCPI command:

```
CALCulate<n>: PMETer: RELative[:MAGNitude] on page 600
```

Use Ref Lev Offset

If activated, takes the reference level offset defined for the analyzer into account for the measured power (see "Shifting the Display (Offset)" on page 188). If deactivated, takes no offset into account.

SCPI command:

```
[SENSe:]PMETer:ROFFset[:STATe] on page 604
```

Average Count (Number of Readings)

Defines the number of readings (averages) to be performed after a single sweep has been started. This setting is only available if manual averaging is selected (Meas Time/Average setting).

The values for the average count range from 0 to 256 in binary steps (1, 2, 4, 8, ...). For average count = 0 or 1, one reading is performed. The general averaging and sweep count for the trace are independent from this setting.

Results become more stable with extended average, particularly if signals with low power are measured. This setting can be used to minimize the influence of noise in the power sensor measurement.

SCPI command:

```
[SENSe:]PMETer:MTIMe:AVERage:COUNt on page 603
```

Duty Cycle

Sets the duty cycle to a percent value for the correction of pulse-modulated signals and activates the duty cycle correction. With the correction activated, the sensor calculates the signal pulse power from this value and the mean power.

SCPI command:

```
[SENSe:]PMETer:DCYCle[:STATe] on page 602
[SENSe:]PMETer:DCYCle:VALue on page 602
```

Using the power sensor as an external trigger

If activated, the power sensor creates a trigger signal when a power higher than the defined "External Trigger Level" is measured. This trigger signal can be used as an external power trigger by the R&S FSW.

This setting is only available in conjunction with a compatible power sensor.

For details on using a power sensor as an external trigger, see "Using a Power Sensor as an External Power Trigger" on page 169.

SCPI command:

```
[SENSe:]PMETer:TRIGger[:STATe] on page 608
TRIG:SOUR PSE, see TRIGger[:SEQuence]:SOURce on page 585
```

External Trigger Level ← Using the power sensor as an external trigger

Defines the trigger level for the power sensor trigger.

For details on supported trigger levels, see the data sheet.

SCPI command:

```
[SENSe:]PMETer:TRIGger:LEVel on page 607
```

Hysteresis ← Using the power sensor as an external trigger

Defines the distance in dB to the trigger level that the trigger source must exceed before a trigger event occurs. Setting a hysteresis avoids unwanted trigger events caused by noise oscillation around the trigger level.

SCPI command:

[SENSe:]PMETer:TRIGger:HYSTeresis on page 607

Trigger Holdoff ← Using the power sensor as an external trigger

Defines the minimum time (in seconds) that must pass between two trigger events. Trigger events that occur during the holdoff time are ignored.

SCPI command:

[SENSe:]PMETer:TRIGger:HOLDoff on page 606

Drop-Out Time ← Using the power sensor as an external trigger

Defines the time the input signal must stay below the trigger level before triggering again.

Slope ← Using the power sensor as an external trigger

Defines whether triggering occurs when the signal rises to the trigger level or falls down to it.

SCPI command:

[SENSe:]PMETer:TRIGger:SLOPe on page 608

5.2.4.3 How to Work With a Power Sensor

The following step-by-step instructions demonstrate how to set up a power sensor. For details on individual functions and settings see chapter 5.2.4.2, "Power Sensor Settings", on page 170.

The remote commands required to perform these tasks are described in chapter 10.5.6.2, "Working with Power Sensors", on page 598.



Power sensors can also be used to trigger a measurement at a specified power level, e.g. from a signal generator. This is described in "How to Configure a Power Sensor as an External (PSE) Trigger" on page 177.

How to Set Up a Power Sensor

Up to 4 external power sensors can be configured separately and used for precise power measurement, as a trigger, or both. All power sensors can be activated and deactivated individually.

The following procedure describes in detail how to configure and activate power sensors.

- 1. To display the "Power Sensor" tab of the "Input" dialog box, do one of the following:
 - Select "Input" from the "Overview".
 - Select the INPUT/OUTPUT key and then the "Power Sensor Config" softkey.
- 2. Select the tab for the power sensor index you want to configure, e.g. "Sensor 1".

- 3. Press "Select" to analyze the power sensor data according to the current configuration when power measurement is activated.
- 4. From the selection list with serial numbers of connected power sensors, select the sensor you want to configure.
 - To have newly connected power sensors assigned to a tab automatically (default), select "Auto".
- 5. Define the frequency of the signal whose power you want to measure.
 - a) To define the frequency manually, select "Frequency Manual" and enter a frequency.
 - b) To determine the frequency automatically, select "Frequency Coupling" and then either "Center", to use the center frequency, or "Marker", to use the frequency defined by marker 1.
- 6. Select the unit for the power result display.
- Select the measurement time for which the average is calculated, or define the number of readings to average. To define the number of readings to be taken into account manually, select "Manual" and enter the number in the "Number of Readings" field.
- 8. To activate the duty cycle correction, select "DutyCycle" and enter a percentage as the correction value.
- 9. If you selected "dB" or "%" as units (relative display), define a reference value:
 - To set the currently measured power as a reference value, press the "Meas -> Ref" button.
 - b) Alternatively, enter a value manually in the "Reference Value" field.
 - c) Optionally, select the "Use Ref Level Offset" option to take the reference level offset set for the analyzer into account for the measured power.
- To use the power sensor as an external power trigger, select the "External Power Trigger" option and define the trigger settings.
 - For details see "How to Configure a Power Sensor as an External (PSE) Trigger" on page 177.
- 11. If necessary, repeat steps 3-10 for another power sensor.
- 12. Set the "Power Sensor State" at the top of the "Power Sensor" tab to "On" to activate power measurement for the selected power sensors.

The results of the power measurement are displayed in the marker table (Function: "Sensor<1...4>").

How to Zero the Power Sensor

- 1. To display the "Power Sensor" tab of the "Input" dialog box, do one of the following:
 - Select "Input" from the "Overview".
 - Select the INPUT/OUTPUT key and then the "Power Sensor Config" softkey.
- 2. Select the tab that is assigned to the power sensor you want to zero.

- Press the "Zeroing Power Sensor" button.
 A dialog box is displayed that prompts you to disconnect all signals from the input of the power sensor.
- 4. Disconnect all signals sending input to the power sensor and press ENTER to continue.
- Wait until zeroing is complete.
 A corresponding message is displayed.

How to Configure a Power Sensor as an External (PSE) Trigger

The following step-by-step instructions demonstrate how to configure a power sensor to be used as an external power sensor trigger.

To configure a power sensor as an external power sensor (PSE) trigger

- 1. Connect a compatible power sensor to the "Power Sensor" interface on the front panel of the R&S FSW. (For details on supported sensors see "Using a Power Sensor as an External Power Trigger" on page 169).
- 2. Set up the power sensor as described in "How to Set Up a Power Sensor" on page 175.
- 3. In the "Power Sensor" tab of the "Input" dialog box, select the "External Power Trigger" option.
- 4. Enter the power level at which a trigger signal is to be generated ("External Trigger Level") and the other trigger settings for the power sensor trigger.
- 5. Press the TRIG key on the front panel of the instrument and then select "Trigger / Gate Config".
- 6. In the "Trigger and Gate" dialog box, select "Signal Source" = "PSE".
 - The R&S FSW is configured to trigger when the defined conditions for the power sensor occur. Power measurement results are provided as usual.

5.3 Frequency and Span Configuration

The frequency and span settings define the scope of the signal and spectrum to be analyzed with the R&S FSW.

•	Impact of the Frequency and Span Settings	178
	Frequency and Span Settings	
	How To Define the Frequency Range	
	How to Move the Center Frequency through the Frequency Range	
	How to Keep the Center Frequency Stable	

Frequency and Span Configuration

5.3.1 Impact of the Frequency and Span Settings

Some background knowledge on the impact of the described settings is provided here for a better understanding of the required configuration.

5.3.1.1 Defining the Scope of the Measurement - Frequency Range

The frequency range defines the scope of the signal and spectrum to be analyzed. It can either be defined as a span around a center frequency, or as a range from a start to a stop frequency. Furthermore, the full span comprising the entire possible frequency range can be selected, or a zero span. The full span option allows you to perform an overview measurement over the entire span. Using the "Last Span" function you can easily switch back to the detailed measurement of a specific frequency range.

For sinusoidal signals, the center frequency can be defined automatically by the R&S FSW as the highest frequency level in the frequency span (see "Adjusting the Center Frequency Automatically (Auto Freq)" on page 226).

5.3.1.2 Stepping Through the Frequency Range - Center Frequency Stepsize

Using the arrow keys you can move the center frequency in discrete steps through the available frequency range. The step size by which the center frequency is increased or decreased is defined by the "Center Frequency Stepsize".



The "Center Frequency Stepsize" also defines the step size by which the value is increased or decreased when you use the rotary knob to change the center frequency; however, the **rotary knob** moves in steps of only **1/10 of the "Center Frequency Stepsize"** to allow for a more precise setting.

By default, the step size is set in relation to the selected span or resolution bandwidth (for zero span measurements). In some cases, however, it may be useful to set the step size to other values.

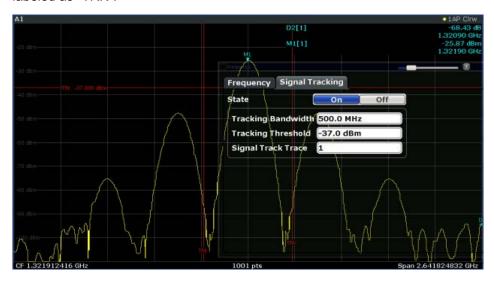
For example, to analyze signal harmonics, you can define the step size to be equal to the center frequency. In this case, each stroke of the arrow key selects the center frequency of another harmonic. Similarly, you can define the step size to be equal to the current marker frequency.

5.3.1.3 Keeping the Center Frequency Stable - Signal Tracking

If the signal drifts on the display but you want to keep the center frequency on the signal peak, the center frequency can be adjusted automatically using **signal tracking**. In this case, the signal trace is surveyed in a specified bandwidth around the expected center frequency. After each sweep, the center frequency is set to the maximum signal found within the searched bandwidth. If no maximum signal above a defined threshold value is

Frequency and Span Configuration

found in the searched bandwidth, the center frequency remains unchanged. The search bandwidth and the threshold value are shown in the diagram by red lines which are labeled as "TRK".



5.3.2 Frequency and Span Settings

Frequency and span settings can be configured via the "Frequency" dialog box. Signal tracking is configured in the "Signal Tracking" tab of this dialog box. For details see chapter 5.3.3, "How To Define the Frequency Range", on page 183.





Center	180	
Span	180	
Start / Stop		
Full Span.		
Zero Span		
Last Span		
Center Frequency Stepsize		
Frequency Offset		
Signal Tracking	182	
L Signal Tracking State		
L Tracking Bandwidth	183	
L Tracking Threshold		
L Signal Track Trace		

Center

Defines the normal center frequency of the signal. The allowed range of values for the center frequency depends on the frequency span.

span > 0: $span_{min}/2 \le f_{center} \le f_{max} - span_{min}/2$

zero span: 0 Hz \leq $f_{center} \leq$ f_{max}

 f_{max} and span_{min} are specified in the data sheet.

SCPI command:

[SENSe:] FREQuency:CENTer on page 563

Span

Defines the frequency span. The center frequency is kept constant. The following range is allowed:

span = 0: 0 Hz

Frequency and Span Configuration

```
span >0: span<sub>min</sub> ≤ f<sub>span</sub> ≤ f<sub>max</sub>
```

f_{max} and span_{min} are specified in the data sheet.

For more information see chapter 5.3.1.1, "Defining the Scope of the Measurement - Frequency Range", on page 178.

SCPI command:

[SENSe:] FREQuency: SPAN on page 566

Start / Stop

Defines the start and stop frequencies. The following range of values is allowed:

```
f_{min} \le f_{start} \le f_{max} - span_{min}
```

$$f_{min} + span_{min} \le f_{stop} \le f_{max}$$

 f_{min} , f_{max} and span_{min} are specified in the data sheet.

SCPI command:

```
[SENSe:] FREQuency:STARt on page 566 [SENSe:] FREQuency:STOP on page 566
```

Full Span

Sets the span to the full frequency range of the R&S FSW specified in the data sheet. This setting is useful for overview measurements.

SCPI command:

```
[SENSe:] FREQuency:SPAN:FULL on page 566
```

Zero Span

Sets the span to 0 Hz (zero span). The x-axis becomes the time axis with the grid lines corresponding to 1/10 of the current sweep time ("SWT").

For details see chapter 4.12, "Basic Measurements", on page 154.

SCPI command:

```
FREQ:SPAN OHz, see [SENSe:] FREQuency:SPAN:FULL on page 566
```

Last Span

Sets the span to the previous value. With this function you can switch between an overview measurement and a detailed measurement quickly.

Center Frequency Stepsize

Defines the step size by which the center frequency is increased or decreased when the arrow keys are pressed. When you use the rotary knob the center frequency changes in steps of only 1/10 of the "Center Frequency Stepsize".

The step size can be coupled to the span (span > 0) or the resolution bandwidth (span = 0), or it can be manually set to a fixed value.

For more details see chapter 5.3.1.2, "Stepping Through the Frequency Range - Center Frequency Stepsize", on page 178.

"0.1 * Span / Sets the step size for the center frequency to 10 % of the span / RBW.

This is the default setting.

Frequency and Span Configuration

"0.5 * Span / Sets the step size for the center frequency to 50 % of the span / RBW. RBW" "X * Span / Sets the step size for the center frequency to a manually defined factor RBW" of the span / RBW. The "X-Factor" defines the percentage of the span / RBW. Values between 1 and 100 % in steps of 1 % are allowed. The default setting is 10 %. "= Center" Sets the step size to the value of the center frequency and removes the coupling of the step size to span or resolution bandwidth. The used value is indicated in the "Value" field. "= Marker" This setting is only available if a marker is active. Sets the step size to the value of the current marker and removes the coupling of the step size to span or resolution bandwidth. The used value is indicated in the "Value" field. "Manual" Defines a fixed step size for the center frequency. Enter the step size in the "Value" field.

SCPI command:

```
[SENSe:]FREQuency:CENTer:STEP:LINK on page 565
[SENSe:]FREQuency:CENTer:STEP:LINK:FACTor on page 565
[SENSe:]FREQuency:CENTer:STEP on page 564
```

Frequency Offset

Shifts the displayed frequency range along the x-axis by the defined offset.

This parameter has no effect on the R&S FSW hardware, or on the captured data or on data processing. It is simply a manipulation of the final results in which absolute frequency values are displayed. Thus, the x-axis of a spectrum display is shifted by a constant offset if it shows absolute frequencies, but not if it shows frequencies relative to the signal's center frequency.

A frequency offset can be used to correct the display of a signal that is slightly distorted by the measurement setup, for example.

The allowed values range from -100 GHz to 100 GHz. The default setting is 0 Hz.

SCPI command:

```
[SENSe:] FREQuency:OFFSet on page 565
```

Signal Tracking

Defines the settings for signal tracking. These settings are only available for spans > 0.

For more details see chapter 5.3.1.3, "Keeping the Center Frequency Stable - Signal Tracking", on page 178.

Signal Tracking State ← Signal Tracking

Activates or deactivates signal tracking. This function is only available for spans > 0.

If activated, after each sweep, the center frequency is set to the maximum level of the specified trace found within the searched bandwidth.

SCPI command:

CALCulate: MARKer: FUNCtion: STRack[:STATe] on page 567

Frequency and Span Configuration

Tracking Bandwidth ← Signal Tracking

Defines the search bandwidth for signal tracking around the center frequency.

SCPI command:

CALCulate: MARKer: FUNCtion: STRack: BANDwidth on page 567

Tracking Threshold ← Signal Tracking

Defines the threshold value for signal tracking. If the signal level does not pass the threshold, the center frequency is not changed.

SCPI command:

CALCulate: MARKer: FUNCtion: STRack: THReshold on page 567

Signal Track Trace ← Signal Tracking

Defines the trace to be tracked.

SCPI command:

CALCulate: MARKer: FUNCtion: STRack: TRACe on page 568

5.3.3 How To Define the Frequency Range

The following step-by-step instructions demonstrate how to configure the frequency and span settings. For details on individual functions and settings see chapter 5.3.2, "Frequency and Span Settings", on page 179.

The remote commands required to perform these tasks are described in chapter 10.5.1, "Defining the Frequency and Span", on page 563.

To configure the frequency and span

Frequency and span settings can be configured via the "Frequency" dialog box. Signal tracking is configured in the "Signal Tracking" tab of this dialog box.

- 1. To display the "Frequency" dialog box, do one of the following:
 - Select "Frequency" from the "Overview".
 - Select the FREQ key and then the "Frequency Config" softkey.
 - Select the SPAN key and then the "Frequency Config" softkey.
- 2. Define the frequency range using one of the following methods:
 - Define the "Center frequency" and "Span".
 - Define the "Start frequency" and "Stop frequency".
 - To perform a measurement in the time domain, define the "Center frequency" and select the "Zero span" button.
 - To perform a measurement over the entire available frequency range, select the "Full span" button.
 - To return to the previously set frequency range, select the "Last span" button.

5.3.4 How to Move the Center Frequency through the Frequency Range

In some cases it may be useful to move the center frequency through a larger frequency range, for example from one harmonic to another.

- In the "Frequency" dialog box, define the "Center Frequency Stepsize". This is the size by which the center frequency is to be increased or decreased in each step. Enter a manual or relative value, or set the step size to the current center frequency or marker value. To move from one harmonic to the next, use the center frequency or marker value.
- 2. Select the "Center Frequency" dialog field.
- Use the arrow keys to move the center frequency in discrete steps through the available frequency range.

5.3.5 How to Keep the Center Frequency Stable

If the signal is slightly instable on the display but you want to keep the center frequency on the signal peak, the center frequency can be adjusted automatically using **signal tracking**.

- 1. In the "Frequency" dialog box, select the "Signal Tracking" tab.
- 2. Define the following settings:
 - "Signal Tracking Bandwidth": the frequency range around the center frequency to be tracked
 - "Signal Tracking Threshold": the minimum level the trace must reach to be detected as a maximum
 - "Signal Tracking Trace": the trace to be tracked
- 3. Activate signal tracking by selecting "State: ON".

After each sweep, the center frequency is set to the maximum signal found within the searched bandwidth. If no maximum signal above the defined threshold value is found in the searched bandwidth, the center frequency remains unchanged. The search bandwidth and the threshold value are shown in the diagram by red lines which are labeled as "TRK".

5.4 Amplitude and Vertical Axis Configuration

In the Spectrum application, measurement results usually consist of the measured signal levels (amplitudes) displayed on the vertical (y-)axis for the determined frequency spectrum or for the measurement time (horizontal, x-axis). The settings for the vertical axis, regarding amplitude and scaling, are described here.

•	Impact of the Vertical Axis Settings	185
•	Amplitude Settings	187
•	Scaling the Y-Axis	191
•	How to Optimize the Amplitude Display	192

5.4.1 Impact of the Vertical Axis Settings

Some background knowledge on the impact of the described settings is provided here for a better understanding of the required configuration.

•	Reference Level	.185
•	RF Attenuation	.185
•	Scaling	186

5.4.1.1 Reference Level

The reference level value is the maximum value the AD converter can handle without distortion of the measured value. Signal levels above this value will not be measured correctly, which is indicated by the "IFOVL" status display. The reference level should correspond with the maximum expected RF input level.



When determining the expected input level, consider that the power from *all* input signals contribute to the total power. The reference level must be higher than the total power from all signals.

The optimum reference level for the current measurement settings can be set automatically by the R&S FSW (see "Reference Level" on page 187).

The reference level determines the amplitude represented by the topmost grid line in the display. When you change the reference level, the measurement is not restarted; the results are merely shifted in the display. Only if the reference level changes due to a coupled RF attenuation (see "Attenuation Mode / Value" on page 189), the measurement is restarted.

In general, the R&S FSW measures the signal voltage at the RF input. The level display is calibrated in RMS values of an unmodulated sine wave signal. In the default state, the level is displayed at a power of 1 mW (= dBm). Via the known input impedance (50 Ω or 75 Ω , see "Impedance" on page 164), conversion to other units is possible.

5.4.1.2 RF Attenuation

The attenuation is meant to protect the input mixer from high RF input levels. The level at the input mixer is determined by the set RF attenuation according to the formula:

"level_{mixer} = level_{input} – RF attenuation"

The maximum mixer level allowed is -10 dBm. Mixer levels above this value may lead to incorrect measurement results, which is indicated by the "OVLD" status display. Further-

more, higher input levels may damage the instrument. Therefore, the required RF attenuation is determined automatically according to the reference level by default.

High attenuation levels also avoid intermodulation. On the other hand, attenuation must be compensated for by re-amplifying the signal levels after the mixer. Thus, high attenuation values cause the inherent noise (i.e the noise floor) to rise and the sensitivity of the analyzer decreases.

The sensitivity of a signal analyzer is directly influenced by the selected RF attenuation. The highest sensitivity is obtained at an RF attenuation of 0 dB. Each additional 10 dB step reduces the sensitivity by 10 dB, i.e. the displayed noise is increased by 10 dB. To measure a signal with an improved signal-to-noise ratio, decrease the RF attenuation.



For ideal sinusoidal signals, the displayed signal level is independent of the RF attenuation.

Depending on the type of measurement evaluation that is required, a compromise must be found between a low noise floor and high intermodulation levels, and protecting the instrument from high input levels. This is best done by letting the R&S FSW determine the optimum level automatically (see "Attenuation Mode / Value" on page 189).



Electronic attenuation

If option R&S FSW-B25 is installed, you can also activate an electronic attenuator. For details see "Using Electronic Attenuation (Option B25)" on page 189.

5.4.1.3 **Scaling**

In a linear display, the measurement values are distributed linearly throughout the grid. That means the entire range of measured values is divided by the number of rows in the grid (10) and each row corresponds to 1/10 of the total range. Linear scaling is useful to determine precise levels for a small range of values. However, if large and small values appear in the same display, it is difficult to determine individual values precisely or to distinguish values that are close together.

In a logarithmic display, smaller values are distributed amoung a much larger area of the display, while large values are condensed to a smaller area. Now it is much easier to distinguish several lower values, as they are spread over a wider area. Logarithmic scaling is useful when large ranges of values must be combined in one display. Logarithmic scaling is best applied to measurement values in logarithmic units (dB, dBm etc.).

In addition to linear or logarithmic scaling, the vertical axis can be set to display either absolute or relative values. Absolute values show the measured levels, while relative values show the difference between the measured level and the defined reference level. Relative values are indicated in percent for linear scaling, and in dB for logarithmic scaling.

5.4.2 Amplitude Settings

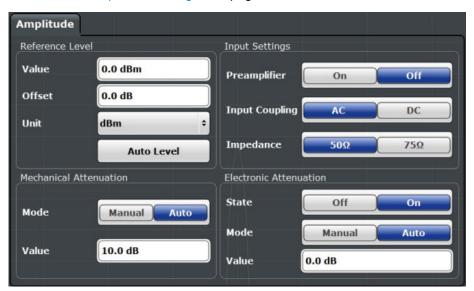
Amplitude settings determine how the R&S FSW must process or display the expected input power levels.

To configure the amplitude settings

Amplitude settings can be configured via the AMPT key or in the "Amplitude" dialog box.

- ► To display the "Amplitude" dialog box, do one of the following:
 - Select "Amplitude" from the "Overview".
 - Select "Input/Frontend" from the "Overview" and then switch to the "Amplitude" tab.
 - Select the AMPT key and then the "Amplitude Config" softkey.

The remote commands required to define these settings are described in chapter 10.5.3.1, "Amplitude Settings", on page 575.



Reference Level	187
L Shifting the Display (Offset)	188
L Unit.	
L Setting the Reference Level Automatically (Auto Level)	
RF Attenuation	189
L Attenuation Mode / Value	189
Using Electronic Attenuation (Option B25)	189
Input Settings	190
L Preamplifier (option B24)	
Noise cancellation	

Reference Level

Defines the expected maximum reference level. Signal levels above this value may not be measured correctly, which is indicated by the "IFOVL" status display.

The reference level is also used to scale power diagrams; the reference level is then used as the maximum on the y-axis.

Since the R&S FSW hardware is adapted according to this value, it is recommended that you set the reference level close above the expected maximum signal level to ensure an optimum measurement (no compression, good signal-to-noise ratio).

Note that the "Reference Level" value ignores the Shifting the Display (Offset). It is important to know the actual power level the R&S FSW must handle.

For details see chapter 5.4.1.1, "Reference Level", on page 185.

SCPI command:

DISPlay[:WINDow<n>]:TRACe:Y[:SCALe]:RLEVel on page 576

Shifting the Display (Offset) ← Reference Level

Defines an arithmetic level offset. This offset is added to the measured level irrespective of the selected unit. The scaling of the y-axis is changed accordingly.

Define an offset if the signal is attenuated or amplified before it is fed into the R&S FSW so the application shows correct power results. All displayed power level results will be shifted by this value.

Note, however, that the Reference Level value ignores the "Reference Level Offset". It is important to know the actual power level the R&S FSW must handle.

To determine the required offset, consider the external attenuation or gain applied to the input signal. A positive value indicates that an attenuation took place (R&S FSW increases the displayed power values), a negative value indicates an external gain (R&S FSW decreases the displayed power values).

The setting range is ±200 dB in 0.01 dB steps.

SCPI command:

DISPlay[:WINDow<n>]:TRACe:Y[:SCALe]:RLEVel:OFFSet on page 576

Unit ← Reference Level

The R&S FSW measures the signal voltage at the RF input. In the default state, the level is displayed at a power of 1 mW (= dBm). Via the known input impedance (50 Ω or 75 Ω , see "Impedance" on page 164), conversion to other units is possible. The following units are available and directly convertible:

- dBm
- dBmV
- dBµV
- dBµA
- dBpW
- Volt
- Ampere
- Watt

SCPI command:

INPut: IMPedance on page 597

CALCulate<n>:UNIT:POWer on page 575

Setting the Reference Level Automatically (Auto Level) ← Reference Level

Automatically determines the optimal reference level for the current input data. At the same time, the internal attenuators and the preamplifier are adjusted so the signal-to-noise ratio is optimized, while signal compression, clipping and overload conditions are minimized.

In order to do so, a level measurement is performed to determine the optimal reference level.

You can change the measurement time for the level measurement if necessary (see "Changing the Automatic Measurement Time (Meastime Manual)" on page 227).

SCPI command:

[SENSe:]ADJust:LEVel on page 595

RF Attenuation

Defines the attenuation applied to the RF input.

Attenuation Mode / Value ← RF Attenuation

The RF attenuation can be set automatically as a function of the selected reference level (Auto mode). This ensures that the optimum RF attenuation is always used. It is the default setting. By default and when Using Electronic Attenuation (Option B25) is not available, mechanical attenuation is applied.

In "Manual" mode, you can set the RF attenuation in 1 dB steps (down to 0 dB, also using the rotary knob). Other entries are rounded to the next integer value. The range is specified in the data sheet. If the defined reference level cannot be set for the defined RF attenuation, the reference level is adjusted accordingly and the warning "Limit reached" is displayed.

NOTICE! Risk of hardware damage due to high power levels. When decreasing the attenuation manually, ensure that the power level does not exceed the maximum level allowed at the RF input, as an overload may lead to hardware damage.

For details see chapter 5.4.1.2, "RF Attenuation", on page 185.

SCPI command:

INPut:ATTenuation on page 577
INPut:ATTenuation:AUTO on page 577

Using Electronic Attenuation (Option B25)

If option R&S FSW-B25 is installed, you can also activate an electronic attenuator.

In "Auto" mode, the settings are defined automatically; in "Manual" mode, you can define the mechanical and electronic attenuation separately.

Note: Electronic attenuation is not available for stop frequencies (or center frequencies in zero span) >13.6 GHz.

In "Auto" mode, RF attenuation is provided by the electronic attenuator as much as possible to reduce the amount of mechanical switching required. Mechanical attenuation may provide a better signal-to-noise ratio, however.

When you switch off electronic attenuation, the RF attenuation is automatically set to the same mode (auto/manual) as the electronic attenuation was set to. Thus, the RF attenuation may be set to automatic mode, and the full attenuation is provided by the mechanical attenuator, if possible.

Both the electronic and the mechanical attenuation can be varied in 1 dB steps. Other entries are rounded to the next lower integer value.

If the defined reference level cannot be set for the given attenuation, the reference level is adjusted accordingly and the warning "Limit reached" is displayed in the status bar.

SCPI command:

INPut:EATT:STATe on page 578
INPut:EATT:AUTO on page 578
INPut:EATT on page 578

Input Settings

Some input settings affect the measured amplitude of the signal, as well.

The parameters "Input Coupling" and "Impedance" are identical to those in the "Input" settings, see chapter 5.2.2, "Input Settings", on page 163.

Preamplifier (option B24) ← Input Settings

If option R&S FSW-B24 is installed, a preamplifier can be activated for the RF input signal.

For R&S FSW 26 models, the input signal is amplified by 30 dB if the preamplifier is activated.

For R&S FSW 8 or 13 models, the following settings are available:

"Off" Deactivates the preamplifier.

"15 dB" The RF input signal is amplified by about 15 dB.

"30 dB" The RF input signal is amplified by about 30 dB.

SCPI command:

INPut:GAIN:STATe on page 579
INPut:GAIN[:VALue] on page 579

Noise cancellation

The results can be corrected by the instrument's inherent noise, which increases the dynamic range.

In this case, a reference measurement of the instrument's inherent noise is carried out. The measured noise power is then subtracted from the power in the channel that is being analyzed (first active trace only).

The inherent noise of the instrument depends on the selected center frequency, resolution bandwidth and level setting. Therefore, the correction function is disabled whenever one of these parameters is changed. A disable message is displayed on the screen. To enable the correction function after changing one of these settings, activate it again. A new reference measurement is carried out.

Noise cancellation is also available in zero span.

Currently, noise cancellation is only available for the following trace detectors (see "Detector" on page 250):

- RMS
- Average
- Sample

Positive Peak

SCPI command:

[SENSe:] POWer:NCORrection on page 576

5.4.3 Scaling the Y-Axis

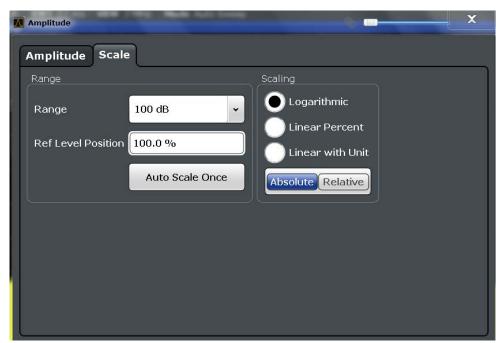
The individual scaling settings that affect the vertical axis are described here.

To configure the y-axis scaling settings

Vertical Axis settings can be configured via the AMPT key or in the "Amplitude" dialog box.

- ► To display the "Amplitude" dialog box, do one of the following:
 - Select "Amplitude" from the "Overview".
 - Select the AMPT key and then the "Scale Config" softkey.

The remote commands required to define these settings are described in chapter 10.5.3, "Configuring the Vertical Axis (Amplitude, Scaling)", on page 575.



Range	191
Ref Level Position	
Auto Scale Once	192
Scaling	192

Range

Defines the displayed y-axis range in dB (frequency domain) or Hz (time domain).

The default value is 100 dB or 500 kHz.

SCPI command:

```
DISPlay[:WINDow<n>]:TRACe:Y[:SCALe] on page 580
```

Ref Level Position

Defines the reference level position, i.e. the position of the maximum AD converter value on the level axis in %, where 0 % corresponds to the lower and 100 % to the upper limit of the diagram.

SCPI command:

```
DISPlay[:WINDow<n>]:TRACe:Y[:SCALe]:RPOSition on page 581
```

Auto Scale Once

Automatically determines the optimal range and reference level position to be displayed for the current measurement settings.

The display is only set once; it is not adapted further if the measurement settings are changed again.

SCPI command:

```
DISPlay[:WINDow<n>]:TRACe:Y[:SCALe]:AUTO ONCE on page 580
```

Scaling

Defines the scaling method for the y-axis.

For more information see chapter 5.4.1.3, "Scaling", on page 186.

"Logarithmic" Logarithmic scaling (only available for logarithmic units - dB...)

"Linear Unit" Linear scaling in the unit of the measured signal

"Linear Per- Linear scaling in percentages from 0 to 100

cent"

"Absolute" The labeling of the level lines refers to the absolute value of the refer-

ence level (not available for "Linear Percent")

"Relative" The scaling is in dB, relative to the reference level (only available for

logarithmic units - dB...). The upper line of the grid (reference level) is

always at 0 dB.

SCPI command:

```
DISPlay[:WINDow<n>]:TRACe:Y:SPACing on page 581
DISPlay[:WINDow<n>]:TRACe:Y[:SCALe]:MODE on page 580
```

5.4.4 How to Optimize the Amplitude Display

This section gives you some advice on how to optimize the display of the measured signal amplitudes depending on the required evaluation.

- 1. Perform a measurement with the default settings to get an impression of the values to be expected.
- 2. Use the "Auto Level" function (AUTO menu) to optimize the reference level.

3. Use the "Auto Scale" function (AUTO menu) to optimize the scaling.

4. To determine a precise level at a specific point in the signal:

- Reduce the "Range" of the y-axis to a small area around the required level. If necessary, change the "Ref Level Position" so the required range remains visible.
- Select "Linear Unit" scaling.

Now you can set a marker at the point in question and read the result.

5. To detect a spurious signal close to the noise floor:

- Set the "RF attenuation" to "Manual" mode and reduce the "Value" to lower the noise floor.
- Select "Relative Logarithmic" scaling.

Now you can determine if any spurious levels of a certain size are visible.

5.5 Bandwidth, Filter and Sweep Configuration

The basic bandwidth, filter and sweep settings that apply to most measurements are described here. These parameters define how the data is measured: how much data is collected internally and which filters are used.

5.5.1 Impact of the Bandwidth, Filter and Sweep Settings

The bandwidth, filter and sweep settings are closely related and interdependant. The values available for resolution bandwidth and video bandwidth depend on the selected filter type. In addition, these settings have an impact on other measurement parameters. The following equation shows the interdependency of these settings:

$T_{\text{sweepMIN}} = K*Span/RBW^2$

where K = Filter constant

By default, a Gaussian filter is used. The resolution bandwidth, the video bandwidth and the sweep time are set automatically according to the set span, and default coupling is used. Thus, the following settings are applied:

RBW = 100 * Span

VBW = RBW = 100 * Span

Sweep time = T_{min} for set Span, RBW, VBW

When defining the bandwidth and filter settings, consider the impact of the individual settings on the other settings and the measurement result, as described in more detail in the following sections.

•	Separating Signals by Selecting an Appropriate Resolution Bandwidth	194
	Smoothing the Trace Using the Video Bandwidth	
•	Coupling VBW and RBW	195
	Coupling Span and RBW	
•	How Data is Measured: the Sweep Type	196
	Which Data May Pass: Filter Types	
	How Long the Data is Measured: Sweep Time	
•	How Much Data is Measured: Sweep Points and Sweep Count	198
	How Often Data is Measured: Sweep Mode	

5.5.1.1 Separating Signals by Selecting an Appropriate Resolution Bandwidth

The resolution bandwidth defines the 3 dB bandwidth of the resolution filter to be used. An RF sinusoidal signal is displayed according to the passband characteristic of the resolution filter (RBW), i.e. the signal display reflects the shape of the filter.

A basic feature of a signal analyzer is being able to separate the spectral components of a mixture of signals. The resolution at which the individual components can be separated is determined by the resolution bandwidth. Selecting a resolution bandwidth that is too large may make it impossible to distinguish between spectral components, i.e. they are displayed as a single component. Smaller resolution bandwidths, however, increase the required measurement time.

Two signals with the same amplitude can be resolved if the resolution bandwidth is smaller than or equal to the frequency spacing of the signal. If the resolution bandwidth is equal to the frequency spacing, the spectrum display screen shows a level drop of 3 dB precisely in the center of the two signals. Decreasing the resolution bandwidth makes the level drop larger, which thus makes the individual signals clearer.

The highest sensitivity is obtained at the smallest bandwidth (1 Hz). If the bandwidth is increased, the reduction in sensitivity is proportional to the change in bandwidth. Increasing the bandwidth by a factor of 3 increases the displayed noise by approx. 5 dB (4.77 dB precisely). If the bandwidth is increased by a factor of 10, the displayed noise increases by a factor of 10, i.e. 10 dB.

If there are large level differences between signals, the resolution is determined by selectivity as well as by the resolution bandwidth that has been selected. The measure of selectivity used for signal analyzers is the ratio of the 60 dB bandwidth to the 3 dB bandwidth (= shape factor).

For the R&S FSW, the shape factor for bandwidths is < 5, i.e. the 60 dB bandwidth of the 30 kHz filter is <150 kHz.

The higher spectral resolution with smaller bandwidths is won by longer sweep times for the same span. The sweep time has to allow the resolution filters to settle during a sweep at all signal levels and frequencies to be displayed.

If the RBW is too large, signal parts that are very far away (e.g. from a different signal) are considered in the measurement and distort the results. The noise increases.

If the RBW is too small, parts of the signal are lost. As the displayed signal always reflects the shape of the filter, select a bandwidth large enough so the displayed signal reflects the entire shape of the filter.

5.5.1.2 Smoothing the Trace Using the Video Bandwidth

The video filters are responsible for smoothing the displayed trace. Using video bandwidths that are small compared to the resolution bandwidth, only the signal average is displayed and noise peaks and pulsed signals are repressed. If pulsed signals are to be measured, it is advisable to use a video bandwidth that is large compared to the resolution bandwidth (VBW = 10 x RBW) for the amplitudes of pulses to be measured correctly.

The level of a sine wave signal is not influenced by the video bandwidth. A sine wave signal can therefore be freed from noise by using a video bandwidth that is small compared with the resolution bandwidth, and thus be measured more accurately.



RMS/Average detector and VBW

If an RMS or average detector is used, the video bandwidth in the hardware is bypassed. Thus, duplicate trace averaging with small VBWs and RMS or average detector no longer occurs. However, the VBW is still considered when calculating the sweep time. This leads to a longer sweep time for small VBW values. Thus, you can reduce the VBW value to achieve more stable trace curves even when using an RMS or average detector. Normally, if the RMS or average detector is used the sweep time should be increased to get more stable traces.

5.5.1.3 Coupling VBW and RBW

The video bandwidth can be coupled to the resolution bandwidth automatically. In this case, if the resolution bandwidth is changed, the video bandwidth is automatically adjusted

Coupling is recommended if a minimum sweep time is required for a selected resolution bandwidth. Narrow video bandwidths require longer sweep times due to the longer settling time. Wide bandwidths reduce the signal/noise ratio.

Table 5-1: Ove	erview of RBW/VBV	/ ratios and rec	ommendations	for use
Table 3-1. Ove		i iauos anu iec	Ullilliellualiulis	iui use

Ratio RBW/VBW	Recommendation for use
1/1	Recommended for sinusoidal signals This is the default setting for automatic coupling.
0.1	Recommended when the amplitudes of pulsed signals are to be measured correctly. The IF filter is exclusively responsible for the pulse shape. No additional evaluation is performed by the video filter.
10	Recommended to suppress noise and pulsed signals in the video domain.
Manually set (0.001 to 1000)	Recommended for other measurement requirements

5.5.1.4 Coupling Span and RBW

The resolution bandwidth can be coupled to the span setting, either by a manually defined factor or automatically. If the span is changed, the resolution bandwidth is automatically adjusted. The automatic coupling adapts the resolution bandwidth to the currently set

frequency span/100. The 6 dB bandwidths 200 Hz, 9 kHz and 120 kHz and the available channel filters are not changed by the coupling.

With a span/RBW ratio of 100 and a screen resolution of 1000 pixels, each frequency in the spectrum is displayed by 10 pixels. A span/RBW ratio of 1000 provides the highest resolution.

A higher span/RBW ratio (i.e. low RBW values and large frequency spans), however, results in large amounts of data.

5.5.1.5 How Data is Measured: the Sweep Type

In a standard analog **frequency sweep**, the local oscillator of the analyzer sweeps the input data quasi analog from the start to the stop frequency to determine the frequency spectrum.

Alternatively, the analyzer can sample signal levels at a defined frequency and transform the data by Fast Fourier Transformation (**FFT sweep**). This measurement method provides very precise results without spurious effects. However, the calculations add to the overall measurement time, so that measurements with long sweep times and large numbers of sweep points may take longer than a common frequency sweep.

By default (Auto mode), the R&S FSW automatically uses the optimal sweep type depending on the current measurement settings.



Restrictions for FFT mode

FFT mode is not available when using 5-Pole filters, Channel filters or RRC filters, or the Quasi peak detector. In this case, sweep mode is used.

FFT Filter Mode

In order to convert a signal in the time domain to a spectrum of frequencies (e.g. in FFT sweep mode), FFT analysis is performed. Several analysis steps are required to cover the entire span. The partial span which is covered by one FFT analysis is defined by the FFT filter. Narrow filters provide a better frequency resolution. On the other hand, the narrower the filter, the more steps are required to cover the entire span, thus increasing analysis time.

This allows you to perform measurements near a carrier with a reduced reference level due to a narrower analog prefilter.

5.5.1.6 Which Data May Pass: Filter Types

While the filter is irrelevant when measuring individual narrowband signals (as long as the signal remains within the RBW), the measurement result for broadband signals is very dependant on the selected filter type and its shape. If the filter is too narrow, the signal is distorted by the filter. If the filter is too wide, multiple signals can no longer be distinguished. Generally, the smaller the filter width and the steeper its edges, the longer the settling time and thus the longer the sweep time must be.

All resolution bandwidths are realized with digital filters. Normal (3dB) Gaussian filters are set by default. Some communication standards require different filters.



FFT Filters

FFT filters are not supported as resolution or video filters in the R&S FSW. However, when FFT sweeps are performed (Sweep type = FFT, see chapter 5.5.1.5, "How Data is Measured: the Sweep Type", on page 196), FFT filters are used. The "FFT Filter Mode" setting refers to the filter bandwidth in this sweep mode.

For a list of available filter types, see chapter 5.5.3, "Reference: List of Available RRC and Channel Filters", on page 206.

Normal (3dB) Gaussian filters

Gaussian filters provide a good compromise between steep edges and a short settling time. This filter is suitable for most measurement tasks and is used by default.

The available Gaussian (3dB) sweep filters are listed in the R&S FSW data sheet.

Channel filters

Channel filters are fairly steep but require a long settling time; they are useful for pulse measurements in the time domain.

RRC filters

Root raised cosine filters are similar in shape to channel filters and are required by some measurement standards.

5-Pole filters

5-Pole filters are very broad and allow for a large bandwidth to pass.

5.5.1.7 How Long the Data is Measured: Sweep Time

Each filter has a settling time that must be awaited in order to obtain correct results. Since the resolution bandwidth and video bandwidth define the filter, the smaller of the two determines the minimum sweep time required for the measurement. Allowed values depend on the ratio of span to RBW and RBW to VBW.

If the selected sweep time is too short for the selected bandwidth and span, level measurement errors will occur. In this case, the R&S FSW displays the error message "Sweep time too low" and marks the indicated sweep time with a red bullet. Furthermore, a status bit indicates an error (see "STATus:QUEStionable:TIMe Register" on page 409).

The sweep time can be coupled to the span (not zero span), video bandwidth (VBW) and resolution bandwidth (RBW) automatically. If the span, resolution bandwidth or video bandwidth is changed, the sweep time is automatically adjusted.

5.5.1.8 How Much Data is Measured: Sweep Points and Sweep Count

By default, 1001 data points are determined in a single sweep. During the next sweep, 1001 new data points are collected, and so on. The number of **sweep points** defines how much of the entire span is covered by a single data point. By increasing the number of sweep points you can increase the reliability of the individual data points and thus the accuracy of the analyzed results. However, these data points are all stored on the instrument, occupying a large amount of memory, and each sweep point increases the overall measurement time. Up to 200 000 points can be swept at once.

The number of sweeps to be performed in single sweep mode is defined by the "Sweep Count". Values from 0 to 32767 are allowed. If the values 0 or 1 are set, one sweep is performed. The sweep count is applied to all the traces in a diagram.

If the trace configurations "Average", "Max Hold" or "Min Hold" are set, the "sweep/average count" also determines the number of averaging or maximum search procedures (see chapter 6.3.1.2, "Analyzing Several Traces - Trace Mode", on page 239).

For details on how the number of sweep points and the sweep count affect the trace results on the screen, see chapter 6.3.1.1, "Mapping Samples to Sweep Points with the Trace Detector", on page 237.

5.5.1.9 How Often Data is Measured: Sweep Mode

How often the spectrum is swept depends on the sweep mode. Either a certain number of sweeps can be defined ("Sweep Count") which are performed in "Single Sweep" mode, or the sweep is repeated continuously ("Continuous Sweep" mode).

By default, the data is collected for the specified number of sweeps and the corresponding trace is displayed. When the next sweep is started, the previous trace is deleted.

However, the data from a single sweep run can also be retained and displayed together with the new data ("Continue Single Sweep" mode). This is particularly of interest when using the trace configurations "Average" or "Max Hold" to take previously recorded measurements into account for averaging/maximum search (see chapter 6.3.1.2, "Analyzing Several Traces - Trace Mode", on page 239).

5.5.2 Bandwidth, Filter and Sweep Settings

To configure the bandwidth, filter and sweep

Bandwidth and filter settings can be configured via the "Bandwidth" tab of the "Bandwidth" dialog box.

Sweep settings can be configured in the Sweep dialog box or via the "Sweep" tab of the "Bandwidth" dialog box.

- 1. To display the "Bandwidth" dialog box, do one of the following:
 - Select "Bandwidth" from the "Overview".
 - Select the BW key and then the "Bandwidth Config" softkey.
 - Select the SWEEP key and then the "Sweep Config" softkey.

- 2. To display the "Sweep" dialog box, do one of the following:
 - Select "Bandwidth" from the "Overview" and switch to the "Sweep" tab in the "Bandwidth" dialog box.
 - Select the SWEEP key and then the "Sweep Config" softkey.

The remote commands required to define these settings are described in chapter 10.5.2, "Configuring Bandwidth and Sweep Settings", on page 568.

How to perform a basic sweep measurement is described in chapter 4.12.1, "How to Perform a Basic Sweep Measurement", on page 154.



Fig. 5-3: Bandwidth dialog box

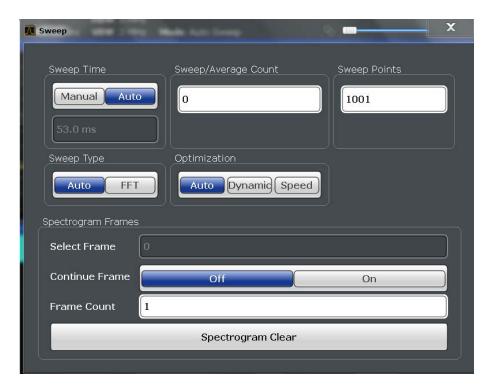


Fig. 5-4: Sweep dialog box for spectrogram display

RBW	∠00
VBW	201
Sweep Time	201
Span/RBW	202
RBW/VBW	202
Filter Type	202
Default Coupling	202
Sweep/Average Count	
Sweep Points	203
Optimization	203
Sweep Type	203
Single Sweep/ RUN SINGLE	
Continuous Sweep/RUN CONT	
Continue Single Sweep	205
Spectrogram Frames	205
L Select frame	205
L Continue Frame	205
L Frame Count	205
L Clear Spectrogram	206

RBW

Defines the resolution bandwidth automatically or manually.

For more information see chapter 5.5.1.1, "Separating Signals by Selecting an Appropriate Resolution Bandwidth", on page 194.

200

"Auto" Couples the resolution bandwidth to the selected span (for span > 0).

If the span is changed, the resolution bandwidth is automatically adjus-

ted.

"Manual" For manual mode, define the bandwidth value. The available resolution

bandwidths are specified in the data sheet. Numeric input is always

rounded to the nearest possible bandwidth.

If the resolution bandwidth is defined manually, a green bullet is dis-

played next to the "RBW" display in the channel bar.

SCPI command:

```
[SENSe:]BANDwidth|BWIDth[:RESolution] on page 568
[SENSe:]BANDwidth|BWIDth[:RESolution]:AUTO on page 569
```

VRW

Defines the video bandwidth automatically or manually.

For more information see chapter 5.5.1.2, "Smoothing the Trace Using the Video Bandwidth", on page 195.

"Auto" The video bandwidth is coupled to the resolution bandwidth. If the res-

olution bandwidth is changed, the video bandwidth is automatically

adjusted.

"Manual" For manual mode, define the bandwidth value. The available video

bandwidths are specified in the data sheet. Numeric input is always

rounded to the nearest possible bandwidth.

If the video bandwidth is defined manually, a green bullet is displayed

next to the "VBW" display in the channel bar.

SCPI command:

```
[SENSe:]BANDwidth|BWIDth:VIDeo:AUTO on page 570 [SENSe:]BANDwidth|BWIDth:VIDeo on page 570
```

Sweep Time

Defines the duration of a single sweep, during which the defined number of sweep points are measured. The sweep time can be defined automatically or manually.

The allowed sweep times depend on the device model; refer to the data sheet.

For more information see chapter 5.5.1.7, "How Long the Data is Measured: Sweep Time", on page 197.

"Auto" The sweep time is coupled to the span (not zero span), video bandwidth

(VBW) and resolution bandwidth (RBW). If the span, resolution bandwidth or video bandwidth is changed, the sweep time is automatically

adjusted.

"Manual" For manual mode, define the sweep time. Allowed values depend on

the ratio of span to RBW and RBW to VBW. For details refer to the data sheet. Numeric input is always rounded to the nearest possible sweep

time.

SCPI command:

```
[SENSe:]SWEep:TIME:AUTO on page 573 [SENSe:]SWEep:TIME on page 573
```

Span/RBW

Sets the coupling ratio if RBW is set to auto mode.

For more information see chapter 5.5.1.4, "Coupling Span and RBW", on page 195.

"Auto [100]" "resolution bandwidth = span/100"

This coupling ratio is the default setting of the R&S FSW.

"Manual" The coupling ratio is defined manually.

The span/resolution bandwidth ratio can be set in the range from 1 to

10000.

SCPI command:

[SENSe:]BANDwidth|BWIDth[:RESolution]:RATio on page 569

RBW/VBW

Sets the coupling ratio between the resolution bandwidth and the video bandwidth.

This setting is only effective if VBW is set to auto mode.

For more information see chapter 5.5.1.3, "Coupling VBW and RBW", on page 195.

"Sine [1/1]" "video bandwidth = resolution bandwidth"

This is the default setting for the coupling ratio RBW/VBW and is rec-

ommended if sinusoidal signals are to be measured.

"Pulse [.1]" "video bandwidth = 10 × resolution bandwidth"

or

"video bandwidth = 10 MHz (= max. VBW)"

Recommended for pulse signals

"Noise [10]" "video bandwidth = resolution bandwidth/10"

Recommended for noise measurements

"Manual" The coupling ratio is defined manually.

The RBW/VBW ratio can be set in the range of 0.001 to 1000.

SCPI command:

```
[SENSe:]BANDwidth|BWIDth:VIDeo:AUTO on page 570 [SENSe:]BANDwidth|BWIDth:VIDeo:RATio on page 570
```

Filter Type

Defines the filter type.

The following filter types are available:

- Normal (3dB)
- Channel
- RRC
- 5-Pole (not available for sweep type "FFT")

For more information see chapter 5.5.1.6, "Which Data May Pass: Filter Types", on page 196.

SCPI command:

```
[SENSe:]BANDwidth|BWIDth[:RESolution]:TYPE on page 569
```

Default Coupling

Sets all coupled functions to the default state ("AUTO"). In addition, the ratio "RBW/VBW" is set to "SINE [1/1]" and the ratio "SPAN/RBW" to 100.

For more information see chapter 5.5.1.3, "Coupling VBW and RBW", on page 195.

SCPI command:

```
[SENSe:]BANDwidth|BWIDth[:RESolution]:AUTO on page 569
[SENSe:]BANDwidth|BWIDth:VIDeo:AUTO on page 570
[SENSe:]SWEep:TIME:AUTO on page 573
```

Sweep/Average Count

Defines the number of sweeps to be performed in the single sweep mode. Values from 0 to 200000 are allowed. If the values 0 or 1 are set, one sweep is performed. The sweep count is applied to all the traces in all diagrams.

If the trace configurations "Average", "Max Hold" or "Min Hold" are set, this value also determines the number of averaging or maximum search procedures.

In continuous sweep mode, if sweep count = 0 (default), averaging is performed over 10 sweeps. For sweep count =1, no averaging, maxhold or minhold operations are performed.

For more information see chapter 5.5.1.8, "How Much Data is Measured: Sweep Points and Sweep Count", on page 198.

For spectrogram displays, the sweep count determines how many sweeps are combined in one frame in the spectrogram, i.e. how many sweeps the R&S FSW performs to plot one trace in the spectrogram result display. For more details see "Time Frames" on page 244.

SCPI command:

```
[SENSe:]SWEep:COUNt on page 571
[SENSe:]AVERage<n>:COUNt on page 615
```

Sweep Points

Defines the number of measured values to be collected during one sweep.

For details see chapter 5.5.1.8, "How Much Data is Measured: Sweep Points and Sweep Count", on page 198.

All values from 101 to 200 000 can be set. The default value is 1001 sweep points.

SCPI command:

```
[SENSe:]SWEep:POINts on page 572
```

Optimization

Defines the filter mode to be used for FFT sweep mode by defining the partial span size. The partial span is the span which is covered by one FFT analysis.

"Auto" Automatically applies the sweep optimization mode that is best for the

current measurement.

"Dynamic" Optimizes the sweep mode for a large dynamic range.

"Speed" Optimizes the sweep mode for high performance.

SCPI command:

```
[SENSe:] SWEep:OPTimize on page 572
```

Sweep Type

Defines the sweep type.

"Auto" Automatically sets the fastest available sweep type for the current mea-

surement (Frequency or FFT). Auto mode is set by default.

"FFT" The FFT sweep samples on a defined frequency value and transforms

it to the spectrum by fast Fourier transformation (FFT) (see also "Opti-

mization" on page 203).

FFT is not available when using 5-Pole filters, Channel filters or RRC filters, or when using the Quasi peak detector. In this case, frequency

sweep is used.

SCPI command:

[SENSe:] SWEep:TYPE on page 573

Single Sweep/ RUN SINGLE

After triggering, starts the number of sweeps set in "Sweep Count". The measurement stops after the defined number of sweeps has been performed.

While the measurement is running, the "Single Sweep" softkey and the RUN SINGLE key are highlighted. The running measurement can be aborted by selecting the highlighted softkey or key again.

Note: Sequencer. If the Sequencer is active, the "Single Sweep" softkey only controls the sweep mode for the currently selected channel; however, the sweep mode only has an effect the next time the Sequencer activates that channel, and only for a channel-defined sequence. In this case, a channel in single sweep mode is swept only once by the Sequencer.

Furthermore, the RUN SINGLE key on the front panel controls the Sequencer, not individual sweeps. RUN SINGLE starts the Sequencer in single mode.

If the Sequencer is off, only the evaluation for the currently displayed measurement channel is updated.

For details on the Sequencer, see chapter 3.5.1, "The Sequencer Concept", on page 26.

SCPI command:

INITiate[:IMMediate] on page 461

Continuous Sweep/RUN CONT

After triggering, starts the sweep and repeats it continuously until stopped. This is the default setting.

While the measurement is running, the "Continuous Sweep" softkey and the RUN CONT key are highlighted. The running measurement can be aborted by selecting the highlighted softkey or key again. The results are not deleted until a new measurement is started.

Note: Sequencer. If the Sequencer is active, the "Continuous Sweep" softkey only controls the sweep mode for the currently selected channel; however, the sweep mode only has an effect the next time the Sequencer activates that channel, and only for a channel-defined sequence. In this case, a channel in continuous sweep mode is swept repeatedly. Furthermore, the RUN CONT key on the front panel controls the Sequencer, not individual sweeps. RUN CONT starts the Sequencer in continuous mode.

For details on the Sequencer, see chapter 3.5.1, "The Sequencer Concept", on page 26.

SCPI command:

INITiate: CONTinuous on page 460

Continue Single Sweep

After triggering, repeats the number of sweeps set in "Sweep Count", without deleting the trace of the last measurement.

While the measurement is running, the "Continue Single Sweep" softkey and the RUN SINGLE key are highlighted. The running measurement can be aborted by selecting the highlighted softkey or key again.

SCPI command:

INITiate: CONMeas on page 459

Spectrogram Frames

These settings are only available if spectrogram display is active (see chapter 6.3.3.2, "How to Display and Configure a Spectrogram", on page 260).

Select frame ← Spectrogram Frames

Selects a specific frame and loads the corresponding trace from the memory.

Note that activating a marker or changing the position of the active marker automatically selects the frame that belongs to that marker.

This function is available in single sweep mode or if the sweep is stopped.

The most recent frame is number 0, all previous frames have a negative number.

For more information see "Time Frames" on page 244.

SCPI command:

CALCulate:SGRam:FRAMe:SELect on page 619

Continue Frame ← Spectrogram Frames

Determines whether the results of the previous sweeps are included in the analysis of the next sweeps for trace modes "Max Hold", "Min Hold", and "Average".

This function is available in single sweep mode only.

On

When the average or peak values are determined for the new sweep, the results of the previous sweeps in the spectrogram are also taken into account.

Off

The average or peak values are determined from the results of the newly swept frames only.

SCPI command:

CALCulate: SGRam: CONT on page 618

Frame Count ← Spectrogram Frames

Defines the number of frames to be captured in a single sweep.

Thus, the frame count defines the number of traces the R&S FSW plots in the spectrogram result display in a single sweep. The maximum number of possible frames depends on the history depth (see "History Depth" on page 256).

The sweep count, on the other hand, determines how many sweeps are combined in one frame in the spectrogram, i.e. how many sweeps the R&S FSW performs to plot one trace in the spectrogram result display (see "Sweep/Average Count" on page 203).

This softkey is available in single sweep mode.

For more details see "Time Frames" on page 244.

SCPI command:

CALCulate:SGRam:FRAMe:COUNt on page 618

Clear Spectrogram ← Spectrogram Frames

Resets the spectrogram result display and clears the history buffer.

SCPI command:

CALCulate:SGRam:CLEar[:IMMediate] on page 618

5.5.3 Reference: List of Available RRC and Channel Filters

For power measurement a number of especially steep-edged channel filters are available (see the following table). The indicated filter bandwidth is the 3 dB bandwidth. For RRC filters, the fixed roll-off factor (a) is also indicated.



The available Gaussian 3dB sweep filters are listed in the R&S FSW data sheet.

Table 5-2: Filter types

Filter Bandwidth	Filter Type	Application
100 Hz	CFILter	
200 Hz	CFILter	A0
300 Hz	CFILter	
500 Hz	CFILter	
1 kHz	CFILter	
1.5 kHz	CFILter	
2 kHz	CFILter	
2.4 kHz	CFILter	SSB
2.7 kHz	CFILter	
3 kHz	CFILter	
3.4 kHz	CFILter	
4 kHz	CFILter	DAB, Satellite
4.5 kHz	CFILter	
5 kHz	CFILter	

Filter Bandwidth	Filter Type	Application
6 kHz	CFILter	
6 kHz, a=0.2	RRC	APCO
8.5 kHz	CFILter	ETS300 113 (12.5 kHz channels)
9 kHz	CFILter	AM Radio
10 kHz	CFILter	
12.5 kHz	CFILter	CDMAone
14 kHz	CFILter	ETS300 113 (20 kHz channels)
15 kHz	CFILter	
16 kHz	CFILter	ETS300 113 (25 kHz channels)
18 kHz, a=0.35	RRC	TETRA
20 kHz	CFILter	
21 kHz	CFILter	PDC
24.3 kHz, a=0.35	RRC	IS 136
25 kHz	CFILter	
30 kHz	CFILter	CDPD, CDMAone
50 kHz	CFILter	
100 kHz	CFILter	
150 kHz	CFILter	FM Radio
192 kHz	CFILter	PHS
200 kHz	CFILter	
300 kHz	CFILter	
500 kHz	CFILter	J.83 (8-VSB DVB, USA)
1 MHz	CFILter	CDMAone
1.228 MHz	CFILter	CDMAone
1.28 MHz, a=0.22	RRC	
1.5 MHz	CFILter	DAB
2 MHz	CFILter	
3 MHz	CFILter	
3.75 MHz	CFILter	
3.84 MHz, a=0.22	RRC	W-CDMA 3GPP

Trigger and Gate Configuration

Filter Bandwidth	Filter Type	Application
4.096 MHz, a=0.22	RRC	W-CDMA NTT DOCoMo
5 MHz	CFILter	
10 MHz *)	CFILter	
20 MHz *)	CFILter	
28 MHz *)	CFILter	
40 MHz *)	CFILter	
80 MHz *)	CFILter	
*) These filters are only available with option	on R&S FSW-B8 (Res	olution Bandwidths > 10 MHz).

5.6 Trigger and Gate Configuration

Triggering means to capture the interesting part of the signal. Choosing the right trigger type and configuring all trigger settings correctly allows you to detect various incidents in your signals.

Gating allows you to restrict measurement analysis to the important part or parts of the signal, for example bursts.

•	Basics of Triggering and Gated Measurements	208
•	Trigger and Gate Settings	214
	How to Configure a Triggered and Gated Measurement	
	How to Output a Trigger Signal	

5.6.1 Basics of Triggering and Gated Measurements

Some background knowledge on triggering and gated measurements is provided here for a better understanding of the required configuration settings.

•	Triggered measurements2	.08
•	Gated Measurements	11
•	Determining the Parameters in Preview Mode	14

5.6.1.1 Triggered measurements

In a basic sweep measurement with default settings, the sweep is started immediately when you start the measurement, for example by pressing the RUN SINGLE key. However, sometimes you want the measurement to start only when a specific condition is fulfilled, for example a signal level is exceeded, or in certain time intervals. For these cases you can define a trigger for the measurement. In FFT sweep mode, the trigger defines when the data acquisition starts for the FFT conversion.

An "Offset" can be defined to delay the measurement after the trigger event, or to include data before the actual trigger event in time domain measurements (pre-trigger offset).

Trigger and Gate Configuration

For complex tasks, advanced trigger settings are available:

- Hysteresis to avoid unwanted trigger events caused by noise
- Holdoff to define exactly which trigger event will cause the trigger in a jittering signal

Trigger Source	209
Trigger Offset	209
Trigger Hysteresis	209
Trigger Drop-Out Time	210
Trigger Holdoff	210

Trigger Source

The trigger source defines which source must fulfill the condition that triggers the measurement. Basically, this can be:

- Time: the measurement is repeated in a regular interval
- Power: an input signal is checked for a defined power level
 The trigger signal can be an internal one (the input signal at one of various stages in
 the signal analysis process before or after the input mixer, after the video filter etc.)
 or it may come from an external device via one of the TRIGGER INPUT connectors
 on the front or rear panel of the instrument.

A power sensor can also provide an external trigger, see "Using a Power Sensor as an External Power Trigger" on page 169.

For details on the available trigger sources see "Trigger Source" on page 216.

Trigger Offset

An offset can be defined to delay the measurement after the trigger event, or to include data before the actual trigger event in time domain measurements (pre-trigger offset). Pre-trigger offsets are possible because the R&S FSW captures data continuously in the time domain, even before the trigger occurs.

See "Trigger Offset" on page 220.

Trigger Hysteresis

Setting a hysteresis for the trigger helps avoid unwanted trigger events caused by noise, for example. The hysteresis is a threshold to the trigger level that the signal must fall below on a rising slope or rise above on a falling slope before another trigger event occurs.

Example:

In the following example, the second possible trigger event is ignored as the signal does not exceed the hysteresis (threshold) before it reaches the trigger level again on the rising edge. On the falling edge, however, two trigger events occur as the signal exceeds the hysteresis before it falls to the trigger level the second time.

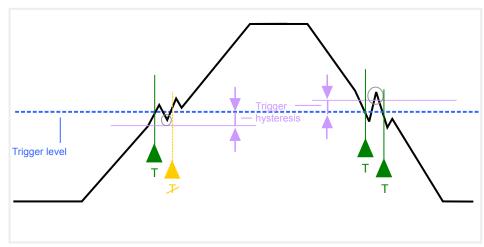


Fig. 5-5: Effects of the trigger hysteresis

See "Hysteresis" on page 220

Trigger Drop-Out Time

If a modulated signal is instable and produces occassional "drop-outs" during a burst, you can define a minimum duration that the input signal must stay below the trigger level before triggering again. This is called the "drop-out" time. Defining a dropout time helps you stabilize triggering when the analyzer is triggering on undesired events.

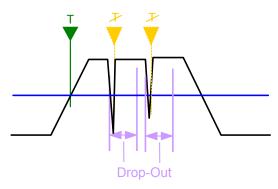


Fig. 5-6: Effect of the trigger drop-out time

See "Drop-Out Time" on page 219.

Trigger Holdoff

The trigger holdoff defines a waiting period before the next trigger after the current one will be recognized.

Trigger and Gate Configuration

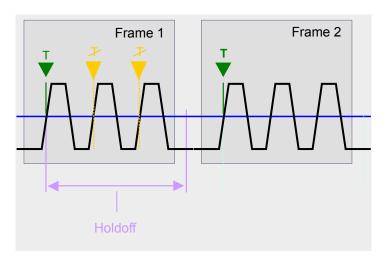


Fig. 5-7: Effect of the trigger holdoff

See "Trigger Holdoff" on page 220.

5.6.1.2 Gated Measurements

Like a gate provides an opening in a fence, a gated measurement lets data from the input signal pass in defined areas only. The *gate* controls exactly when data is included in the measurement results and when not. The gate is opened by the trigger source, which is also the gate source. Gates can be used in two different modes:

- Level: The gate opens and the measurement starts when a defined level in the gate source is exceeded and stops when the gate source drops below the "Gate Level".
 Using a pulsed gate signal in level mode, the following behaviour can be achieved: When the gate source signal is active, the input signal data is collected; when the gate signal is inactive, the input signal is ignored.
- **Edge:** The gate opens and the measurement starts when a defined level in the gate source is exceeded and stops when the defined "Gate Length" is reached.



The "Gate Mode" *Level* is not supported for R&S power sensors. The signal sent by these sensors merely reflects the instant the level is first exceeded, rather than a time period. However, only time periods can be used for gating in level mode. Thus, the trigger impulse from the sensors is not long enough for a fully gated measurement; the measurement cannot be completed. For details on power sensors see "Using a Power Sensor as an External Power Trigger" on page 169.

Additionally, a delay time can be defined so that the first few measurement points after the gate opening are ignored.

Trigger and Gate Configuration

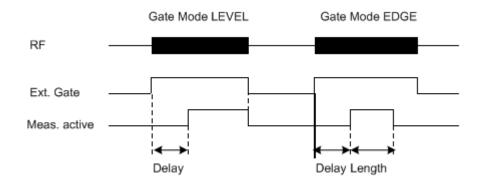


Fig. 5-8: Effects of Gate mode, Gate delay and Gate length

Example:

By using a gate in sweep mode and stopping the measurement while the gate signal is inactive, the spectrum for pulsed RF carriers can be displayed without the superposition of frequency components generated during switching. Similarly, the spectrum can also be analyzed for an inactive carrier. The sweep can be controlled by an external gate or by the internal power trigger.

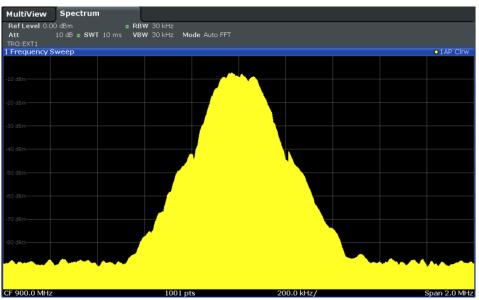


Fig. 5-9: GSM signal with GATE OFF

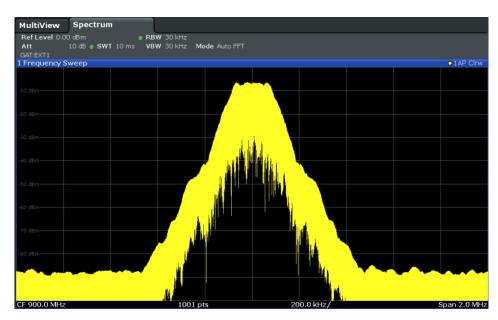


Fig. 5-10: GSM signal with GATE ON

Gated sweep operation is also possible for zero span measurements. This allows you to display level variations of individual slots, for instance in burst signals, versus time.

Trigger and Gate Configuration

To indicate that a gate is used for the sweep, "GAT" and the gate source is displayed in the channel bar.

5.6.1.3 Determining the Parameters in Preview Mode

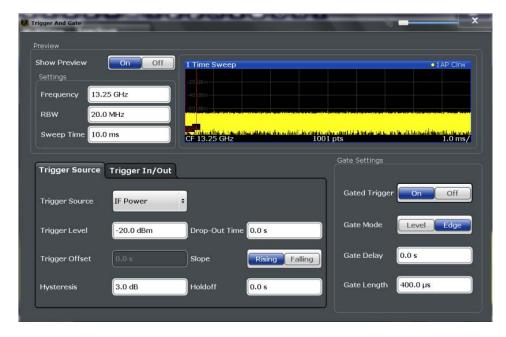
The preview mode allows you to try out trigger and gate settings before actually applying them to the current measurement. When the preview diagram shows the correct results, you can "Update the Main Diagram" and check the results in the background before closing the dialog box.

If preview mode is switched off, changes to the trigger and gate settings are applied to the measurement diagram directly.

The preview diagram displays a zero span measurement at the center frequency with the defined RBW and sweep time. This is useful to analyze bursts, for example, to determine the required gate settings. The main diagram remains unchanged concerning the zero span settings. Only the trigger and gate settings are applied to the measurement.

5.6.2 Trigger and Gate Settings

Trigger and gate settings can be configured via the TRIG key or in the "Trigger and Gate" dialog box, which is displayed when you select the "Trigger/Gate" button in the "Overview".



External triggers from one of the TRIGGER INPUT/OUTPUT connectors on the R&S FSW are configured in a separate tab of the dialog box.



For step-by-step instructions on configuring triggered and gated measurements, see chapter 5.6.3, "How to Configure a Triggered and Gated Measurement", on page 223.

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L Gate Delay	
L Gate Length	

Trigger and Gate Configuration

Preview

The preview diagram displays a zero span measurement at the center frequency with the defined RBW and sweep time.

For details see chapter 5.6.1.3, "Determining the Parameters in Preview Mode", on page 214.

Note: The zero span settings refer only to the preview diagram. The main diagram remains unchanged.

The trigger and gate settings are applied to the measurement when the dialog box is closed or "Update Main Diagram" is selected.

If preview mode is switched off, any changes to the settings in this dialog box are applied to the measurement diagram directly. In this case, the zero span settings for the preview diagram are not displayed.

For information on the zero span settings see:

- "Center" on page 180
- "RBW" on page 200
- "Sweep Time" on page 201

Frequency ← Preview

Defines the center frequency.

SCPI command:

[SENSe:] FREQuency: CENTer on page 563

RBW ← **Preview**

Defines the bandwidth value. The available resolution bandwidths are specified in the data sheet. Numeric input is always rounded to the nearest possible bandwidth.

SCPI command:

[SENSe:]BANDwidth|BWIDth[:RESolution] on page 568

Sweep Time ← Preview

Defines the sweep time. Allowed values depend on the ratio of span to RBW and RBW to VBW. For details refer to the data sheet. Numeric input is always rounded to the nearest possible sweep time.

SCPI command:

[SENSe:] SWEep:TIME on page 573

Trigger Settings

The trigger settings define the beginning of a measurement.

Trigger Source ← **Trigger Settings**

Defines the trigger source. If a trigger source other than "Free Run" is set, "TRG" is displayed in the channel bar and the trigger source is indicated.

For gated measurements, this setting also defines the gating source.

For more information see "Trigger Source" on page 209.

Note: When triggering or gating is activated, the squelch function is automatically disabled.

(See "Demodulating Marker Values and Providing Audio Output" on page 274).

SCPI command:

```
TRIGger[:SEQuence]:SOURce on page 585
[SENSe:]SWEep:EGATe:SOURce on page 588
```

Free Run ← Trigger Source ← Trigger Settings

No trigger source is considered. Data acquisition is started manually or automatically and continues until stopped explicitely.

In the Spectrum application, this is the default setting.

SCPI command:

```
TRIG:SOUR IMM, see TRIGger[:SEQuence]:SOURce on page 585
```

External Trigger 1/2/3 ← Trigger Source ← Trigger Settings

Data acquisition starts when the TTL signal fed into the specified input connector (on the front or rear panel) meets or exceeds the specified trigger level.

```
(See "Trigger Level" on page 219).
```

Note: The "External Trigger 1" softkey automatically selects the trigger signal from the TRIGGER INPUT connector on the front panel.

For details see the "Instrument Tour" chapter in the R&S FSW Getting Started manual.

"External Trigger 1"

Trigger signal from the TRIGGER INPUT connector on the front panel.

"External Trigger 2"

Trigger signal from the TRIGGER INPUT/OUTPUT connector on the front panel.

Note: Connector must be configured for "Input" in the "Outputs" configuration (see "Trigger 2/3" on page 167).

"External Trigger 3"

Trigger signal from the TRIGGER 3 INPUT/ OUTPUT connector on the rear panel.

Note: Connector must be configured for "Input" in the "Outputs" configuration (see "Trigger 2/3" on page 167).

SCPI command:

```
TRIG:SOUR EXT, TRIG:SOUR EXT2, TRIG:SOUR EXT3

See TRIGger[:SEQuence]:SOURce on page 585
```

SWE:EGAT:SOUR EXT for gated triggering, see [SENSe:]SWEep:EGATe:SOURce on page 588

Video ← Trigger Source ← Trigger Settings

Defines triggering by the video signal, i.e. the filtered and detected version of the input signal (the envelope of the IF signal), as displayed on the screen.

Define a trigger level from 0 % to 100 % of the diagram height. The absolute trigger level is indicated by a horizontal trigger line in the diagram, which you can also move graphically to change the trigger level.

Video mode is only available in the time domain.

SCPI command:

```
TRIG:SOUR VID, see TRIGger[:SEQuence]:SOURce on page 585

SWE:EGAT:SOUR VID for gated triggering, see [SENSe:]SWEep:EGATe:SOURce on page 588
```

IF Power ← Trigger Source ← Trigger Settings

The R&S FSW starts capturing data as soon as the trigger threshold is exceeded around the third intermediate frequency.

For frequency sweeps, the third IF represents the start frequency. The trigger bandwidth at the third IF depends on the RBW and sweep type.

For measurements on a fixed frequency (e.g. zero span or I/Q measurements), the third IF represents the center frequency.

The trigger threshold depends on the defined trigger level, as well as on the RF attenuation and preamplification. For details on available trigger levels and trigger bandwidths see the data sheet.

This trigger source is only available for RF input.

Note: Be aware that in auto sweep type mode, due to a possible change in sweep types, the trigger bandwidth may vary considerably for the same RBW setting.

SCPI command:

```
TRIG:SOUR IFP, see TRIGger[:SEQuence]:SOURce on page 585

SWE:EGAT:SOUR IFP for gated triggering, see [SENSe:]SWEep:EGATe:SOURce on page 588
```

RF Power ← Trigger Source ← Trigger Settings

Defines triggering of the measurement via signals which are outside the displayed measurement range.

For this purpose the instrument uses a level detector at the first intermediate frequency. The input signal must be in the frequency range between 500 MHz and 8 GHz. The resulting trigger level at the RF input depends on the RF attenuation and preamplification. For details on available trigger levels see the data sheet.

Note: If the input signal contains frequencies outside of this range (e.g. for fullspan measurements), the sweep may be aborted and a message indicating the allowed input frequencies is displayed in the status bar.

A "Trigger Offset", "Trigger Polarity" and "Trigger Holdoff" (to improve the trigger stability) can be defined for the RF trigger, but no "Hysteresis".

SCPI command:

```
TRIG:SOUR RFP, see TRIGger[:SEQuence]:SOURce on page 585

SWE:EGAT:SOUR RFP for gated triggering, see [SENSe:]SWEep:EGATe:SOURce on page 588
```

Power Sensor ← **Trigger Source** ← **Trigger Settings**

Uses an external power sensor as a trigger source. This option is only available if a power sensor is connected and configured.

(See chapter 5.2.4.3, "How to Work With a Power Sensor", on page 175.)

If a power sensor is selected as the trigger mode, the following softkeys are not available; these settings are configured in the "Power Sensor Configuration" dialog box (seechapter 5.2.4.2, "Power Sensor Settings", on page 170).

- "Trigger Level" on page 219
- "Slope" on page 220
- "Hysteresis" on page 220
- "Trigger Holdoff" on page 220

Note: For R&S power sensors, the "Gate Mode" *LvI* is not supported. The signal sent by these sensors merely reflects the instant the level is first exceeded, rather than a time period. However, only time periods can be used for gating in level mode. Thus, the trigger impulse from the sensors is not long enough for a fully gated measurement; the measurement cannot be completed.

SCPI command:

```
TRIG:SOUR PSE, see TRIGger[:SEQuence]:SOURce on page 585

SWE:EGAT:SOUR PSE for gated triggering, see [SENSe:]SWEep:EGATe:SOURce on page 588
```

Time ← Trigger Source ← Trigger Settings

Triggers in a specified repetition interval.

SCPI command:

```
TRIG:SOUR TIME, see TRIGger[:SEQuence]:SOURce on page 585
```

Trigger Level ← Trigger Settings

Defines the trigger level for the specified trigger source.

For gated measurements, this setting also defines the gate level.

For details on supported trigger levels, see the data sheet.

SCPI command:

```
TRIGger[:SEQuence]:LEVel:IFPower on page 584
TRIGger[:SEQuence]:LEVel:IQPower on page 584
TRIGger[:SEQuence]:LEVel[:EXTernal<port>] on page 583
TRIGger[:SEQuence]:LEVel:VIDeo on page 585
TRIGger[:SEQuence]:LEVel:RFPower on page 584
```

Repetition Interval ← Trigger Settings

Defines the repetition interval for a time trigger. The shortest interval is 2 ms.

The repetition interval should be set to the exact pulse period, burst length, frame length or other repetitive signal characteristic.

SCPI command:

```
TRIGger[:SEQuence]:TIME:RINTerval on page 586
```

Drop-Out Time ← Trigger Settings

Defines the time the input signal must stay below the trigger level before triggering again.

For more information on the drop-out time see "Trigger Drop-Out Time" on page 210.

SCPI command:

```
TRIGger[:SEQuence]:DTIMe on page 582
```

Trigger Offset ← Trigger Settings

Defines the time offset between the trigger event and the start of the sweep.

For more information see "Trigger Offset" on page 209.

offset > 0:	Start of the sweep is delayed	
offset < 0:	Sweep starts earlier (pre-trigger)	
	Only possible for zero span (e.g. I/Q Analyzer application) and gated trigger switched off	
	Maximum allowed range limited by the sweep time:	
	pretrigger _{max} = sweep time	

For the trigger sources "External" or "IF Power", a common input signal is used for both trigger and gate. Therefore, changes to the gate delay will affect the trigger delay ("Trigger Offset") as well.

For the "Time" trigger source, this function is not available.

SCPI command:

```
TRIGger[:SEQuence]:HOLDoff[:TIME] on page 582
```

Hysteresis ← Trigger Settings

Defines the distance in dB to the trigger level that the trigger source must exceed before a trigger event occurs. Settling a hysteresis avoids unwanted trigger events caused by noise oscillation around the trigger level.

This setting is only available for "IF Power" trigger sources. The range of the value is between 3 dB and 50 dB with a step width of 1 dB.

For more information see "Trigger Hysteresis" on page 209.

SCPI command:

```
TRIGger[:SEQuence]:IFPower:HYSTeresis on page 583
```

Trigger Holdoff ← Trigger Settings

Defines the minimum time (in seconds) that must pass between two trigger events. Trigger events that occur during the holdoff time are ignored.

For more information see "Trigger Holdoff" on page 210.

SCPI command:

```
TRIGger[:SEQuence]:IFPower:HOLDoff on page 583
```

Slope ← Trigger Settings

For all trigger sources except time you can define whether triggering occurs when the signal rises to the trigger level or falls down to it.

For gated measurements in "Edge" mode, the slope also defines whether the gate starts on a falling or rising edge.

SCPI command:

```
TRIGger[:SEQuence]:SLOPe on page 585
[SENSe:]SWEep:EGATe:POLarity on page 588
```

Trigger 2/3

Defines the usage of the variable TRIGGER INPUT/OUTPUT connectors, where:

"Trigger 2": TRIGGER INPUT/OUTPUT connector on the front panel

"Trigger 3": TRIGGER 3 INPUT/ OUTPUT connector on the rear panel

(Trigger 1 is INPUT only.)

Note: Providing trigger signals as output is described in detail in the R&S FSW User Manual.

"Input" The signal at the connector is used as an external trigger source by the

R&S FSW. No further trigger parameters are available for the connec-

tor.

"Output" The R&S FSW sends a trigger signal to the output connector to be used

by connected devices.

Further trigger parameters are available for the connector.

SCPI command:

OUTPut:TRIGger<port>:LEVel on page 590
OUTPut:TRIGger<port>:DIRection on page 589

Output Type ← Trigger 2/3

Type of signal to be sent to the output

"Device Trig- (Default) Sends a trigger when the R&S FSW triggers.

gered"

"Trigger Sends a (high level) trigger when the R&S FSW is in "Ready for trig-

Armed" ger" state.

This state is indicated by a status bit in the STATUS:OPERation register (bit 5), as well as by a low level signal at the AUX port (pin 9). For details see "STATUS:OPERation Register" on page 403 and the

R&S FSW Getting Started manual.

"User Defined" Sends a trigger when user selects "Send Trigger" button.

In this case, further parameters are available for the output signal.

SCPI command:

OUTPut: TRIGger<port>:OTYPe on page 590

Level ← Output Type ← Trigger 2/3

Defines whether a constant high (1) or low (0) signal is sent to the output connector.

SCPI command:

OUTPut: TRIGger<port>: LEVel on page 590

Pulse Length ← Output Type ← Trigger 2/3

Defines the length of the pulse sent as a trigger to the output connector.

SCPI command:

OUTPut:TRIGger<port>:PULSe:LENGth on page 591

$\textbf{Send Trigger} \leftarrow \textbf{Output Type} \leftarrow \textbf{Trigger 2/3}$

Sends a user-defined trigger to the output connector immediately. Note that the trigger pulse level is always opposite to the constant signal level defined by the output "Level" setting, e.g. for "Level = High", a constant high signal is output to the connector until the "Send Trigger" button is selected. Then, a low pulse is sent.

Which pulse level will be sent is indicated by a graphic on the button.

SCPI command:

OUTPut: TRIGger<port>: PULSe: IMMediate on page 591

Gate Settings

Gate settings define one or more extracts of the signal to be measured.

Gated Trigger ← **Gate Settings**

Switches gated triggering on or off.

If the gate is switched on, a gate signal applied to one of the "TRIGGER INPUT" connectors or the internal IF power detector controls the sweep of the analyzer.

Gate Mode ← Gate Settings

Sets the gate mode.

For more information see chapter 5.6.1.2, "Gated Measurements", on page 211

"Edge" The gate opens and the measurement starts when a defined level in

the gate source is exceeded and stops when the defined "Gate

Length" is reached.

"LvI" The gate opens and the measurement starts when a defined level in

the gate source is exceeded and stops when the gate source drops

below the "Trigger Level".

This mode is not supported when using R&S Power Sensors as power

triggers ("Trg/Gate Source" = Power Sensor or External).

SCPI command:

[SENSe:] SWEep:EGATe:TYPE on page 589

Gate Delay ← Gate Settings

Defines the delay time between the gate signal and the continuation of the measurement. The delay position on the time axis in relation to the sweep is indicated by a line labeled "GD".

As a common input signal is used for both trigger and gate when selecting the "External" or "IF Power" trigger source, changes to the gate delay will affect the trigger delay ("Trigger Offset") as well.

For more information see chapter 5.6.1.2, "Gated Measurements", on page 211 SCPI command:

```
[SENSe:] SWEep:EGATe:HOLDoff on page 587
```

Gate Length ← Gate Settings

Defines how long the gate is open when it is triggered. The gate length can only be set in the edge-triggered gate mode. In the level-triggered mode the gate length depends on the level of the gate signal.

The gate length in relation to the sweep is indicated by a line labeled "GL".

For more information see chapter 5.6.1.2, "Gated Measurements", on page 211

SCPI command:

[SENSe:] SWEep:EGATe:LENGth on page 588

5.6.3 How to Configure a Triggered and Gated Measurement

The following step-by-step instructions demonstrate how to configure a triggered and gated measurement manually. For remote operation see chapter 10.5.4, "Configuring Triggered and Gated Measurements", on page 581.

Trigger and gate settings are configured in the "Trigger and Gate" dialog box.

To display the "Trigger and Gate" dialog box, do one of the following:

- Select "Trigger/Gate" from the "Overview".
- Select the TRIG key and then the "Trigger/Gate Config" softkey.

The following tasks are described:

5.6.3.1	How to Determine the Required Trigger/Gate Parameters	223
5.6.3.2	How to Configure a Triggered Measurement	223
5.6.3.3	How to Configure a Gated Measurement	224

5.6.3.1 How to Determine the Required Trigger/Gate Parameters

- In the "Trigger and Gate" dialog box, switch on "Show Preview".
 A zero span measurement for the currently defined center frequency is displayed.
- 2. Set the "Frequency", "RBW" and "Sweep Time" such that the relevant part of the signal is displayed, for example a complete burst.
- 3. Determine the parameters you want to use to define the trigger and gate conditions from the preview diagram, for example:
 - the length of a burst or slot
 - the upper or lower power level of a pulse
 - the maximum noise level
 - the power level or time at which a certain incident occurs
- 4. Try out different trigger and gate settings as described in How to Configure a Triggered Measurement and How to Configure a Gated Measurement, then select "Update Main Diagram" to see the effect of the current settings on the main measurement in the background.
- 5. If the results are as expected, close the dialog box to keep the changes permanently. Otherwise, correct the settings as necessary.

5.6.3.2 How to Configure a Triggered Measurement

To define a time trigger:

- 1. In the "Trigger and Gate" dialog box, define the "Trigger Source" = "Time".
- 2. Define the "Repetition Interval": the time after which a new measurement is started.

To define an external trigger:

- Connect an external device that will provide the trigger signal to one of the TRIGGER INPUT connectors on the front or rear panel (for details see the R&S FSW "Getting Started" manual).
- In the "Trigger and Gate" dialog box, define the "Trigger Source" = "External".
- 3. If you are using one of the variable TRIGGER INPUT/OUTPUT connectors, you must define their use as input connectors. In the "Trigger In/Out" tab of the "Trigger and Gate" dialog box, set the corresponding trigger to "Input". (Note: Trigger 2 is on the front panel, Trigger 3 is on the rear panel.)
- 4. Configure the external trigger as described for the other power triggers.

To define a power trigger:

- 1. In the "Trigger and Gate" dialog box, define the "Trigger Source" = "IF Power" or "Video". Note that the video signal corresponds to the envelope of the IF signal: it has been processed by the resolution and video filters and the selected detector.
- 2. Define the "Trigger Level": the power level at which the measurement will start. For a "Video" trigger source you can move the level line graphically to define the level. If you define the value numerically, you must enter a percentage of the full diagram height as the level.
- 3. Define whether the signal must cross the trigger level on a falling or on a rising edge ("Slope") to trigger the measurement.
- 4. To start the measurement with a time delay, define a "Trigger Offset".
- 5. To reject triggers due to noise or jittering in the signal, define a "Hysteresis" that is larger than the expected noise or jittering. After the previous trigger, the signal must exceed this threshold before the next level crossing triggers a new measurement.
- 6. To skip multiple triggers in a burst, define a "Holdoff" time that must pass between two triggers. The holdoff time should be slightly larger than the burst.

5.6.3.3 How to Configure a Gated Measurement

- 1. Determine the required parameters as described in chapter 5.6.3.1, "How to Determine the Required Trigger/Gate Parameters", on page 223.
- The gate is opened by a trigger event, which must be based on a power source.
 Define the trigger as described in chapter 5.6.3.2, "How to Configure a Triggered Measurement", on page 223. As the "Trigger Source", use "IF Power", "Video" or "External".
- Define how long the gate is to remain open:
 To measure the signal as long as the trigger level is exceeded, for example for one or more pulses, define "Gate Mode" = "Level".

Adjusting Settings Automatically

To measure the signal for a certain time after a level is exceeded, for example during a burst:

- a) Define "Gate Mode" = "Edge".
- b) Define the time to measure for each gate: "Gate Length".
- 4. To open the gate with a time delay, for example to ignore an overshoot, define a "Gate Delay".
- 5. Select "Gated Trigger" = "On".

5.6.4 How to Output a Trigger Signal

Using one of the variable TRIGGER INPUT/OUTPUT connectors of the R&S FSW, the internal trigger signal can be output for use by other connected devices. For details on the connectors see the R&S FSW "Getting Started" manual.

To output a trigger to a connected device

- 1. In the "Trigger In/Out" tab of the "Trigger and Gate" dialog box, set the trigger to be used to "Output". (Note: Trigger 2 is output to the front panel connector, Trigger 3 is output to the rear panel connector.)
- Define whether the trigger signal is to be output automatically ("Output Type" =
 "Device triggered" or "Trigger Armed") or whether you want to start output manually
 ("Output Type" = "User-defined").
- 3. For manual output: Specify the constant signal level and the length of the trigger pulse to be output. Note that the level of the trigger pulse is opposite to the constant output "Level" setting (compare the graphic on the "Send Trigger" button).
- 4. Connect a device that will receive the trigger signal to the configured TRIGGER INPUT/OUTPUT connector.
- 5. Start a measurement and wait for an internal trigger, or select the "Send Trigger" button.

The configured trigger is output to the connector.

5.7 Adjusting Settings Automatically

Some settings can be adjusted by the R&S FSW automatically according to the current measurement settings. In order to do so, a measurement is performed. The duration of this measurement can be defined automatically or manually.

To activate the automatic adjustment of a setting, select the corresponding function in the AUTO SET menu or in the configuration dialog box for the setting, where available.

Adjusting Settings Automatically



MSRA operating mode

In MSRA operating mode, settings related to data acquisition can only be adjusted automatically for the MSRA Master, not the applications.



Adjusting settings automatically during triggered measurements

When you select an auto adjust function a measurement is performed to determine the optimal settings. If you select an auto adjust funtion for a triggered measurement, you are asked how the R&S FSW should behave:

- (default:) The measurement for adjustment waits for the next trigger
- The measurement for adjustment is performed without waiting for a trigger.

 The trigger source is temporarily set to "Free Run". After the measurement is completed, the original trigger source is restored. The trigger level is adjusted as follows:
 - For IF Power and RF Power triggers:
 Trigger Level = Reference Level 15 dB
 - For Video trigger:Trigger Level = 85 %

SCPI command:

[SENSe:]ADJust:CONFigure:TRIG on page 594

Adjusting all Determinable Settings Automatically (Auto All)	226
Adjusting the Center Frequency Automatically (Auto Freq)	226
Setting the Reference Level Automatically (Auto Level)	227
Resetting the Automatic Measurement Time (Meastime Auto)	227
Changing the Automatic Measurement Time (Meastime Manual)	
Upper Level Hysteresis	227
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Adjusting all Determinable Settings Automatically (Auto All)

Activates all automatic adjustment functions for the current measurement settings.

This includes:

- "Adjusting the Center Frequency Automatically (Auto Freq)" on page 226
- "Setting the Reference Level Automatically (Auto Level)" on page 189

SCPI command:

[SENSe:]ADJust:ALL on page 592

Adjusting the Center Frequency Automatically (Auto Freq)

This function adjusts the center frequency automatically.

The optimum center frequency can be determined as the highest frequency level in the frequency span. As this function uses the signal counter, it is intended for use with sinusoidal signals.

SCPI command:

[SENSe:]ADJust:FREQuency on page 594

Adjusting Settings Automatically

Setting the Reference Level Automatically (Auto Level)

Automatically determines the optimal reference level for the current input data. At the same time, the internal attenuators and the preamplifier are adjusted so the signal-to-noise ratio is optimized, while signal compression, clipping and overload conditions are minimized.

In order to do so, a level measurement is performed to determine the optimal reference level.

You can change the measurement time for the level measurement if necessary (see "Changing the Automatic Measurement Time (Meastime Manual)" on page 227).

SCPI command:

[SENSe:]ADJust:LEVel on page 595

Resetting the Automatic Measurement Time (Meastime Auto)

Resets the measurement duration for automatic settings to the default value.

(Spectrum application: 1 ms)

SCPI command:

[SENSe:] ADJust:CONFigure:DURation:MODE on page 593

Changing the Automatic Measurement Time (Meastime Manual)

This function allows you to change the measurement duration for automatic setting adjustments. Enter the value in seconds.

SCPI command:

```
[SENSe:]ADJust:CONFigure:DURation:MODE on page 593 [SENSe:]ADJust:CONFigure:DURation on page 592
```

Upper Level Hysteresis

When the reference level is adjusted automatically using the Setting the Reference Level Automatically (Auto Level) function, the internal attenuators and the preamplifier are also adjusted. In order to avoid frequent adaptation due to small changes in the input signal, you can define a hysteresis. This setting defines an upper threshold the signal must exceed (compared to the last measurement) before the reference level is adapted automatically.

SCPI command:

```
[SENSe:] ADJust:CONFigure:HYSTeresis:UPPer on page 594
```

Lower Level Hysteresis

When the reference level is adjusted automatically using the Setting the Reference Level Automatically (Auto Level) function, the internal attenuators and the preamplifier are also adjusted. In order to avoid frequent adaptation due to small changes in the input signal, you can define a hysteresis. This setting defines a lower threshold the signal must fall below (compared to the last measurement) before the reference level is adapted automatically.

SCPI command:

```
[SENSe:] ADJust:CONFigure:HYSTeresis:LOWer on page 593
```

6 Common Analysis and Display Functions

General methods and basic settings to display and analyze measurements, regardless of the operating mode, are described here. If you are performing a specific measurement task, using an operating mode other than Signal and Spectrum Analyzer mode, or an application other than the Spectrum application, be sure to check the specific application or mode description for settings and functions that may deviate from these common settings.



The analysis settings and functions are available via the "Analysis" dialog box, which is displayed when you select the "Analysis" button in the "Overview". Additional measurement-specific analysis functions may be available in separate tabs in the "Analysis" dialog box. These are described with the individual measurements.

See chapter 4, "Measurements", on page 30.

•	Result Display Configuration	228
	Zoomed Displays	
	Trace Configuration	
	Marker Usage	
	Display and Limit Lines	

6.1 Result Display Configuration

Measurement results can be evaluated in many different ways, for example graphically, as spectrograms, as summary tables, statistical evaluations etc. Thus, the result display is highly configurable to suit your specific requirements and optimize analysis. Here you can find out how to optimize the display for your measurement results.

Basic operations concerning the R&S FSW display, for example how to use the Smart-Grid, are described in the R&S FSW Getting Started manual.

General display settings that are usually configured during initial instrument setup, independantly of the current measurement, e.g. which items or colors are displayed on the screen, are described in chapter 8.4, "Display Settings", on page 363.

•	Basic Evaluation Methods	228
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6.1.1 Basic Evaluation Methods

Measurement results can be displayed and evaluated using various different methods, also at the same time. Depending on the currently selected measurement, in particular when using optional firmware applications, not all evaluation methods are available.

The evaluation methods described here are available for most measurements in the Spectrum application.

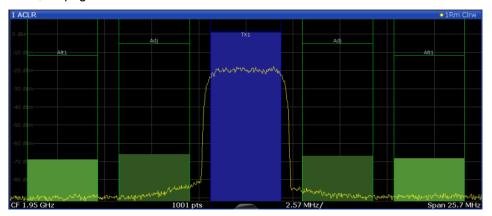
Result Display Configuration

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Diagram

Displays a basic level vs. frequency or level vs. time diagram of the measured data to evaluate the results graphically. This is the default evaluation method. Which data is displayed in the diagram depends on the "Trace" settings. Scaling for the y-axis can be configured.

See chapter 6.3, "Trace Configuration", on page 236 and chapter 5.4.3, "Scaling the Y-Axis", on page 191.



SCPI command:

LAY: ADD? '1', RIGH, DIAG, see LAYout: ADD[:WINDow]? on page 557

Marker Table

Displays a table with the current marker values for the active markers.

This table may be displayed automatically if configured accordingly (see "Marker Table Display" on page 279).



SCPI command:

LAY: ADD? '1', RIGH, MTAB, see LAYout: ADD[:WINDow]? on page 557

Marker Peak List

The marker peak list determines the frequencies and levels of peaks in the spectrum or time domain. How many peaks are displayed can be defined, as well as the sort order. In addition, the detected peaks can be indicated in the diagram. The peak list can also be exported to a file for analysis in an external application.

You can define search and sort criteria to influence the results of the analysis (see "Marker Search Settings" on page 280).

Result Display Configuration

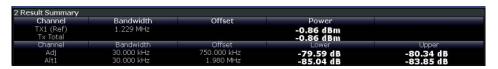


SCPI command:

LAY:ADD? '1', RIGH, PEAK, see LAYout:ADD[:WINDow]? on page 557

Result Summary

Result summaries provide the results of specific measurement functions in a table for numerical evaluation. The contents of the result summary vary depending on the selected measurement function. See the description of the individual measurement functions for details.



SCPI command:

LAY: ADD? '1', RIGH, RSUM, see LAYout: ADD[:WINDow]? on page 557

Spectrogram

A spectrogram shows how the spectral density of a signal varies over time. The x-axis shows the frequency or sweep time, the y-axis shows the measurement time. A third dimension, the power level, is indicated by different colors. Thus you can see how the strength of the signal varies over time for different frequencies.

The spectrogram display consists of two diagrams: the standard spectrum result display (upper diagram) and the spectrogram result display (lower diagram).

For details see chapter 6.3.1.6, "Spectrograms", on page 242.

SCPI command:

LAY: ADD? '1', RIGH, SGR, see LAYout: ADD[:WINDow]? on page 557

6.1.2 How to Select an Evaluation Method

All evaluation methods available for the currently selected measurement are displayed in the evaluation bar in SmartGrid mode. The same evaluation method can be displayed in several windows simultaneously.



For details on working with the SmartGrid see the R&S FSW Getting Started manual.

- To activate SmartGrid mode, do one of the following:
 - Select the "SmartGrid" icon from the toolbar.
 - Select the "Display Config" button in the configuration "Overview".

Select the "Display Config" softkey from the MEAS CONFIG menu.

The Smartgrid functions and the evaluation bar are displayed.

To close the SmartGrid mode and restore the previous softkey menu select the X "Close" icon in the righthand corner of the toolbar, or press any key on the front panel.

6.2 Zoomed Displays

You can zoom into the diagram to visualize the measurement results in greater detail. Using the touch screen or a mouse pointer you can easily define the area to be enlarged.



Zoom and the number of sweep points

Note that zooming is merely a visual tool, it does not change any measurement settings, such as the number of sweep points!

You should increase the number of sweep points before zooming, as otherwise the function has no real effect (see chapter 5.5.1.8, "How Much Data is Measured: Sweep Points and Sweep Count", on page 198).

6.2.1 Single Zoom Versus Multiple Zoom

Two different zoom modes are available: single zoom and multiple zoom. A single zoom replaces the current diagram by a new diagram which displays an enlarged extract of the trace. This function can be used repetitively until the required details are visible. In multiple zoom mode, you can enlarge up to four different areas of the trace simultaneously. An overview window indicates the zoom areas in the original trace, while the zoomed trace areas are displayed in individual windows. The zoom areas can be moved and resized any time. The zoom area that corresponds to the individual zoom display is indicated in the lower right corner, between the scrollbars.

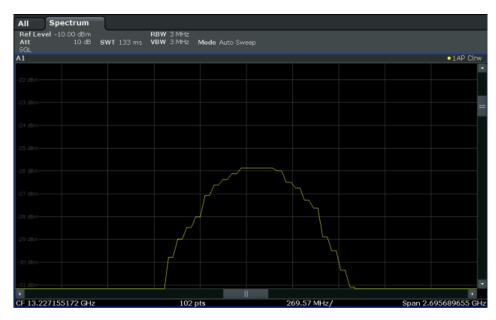


Fig. 6-1: Single zoom

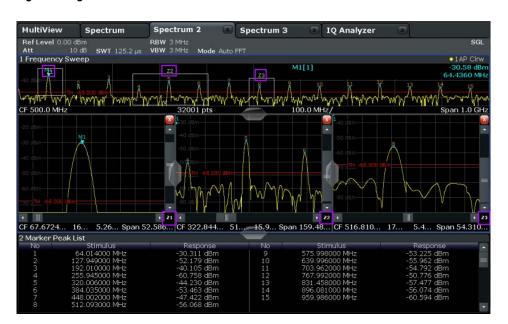


Fig. 6-2: Multiple zoom



Using the zoom area to restrict a peak search

The selected zoom area can be used to restrict the search range for a peak search, but only in single zoom mode (see "Using Zoom Limits" on page 283).

6.2.2 Zoom Functions

The zoom functions are only available from the toolbar.

Single Zoom	233
Multiple Zoom	233
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Single Zoom



A single zoom replaces the current diagram by a new diagram which displays an enlarged extract of the trace. This function can be used repetitively until the required details are visible.

SCPI command:

```
DISPlay[:WINDow<n>]:ZOOM:STATe on page 611
DISPlay[:WINDow<n>]:ZOOM:AREA on page 611
```

Multiple Zoom



In multiple zoom mode, you can enlarge several different areas of the trace simultaneously. An overview window indicates the zoom areas in the original trace, while the zoomed trace areas are displayed in individual windows. The zoom area that corresponds to the individual zoom display is indicated in the lower right corner, between the scrollbars.

SCPI command:

```
DISPlay[:WINDow<n>]:ZOOM:MULTiple<zoom>:STATe on page 612
DISPlay[:WINDow<n>]:ZOOM:MULTiple<zoom>:AREA on page 612
```

Restore Original Display



Restores the original display and closes all zoom windows.

SCPI command:

```
DISPlay[:WINDow<n>]:ZOOM:STATe on page 611 (single zoom)
DISPlay[:WINDow<n>]:ZOOM:MULTiple<zoom>:STATe on page 612 (for each multiple zoom window)
```

Deactivating Zoom (Selection mode)



Deactivates zoom mode; tapping the screen no longer invokes a zoom, but selects an object.

SCPI command:

```
DISPlay[:WINDow<n>]:ZOOM:STATe on page 611 (single zoom)
DISPlay[:WINDow<n>]:ZOOM:MULTiple<zoom>:STATe on page 612 (for each multiple zoom window)
```

6.2.3 How to Zoom Into a Diagram

The remote commands required to zoom into a display are described in chapter 10.6.1, "Zooming into the Display", on page 611.

The following tasks are described here:

- "To zoom into the diagram at one position" on page 234
- "To return to selection mode in the diagram" on page 235
- "To return to original display" on page 235
- "To zoom into multiple positions in the diagram" on page 235

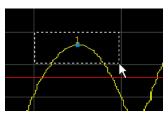
To zoom into the diagram at one position

1.

Click on the "Single Zoom" icon in the toolbar.

Zoom mode is activated.

2. Select the area in the diagram to be enlarged on the touch screen. The selected area is indicated by a dotted rectangle.



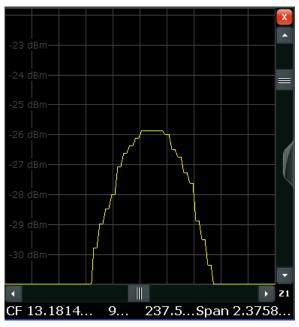
When you leave the touch screen, the diagram is replaced by the zoomed trace area.

3. Repeat these steps, if necessary, to enlarge the diagram further.



Scrolling in the zoomed display

You can scroll the diagram area to display the entire diagram using the scrollbars at the right and at the bottom of the diagram.



To return to selection mode in the diagram

While you are in zoom mode, touching the screen changes the zoom area. In order to select or move a trace or marker, you must switch back to selection mode:



Select the "Selection mode" icon in the toolbar.

To return to original display



Click on the "Zoom Off" icon in the toolbar.

The original trace display is restored. Zoom mode remains active, however. To switch off zoom mode and return to selection mode, select the "Selection mode" icon in the toolbar.

To zoom into multiple positions in the diagram

1.

Click on the "Multiple Zoom" icon in the toolbar.

Multiple zoom mode is activated.

- 2. Select the first area in the diagram to be enlarged on the touch screen. The selected area is indicated by a dotted rectangle.
 - When you have completed your selection, the original trace is shown in an overview diagram with the selected area indicated by a dotted rectangle. The zoomed trace area is displayed in a separate window (see figure 6-2.
- In the overview diagram, select the next area to be enlarged.
 The second zoom area is indicated in the overview diagram, and a second zoom window is displayed.
- 4. Repeat these steps, if necessary, to zoom into further trace areas (up to four).

To move or change zoom areas

In multiple zoom mode, you can change the size or position of the individual zoom areas easily at any time.

- 1. If necessary, switch off zoom mode and return to selection mode by selecting the "Selection mode" icon in the toolbar.
- 2. To resize a zoom area, tap directly **on** the corresponding frame in the overview window and drag the line to change the size of the frame.
 - To move a zoom area, tap **inside** the corresponding frame in the overview window and drag the frame to the new position.

The contents of the zoom windows are adapted accordingly.

6.3 Trace Configuration

A trace is a collection of measured data points. The trace settings determine how the measured data is analyzed and displayed on the screen.

•	Basics on Setting up Traces	236
	Trace Configuration	
	How to Configure Traces	

6.3.1 Basics on Setting up Traces

Some background knowledge on traces is provided here for a better understanding of the required configuration settings.

Each trace represents an analysis of the measured data. Up to 6 traces can be displayed in each window, and up to 16 windows can be displayed on the screen. So, in theory, you can analyze the data measured by the R&S FSW in almost 100 different ways simultaneously!

Trace settings are stored on the instrument for each window. So when you switch to a different window, the trace settings previously configured for that window are restored.

•	Mapping Samples to Sweep Points with the Trace Detector	237
•	Analyzing Several Traces - Trace Mode	239
	How Many Traces are Averaged - Sweep Count + Sweep Mode	
•	How Trace Data is Averaged - the Averaging Mode	241
	Combining Several Trace Results - Trace Math Evaluation	
	Spectrograms	

6.3.1.1 Mapping Samples to Sweep Points with the Trace Detector

A trace displays the power values measured at the sweep points. During a frequency sweep, the R&S FSW increments the first local oscillator in steps that are smaller than approximately 1/10 of the bandwidth. This ensures that the oscillator step speed is conform to the hardware settling times and does not affect the precision of the measured power. The number of samples taken during a sweep is independent of the number of oscillator steps and is much larger than the number of sweep points that are displayed in the measurement trace.

Example:

Assume the following measurement parameters:

Sample rate: 32 MSamples / s

Sweep points: 1000Sweep time: 100 ms

Span: 5 GHz

During a single sweep, $3.2 * 10^6$ samples are collected and distributed to 1000 sweep points, i.e. 3200 samples are collected per sweep point. For each sweep point, the measured data for a frequency span of 1.6 MHz is analyzed.

Note that if you increase the number of sweep points, the frequency span analyzed for each point in the trace decreases, making the result more stable. See also chapter 5.5.1.8, "How Much Data is Measured: Sweep Points and Sweep Count", on page 198.

Obviously, a data reduction must be performed to determine which of the samples are displayed for each sweep point. This is the trace detector's task.

The trace detector can analyze the measured data using various methods:



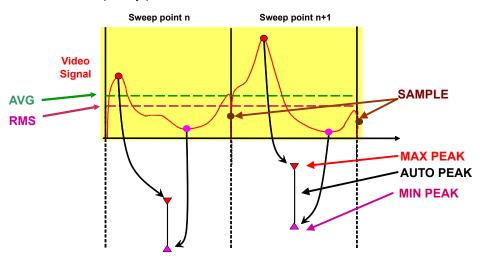
The detector activated for the specific trace is indicated in the corresponding trace information by an abbreviation.

Table 6-1: Detector types

Detector	Abbrev.	Description
Positive Peak	Pk	Determines the largest of all positive peak values of the levels measured at the individual frequencies which are displayed in one sample point
Negative Peak	Mi	Determines the smallest of all negative peak values of the levels measured at the individual frequencies which are displayed in one sample point

Detector	Abbrev.	Description
Auto Peak	Ар	Combines the peak detectors; determines the maximum and the minimum value of the levels measured at the individual frequencies which are displayed in one sample point (not available for SEM)
RMS	Rm	Calculates the root mean square of all samples contained in a sweep point. To this effect, R&S FSW uses the linear voltage after envelope detection. The sampled linear values are squared, summed and the sum is divided by the number of samples (= root mean square). For logarithmic display the logarithm is formed from the square sum. For linear display the root mean square value is displayed. Each sweep point thus corresponds to the power of the measured
		values summed up in the sweep point. The RMS detector supplies the power of the signal irrespective of the waveform (CW carrier, modulated carrier, white noise or impulsive signal). Correction factors as needed for other detectors to measure the power of the different signal classes are not required.
Average	Av	Calculates the linear average of all samples contained in a sweep point. To this effect, R&S FSW uses the linear voltage after envelope detection. The sampled linear values are summed up and the sum is divided by the number of samples (= linear average value). For logarithmic display the logarithm is formed from the average value. For linear display the average value is displayed. Each sweep point thus corresponds to the average of the measured values summed up in the sweep point. The average detector supplies the average value of the signal irrespective of the
Sample	Sa	waveform (CW carrier, modulated carrier, white noise or impulsive signal). Selects the last measured value of the levels measured at the individual frequencies which are displayed in one sample point; all other measured values for the frequency range are ignored

The result obtained from the selected detector for a sweep point is displayed as the power value at this frequency point in the trace.



The trace detector for the individual traces can be selected manually by the user or set automatically by the R&S FSW.

The detectors of the R&S FSW are implemented as pure digital devices. All detectors work in parallel in the background, which means that the measurement speed is independent of the detector combination used for different traces.



RMS detector and VBW

If the RMS detector is selected, the video bandwidth in the hardware is bypassed. Thus, duplicate trace averaging with small VBWs and RMS detector no longer occurs. However, the VBW is still considered when calculating the sweep time. This leads to a longer sweep time for small VBW values. Thus, you can reduce the VBW value to achieve more stable trace curves even when using an RMS detector. Normally, if the RMS detector is used the sweep time should be increased to get more stable traces.

Auto detector

If the R&S FSW is set to define the appropriate detector automatically, the detector is set depending on the selected trace mode:

Trace mode	Detector
Clear Write	Auto Peak
Max Hold	Positive Peak
Min Hold	Negative Peak
Average	Sample Peak
View	-
Blank	-

6.3.1.2 Analyzing Several Traces - Trace Mode

If several sweeps are performed one after the other, or continuous sweeps are performed, the trace mode determines how the data for subsequent traces is processed. After each sweep, the trace mode determines whether:

- the data is frozen (View)
- the data is hidden (Blank)
- the data is replaced by new values (Clear Write)
- the data is replaced selectively (Max Hold, Min Hold, Average)



Each time the trace mode is changed, the selected trace memory is cleared.

The trace mode also determines the detector type if the detector is set automatically, see chapter 6.3.1.1, "Mapping Samples to Sweep Points with the Trace Detector", on page 237.

The R&S FSW offers the following trace modes:

Table 6-2: Overview of available trace modes

Trace Mode	Description
Blank	Hides the selected trace.
Clear Write	Overwrite mode: the trace is overwritten by each sweep. This is the default setting. All available detectors can be selected.

Trace Mode	Description
Max Hold	The maximum value is determined over several sweeps and displayed. The R&S FSW saves the sweep result in the trace memory only if the new value is greater than the previous one.
	This mode is especially useful with modulated or pulsed signals. The signal spectrum is filled up upon each sweep until all signal components are detected in a kind of envelope.
	This mode is not available for statistics measurements.
Min Hold	The minimum value is determined from several measurements and displayed. The R&S FSW saves the sweep result in the trace memory only if the new value is lower than the previous one.
	This mode is useful e.g. for making an unmodulated carrier in a composite signal visible. Noise, interference signals or modulated signals are suppressed, whereas a CW signal is recognized by its constant level.
	This mode is not available for statistics measurements.
Average	The average is formed over several sweeps. The Sweep/Average Count determines the number of averaging procedures.
	This mode is not available for statistics measurements.
View	The current contents of the trace memory are frozen and displayed.



If a trace is frozen ("View" mode), the instrument settings, apart from level range and reference level (see below), can be changed without impact on the displayed trace. The fact that the displayed trace no longer matches the current instrument setting is indicated by the \star icon on the tab label.

If the level range or reference level is changed, the R&S FSW automatically adapts the trace data to the changed display range. This allows an amplitude zoom to be made after the measurement in order to show details of the trace.

6.3.1.3 How Many Traces are Averaged - Sweep Count + Sweep Mode

In "Average" trace mode, the sweep count and sweep mode determine how many traces are averaged. The more traces are averaged, the smoother the trace is likely to become.

The algorithm for averaging traces depends on the sweep mode and sweep count.

- sweep count = 0 (default)
 - In "Continuous Sweep" mode, a continuous average is calculated for 10 sweeps, according to the following formula:

$$Trace = \frac{9 * Trace_{old} + MeasValue}{10}$$

Fig. 6-3: Equation 1

Due to the weighting between the current trace and the average trace, past values have practically no influence on the displayed trace after about ten sweeps. With this setting, signal noise is effectively reduced without need for restarting the averaging process after a change of the signal.

In "Single Sweep" mode, the current trace is averaged with the previously stored averaged trace. No averaging is carried out for the first sweep but the measured value is stored in the trace memory. The next time a sweep is performed, the trace average is calculated according to the following formula:

$$Trace = \frac{Trace_{old} + MeasValue}{2}$$

The averaged trace is then stored in the trace memory.

sweep count = 1

The currently measured trace is displayed and stored in the trace memory. No averaging is performed.

• sweep count > 1

For both "Single Sweep" mode and "Continuous Sweep" mode, averaging takes place over the selected number of sweeps. In this case the displayed trace is determined during averaging according to the following formula:

$$Trace_n = \frac{1}{n} \cdot \left[\sum_{i=1}^{n-1} (T_i) + MeasValue_n \right]$$

Fig. 6-4: Equation 2

where n is the number of the current sweep ($n = 2 \dots$ Sweep Count).

No averaging is carried out for the first sweep but the measured value is stored in the trace memory. With increasing n, the displayed trace is increasingly smoothed since there are more individual sweeps for averaging.

After the selected number of sweeps the average trace is saved in the trace memory. Until this number of sweeps is reached, a preliminary average is displayed. When the averaging length defined by the "Sweep Count" is attained, averaging is continued in continuous sweep mode or for "Continue Single Sweep" according to the following formula:

$$Trace = \frac{(N-1)*Trace_{old} + MeasValue}{N}$$

where N is the sweep count

6.3.1.4 How Trace Data is Averaged - the Averaging Mode

When the trace is averaged over several sweeps (Trace mode: "Average"), different methods are available to determine the trace average.

With logarithmic averaging, the dB values of the display voltage are averaged or substracted from each other with trace mathematical functions.

With linear averaging, the level values in dB are converted into linear voltages or powers prior to averaging. Voltage or power values are averaged or offset against each other and reconverted into level values.

For stationary signals the two methods yield the same result.

Logarithmic averaging is recommended if sinewave signals are to be clearly visible against noise since with this type of averaging noise suppression is improved while the sinewave signals remain unchanged.

For noise or pseudo-noise signals the positive peak amplitudes are decreased in logarithmic averaging due to the characteristic involved and the negative peak values are increased relative to the average value. If the distorted amplitude distribution is averaged, a value is obtained that is smaller than the actual average value. The difference is -2.5 dB.

This low average value is usually corrected in noise power measurements by a 2.5 dB factor. Therefore the R&S FSW offers the selection of linear averaging. The trace data is linearized prior to averaging, then averaged and logarithmized again for display on the screen. The average value is always displayed correctly irrespective of the signal characteristic.

6.3.1.5 Combining Several Trace Results - Trace Math Evaluation

If you have several traces with different modes, for example an average trace and a maximum trace, it may be of interest to compare the results of both traces. In this example, you could analyze the maximum difference between the average and maximum values. To analyze the span of result values, you could subtract the minimum trace from the maximum trace. For such tasks, mathematical functions on trace results are provided.

6.3.1.6 Spectrograms

In addition to the standard "level versus frequency" or "level versus time" spectrum traces, the R&S FSW also provides a spectrogram display of the measured data.

A spectrogram shows how the spectral density of a signal varies over time. The x-axis shows the frequency, the y-axis shows the time. A third dimension, the power level, is indicated by different colors. Thus you can see how the strength of the signal varies over time for different frequencies.